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Change log

|  |  |
| --- | --- |
| ECSS-E-20-08A  30 November 2004 | First issue |
| ECSS-E-20-08B | Never issued |
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| ECSS-E-ST-20-08C Rev.1 18 July 2012 | Second issue Revision 1 |
| ECSS-E-ST-20-08C Rev.2  20 April 2023 | Second issue, Revision 2  Changes with respect to ECSS-E-ST-20-08C Rev.1 (18 July 2012) are identified with revision tracking.  **Main changes**   * Implementation of change requests * Addition of new clause 12 “Planar Blocking Diodes” * Check and update of the use of the verb “define” in the document   **Detailed Change Record:**  Deleted requirements:  4.3.3a; 5.5.1.3.4c; 5.5.1.4.4e; 5.5.2.2a; 6.4.3.6.2c; 6.4.3.11.2f; 6.4.3.15.3b; 7.5.13.2f and h; 9.6.18.2b; Table 10-1; 10.1.1.3e; 10.2.2.2a and b.  Added requirements:  4.3.1d; 5.5.1.5.2c and d; 5.5.1.5.3a to e; 5.5.3.2.9c; 5.5.3.11.2h to j; 6.4.2.2e and f; 6.4.3.4g; 6.4.3.7.2b; 6.4.3.10.2d and h; 6.4.3.15.2i; 6.4.3.15.4a to d; 6.4.3.18.2c and d; 6.4.3.18.3a; 6.4.3.19.2a; 7.5.4f; 7.5.13.2i; 7.5.14.2e to g; 7.5.17.2b; Table 9-5; 9.6.4.2c; 9.6.6.2.2a to g; 9.6.11.2d; all requirements and Tables of new clause 12; A.2.2<6.3.b and c; A.2.2<7.2>a; B.2.2<6.7>a; B.2.2<6.8>a; B.2.2<6.10>a; B.2.2<6.11>a (typo); B.2.2<6.12>a; C.2.2<6.7>a; C.2.2<6.9a; C.2.2<7.10>a; C.2.2<7.11>a; C.2.2<7.13>a; E.2.2<6>e and g; E.2.2<7.3>a; E.2.2<7.6>a; F.2.1a Note moved after text of req.; all requirements of new Annex H.  Modified requirements:  4.3.1a; 4.4c Note; 5.3.2.6a; 5.3.2.7a; 5.3.3.2a and e; 5.3.3.6a Note added; 5.3.3.10a; 5.3.3.2a; 5.3.3.13a; 5.4.2a; 5.4.3.3a Note; 5.4.3.4b; 5.4.3.5a; 5.4.3.6a; 5.5.1.2d and h; Table 5-1 Note added and now normative; 5.5.1.3.2a and c; 5.5.1.3.3a Note added; 5.5.1.3.3c, d and f; 5.5.1.3.4d,e and g; 5.5.1.4.4d Note added; 5.5.1.4.4h Note; 5.5.1.5.2a and b; 5.5.3.2.2a Note; 5.5.3.2.6b; 5.5.3.2.7a (and c for typo); 5.5.3.2.8c; 5.5.3.2.13a Note; 5.5.3.3.2a; 5.5.3.3.3a; 5.5.3.3.7a and c; 5.5.3.6a to c; 5.5.3.7.2b and c; 5.5.3.7.3a and b; 5.5.3.11.2e; 6.1.3a; 6.3.3.2b; 6.4.1b; Table 6-1; 6.4.2.3b and c; 6.4.3.1.2a; 6.4.3.1.6a; 6.4.3.4b, c and f; 6.4.3.6.2a, b, 6.4.3.8.2h; 6.4.3.9.2a; b Note; 6.4.3.10.2a and b; 6.4.3.11.2d Note added, e and g; 6.4.3.12.2b; 6.4.3.15.2a, b, e, f Note added, g, h; 6.4.3.15.3a and c; 6.4.3.18.2a and b; 7.1.2a; 7.3.1d; 7.3.2.2.2b; 7.4.1a and c (brackets removed and Note added); Table 7-2; 7.4.2.2d; 7.4.2.3b and d; 7.5.1.2a; 7.5.1.5.3b; 7.5.4a and b; 7.5.5.2a; 7.5.6.3d; 7.5.7.1.2h; 7.5.7.2.2g; 7.5.8.2a and b Note; 7.5.12.2a, b and d; 7.5.13.2a, d and e; 7.5.14.2a to d; 7.5.15.2a and b; 7.5.17.2a; 8.3.2a; 8.5.2b; 8.6.1a; 8.6.2.3 Notes; Table 8-1; 8.7.2.b; 8.7.3.2a Note moved after req.; 8.7.7b; 8.7.12.2b Note; 8.7.12.2f; 9.2.2.1a; 9.2.2.2a; 9.2.3a (formatting); Table 9-2 (symbol changed to HT2); 9.4.5.2.2c (typo); 9.5.1a; 9.5.2f; Table 9-3; 9.5.3a; Table 9-4; 9.5.4.3a; 9.5.4.3a and c; 9.6.2.2a (formatting); 9.6.3b; 9.6.4.2a; 9.6.6.1.2d (formerly 9.6.6.2d); 9.6.10.2a, b Note and d; 9.6.11.2a and b; 9.6.12.2f; 9.6.15.2c (typo) and two Notes added; 9.6.17.2e and Note in f moved to end of req.; 9.6.18.2c and d Note moved to end of req.; Table 9-5; 10.1.1.1a; 10.1.1.3a to d; Table 10-2 replaced by informative table; 10.1.2a to c, f and g; Table 10-3 replaced by informative table; 10.1.3a to c; Table 10-4; 10.2.1a; 10.2.2.1a; 10.2.2.3.3a; 10.2.3a; 10.2.5a (typo); 10.2.6.1a and b; 10.2.6.2a; 11.1.3.1a Note moved to end of req.; 11.1.3.2d; 11.1.4.2.1a Figure 11-4 and Note moved after text of req.; 11.1.4.2.2b and c; 11.2.2.4a formatting.  Editorial changes:   * Update of figures to separate illustration from text: Figure 6-1; Figure 7-1; Figure 8-1; * Former informative Table 5-1 now normative with new PUID number through call by new requirement 5.5.2.2a. * Notes moved to the end of the requirement: 5.5.3.4.2d; 5.5.3.5.2a; * Figure 6-1 and Table 6-2 moved after referencing requirement. * Addition of new Heading 9.6.6.1 caused renumbering of requirements of former clause 9.6.6.2 to 9.6.6.1.2. * Term “Sun” replaced by “Solar” (e.g. in clause 10). * Bibliography updated. |

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Introduction

The qualification, procurement, storage and delivery of space solar arrays are specified in the dedicated solar array specification, where requirements for the solar array electrical layout, structure and mechanism are specified.

This Standard outlines the requirements for the qualification, procurement, storage and delivery of the main assemblies and components of the space solar array electrical layout: photovoltaic assemblies, solar cell assemblies, bare solar cells, coverglass and protection diodes. This Standard does not outline the requirements for the qualification, procurement, storage and delivery of the solar array subsystem, comprising the solar panels, structural parts and mechanisms.

The general requirements are covered in the main part of this Standard (clauses 5 to 11). Annex A to Annex E specify the contents of the source control drawing of photovoltaic and solar cell assemblies, bare solar cells coverglasses and protection diodes and include the inspection data, physical and electrical characteristics, other ratings and acceptance and qualification specific requirements, which can be different for each space project.

This Standard is divided into five specific subjects, each one corresponding to each assembly or component:

* Clause 5 for photovoltaic assemblies,
* Clause 6 for solar cell assemblies,
* Clause 7 for bare solar cells,
* Clause 8 for coverglasses,
* Clause 9 for protection diodes,
* Clause 12 for planar blocking diodes.

Two additional clauses are dedicated to Sun simulators and calibration procedures (clause 10) and capacitance measurement methods (clause 11).

1. At the time of the publication of this Standard the handbook ECSS-E-HB-20-08A, that is called in this document, has not yet been published.

# Scope

This Standard specifies the general requirements for the qualification, procurement, storage and delivery of photovoltaic assemblies, solar cell assemblies, bare solar cells, coverglasses, protection diodes and planar blocking diodes suitable for space applications.

This standard does not cover the particular qualification requirements for a specific mission.

This Standard is primarily applicable for qualification approval for photovoltaic assemblies, solar cell assemblies, bare solar cells, coverglasses, protection diodes and planar blocking diodes, and to the procurement of these items.

This standard is limited to crystalline Silicon and single and multi-junction GaAs solar cells with a thickness of more than 50 m and does not include thin film solar cell technologies and poly-crystalline solar cells.

This Standard does not cover the concentration technology, and especially the requirements related to the optical components of a concentrator (e.g. reflector and lens) and their verification (e.g. collimated light source).

This Standard is not applicable for qualification of the solar array subsystem, solar panels, structure and solar array mechanisms.

This standard may be tailored for the specific characteristic and constrains of a space project in conformance with ECSS-S-ST-00.

Qualification is a process to confirm compliance with requirements that have been established with reference to foregoing characterization and engineering test programs. Guidelines for characterization and engineering tests and for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. Those clauses in this standard, for which the Handbook gives additional information, will refer to the Handbook.

# Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this ECSS Standard. For dated references, subsequent amendments to, or revision of any of these publications do not apply, However, parties to agreements based on this ECSS Standard are encouraged to investigate the possibility of applying the more recent editions of the normative documents indicated below. For undated references, the latest edition of the publication referred to applies.

|  |  |
| --- | --- |
| ECSS-S-ST-00-01 | ECSS system – Glossary of terms |
| ECSS-E-ST-10-03 | Space engineering – Testing |
| ECSS-E-ST-20 | Space engineering –Electrical and electronic |
| ECSS-E-ST-20-06 | Space engineering – Spacecraft charging |
| ECSS-Q-ST-60 | Space product assurance — Electrical, electronic and electromechanical (EEE) components |
| ECSS-Q-ST-70-01 | Space product assurance – Cleanliness and contamination control |
| ECSS-Q-ST-70-06 | Space product assurance – Particle and UV radiation testing for space materials |
| ECSS-Q-ST-70-09 | Space product assurance – Measurements of thermo-optical properties of thermal control materials |
| ISO 15387 | Space Systems – Single junction space solar cells – Measurement and calibration procedures |
| ISO 14644-1:1999 | Cleanrooms and associated controlled environments – Part 1: Classification of air cleanliness |
| MIL-E-12397B | Eraser, rubber pumice for testing coated optical elements |
| MIL-STD-750 | Test methods for semiconductor devices |
| IEC 60749-26:2006 | Semiconductor devices – Mechanical and climatic test methods - Part 26: Electrostatic discharge (ESD) sensitivity testing – Human body model (HBM) |
| IEC 60904-7 | Photovoltaic devices – Part 7: Computation of the spectral mismatch correction for measurements of photovoltaic devices |
| IEC 60904-10 | Photovoltaic devices – Part 10: Methods of linearity measurement |
| ASTM D1193-99 | Standard specification for reagent water |
| ESCC 23800 Issue 1 | Electrostatic Discharge Sensitivity Test Method; ESCC Basic Specification |
| ESCC 24900 Issue 2 | Minimum Requirements for Controlling Environmental Contamination of Components; ESCC Basic Specification |
| ESCC 2265000 | Evaluation test programme for discrete Non-microwave semiconductors; ESCC Basic Specification |
| EN 1464:2010 | Adhesives - Determination of peel resistance of adhesive bonds - Floating roller method |
| Gueymard, C., 2018 | Gueymard, C., Revised composite extraterrestrial spectrum based on recent solar irradiance observations Solar Energy, Volume 169, 2018, Pages 434-440, ISSN 0038-092X,  <https://doi.org/10.1016/j.solener.2018.04.067>. (<https://www.sciencedirect.com/science/article/pii/S0038092X1830433X>) |

# Terms, definitions and abbreviated terms

## Terms from other standards

For the purpose of this Standard, the terms and definitions from ECSS‑S‑ST‑00‑01 apply, in particular for the following terms:

**qualification**

**verification**

## Terms specific to the present standard

1. General
   1. blistering

forming of multiple small air bubbles inside the perimeter of a finish layer

* 1. bubbles

gaseous inclusion in the cell, coverglass or coverglass adhesive

* 1. chip

local absence of material along the edges and corners of a complete component and which extend through the thickness of the component

* 1. crack

fissure in the component with no separated portion from the remainder

1. Cracks can propagate from the edge of the material (edge cracks) or terminate at both ends within the material (surface cracks).
   1. delamination

physical separation between two material layers, which are joined in design

* 1. discolouration

local variation of solar cell anti–reflection coating colour due to the influence of the structure orientation of the cell layer immediately below or the variation of the anti–reflection coating layer thickness

* 1. dig

cavities in the surface of a component caused by impact with a pointed object or by crushing a material into the surface

* 1. inclusion

volume contained within the component that is devoid of the substrate material

* 1. in–process testing

tests performed during the manufacturing of a component or assembly in order to identify, in advance, defects or low performances

* 1. nick

local absence of material on the surface of a complete component which does not extend through the thickness of the component

* 1. peeling

forming of a delamination of a finish layer at the edge of the finished area. A blister at the edge of the surface

* 1. procurement lot

set of shipment lots of solar cells assemblies, bare solar cells and coverglasses, manufactured with the same processes and materials, with identical manufacturing lines, that fill the same purchase order

* 1. scratch

linear marking of the component that represents a volume devoid of the substrate material emanating from a single face of the component and not penetrating through the whole thickness of the substrate at any point

* 1. shipment lot

solar cell assemblies, bare solar cells and coverglasses manufactured with the same processes and materials with identical manufacturing lines delivered to the customer as a part of a purchase order

* 1. spatter

small bits of solid coating material imbedded on or in the coating or substrate

* 1. voids

absence of deposited materials

1. Examples are absence of cell contact material or anti–reflection coating.
2. Photovoltaic assemblies
   1. photovoltaic assembly

power generating network comprising the interconnected solar cell assemblies (strings and sections), the shunt and blocking diodes, the busbars and wiring collection panels, the string, section and panel wiring, the wing transfer harness, connectors, bleed resistors and thermistors

* 1. qualification coupon

non–flight representative test sample of flight panels, built with flight processes and containing representative materials and components to be used in the manufacture of flight panels, also called DVT coupon

* 1. slicing

procedure to evenly distribute the total number of thermal cycles over temperature domains which are compatible with the temperature excursion on an orbit level rather than on the overall mission temperature envelope

1. Normally used for LEO missions.
2. Solar cell assemblies
   1. cladding

application of a thin layer of material fully covering the surface, For instance silver cladding of an interconnector

* 1. deformed interconnector

interconnector whose initial conformed shape is modified

* 1. interconnected cell

solar cell with interconnector without coverglass

* 1. solar cell assembly

solar cell together with interconnector, coverglass and with or without by–pass diode

* 1. tearing interconnector

interconnector physically separated from the cell due to a failure of the welding or soldering joint

* 1. interconnector tab

part of the interconnector that is joined, e.g. welded, soldered, ultrasonic, with the solar cell contact pad or the solar cell rear side contact

1. Tabs are also known as fingers and interconnectors can be composed of several tabs or fingers.
2. Bare solar cells
   1. bare solar cell

photovoltaic component capable to delivering electrical power when illuminated with light

* 1. cells nominal size

cell dimensions of the solar cell procurement lot

* 1. component bare solar cell

specially manufactured solar cell, with only one active junction and the same spectral response as one sub cell of a multi–junction solar cell

* 1. contact vacuum evaporation batch

bare solar cells manufactured in the same contact vacuum evaporation run

* 1. drops

excess of metallization material on the solar cell contacts

* 1. remaining Factor

ratio of an electrical performance parameter at EOL to its value at BOL

1. E.g. maximum power of a solar cell.
   1. solar cell anti–reflection coating

single or multi–layer coating which reduces the reflection coefficient of the incident solar radiation

* 1. uncoated area

area of the solar cell where the bare solar cell is exposed and is devoid of coatings

* 1. worm shaped bulge

protuberance of contact material shaped in linear irregular paths or single dots where the contact material is locally delaminated from the immediate lower layer

1. Coverglasses
   1. coating

dielectric or conductive material applied to the glass substrate by vacuum deposition

1. Coatings applied to the external face of the coverglass is termed the “front surface coating”. Coatings applied to the internal face of the glass substrate to be bonded to the solar cell is termed the “rear surface coating”. Commonly used coatings include:

* single–layer anti–reflection coating,
* multi–layer anti–reflection coating,
* ultraviolet reflector,
* infrared reflector, and
* conductive coating.
  1. conductive coating

transparent coating used to prevent the exposed surface from charging and consequently protecting the solar cell from the effect of electrostatic discharge

1. The coverglass usually comprises a suitable glass substrate and one or more of a combination of the coatings given in the note in clause 3.2.5.1.
   1. coverglass

glass substrate and coatings applied to its surfaces

* 1. coverglass coating lot

collection of glass substrates subjected to the same coating run or runs (for coverglasses which have more than one coating)

* 1. infrared reflector

multi–layer dielectric coating which has a high reflectance coefficient in the infrared portion of the solar spectrum

1. The infrared reflector is used to reflect light that is not usefully converted to electrical energy by the solar cell thus reducing the operating temperature and increasing the conversion efficiency of the SCA.
   1. mark

See **stain**

* 1. multi–layer anti–reflection coating

multiple layer coating which has the effect of increasing the transmission coefficient of the coverglass

* 1. single layer anti–reflection coating

simplest form of coating comprising a single layer of low index dielectric material which minimizes the reflection coefficient of the incident solar radiation thus increasing the transmission coefficient of the coverglass

1. The single layer of low index dielectrical material is usually done of MgF2.
   1. stain

area which under inspection conditions can clearly be defined as not being optically homogeneous with the bulk material, and that cannot be categorized as an inclusion, scratch, crack, chip, dig, void or coating delamination

1. The term “mark” can be used as a synonymous.
   1. ultraviolet reflector

multi–layer dielectric coating which has a high reflectance coefficient in the UV portion of the solar spectrum

1. The ultraviolet reflector is used to protect the underlying adhesive and to reflect light that is not usefully converted to electrical energy by the solar cell thus reducing the operating temperature of the solar cell and increasing the conversion efficiency of the SCA.
   1. uncoated area

area of the coverglass where the bare coverglass substrate is exposed and is devoid of coatings

1. Verification processes
   1. accelerated testing

test in which the life time requirement is verified in an accelerated way by intensifying one parameter of the environment or load.

1. The following are examples of accelerated tests:

* UV test done with increased sun intensity in the UV part of the spectrum,
* Electron and proton radiation tests with life time fluences in a limited period of time,
* humidity tests done at higher temperature and humidity,
* bake-out done at higher temperature,
* performance parameter degradation at higher temperature,
* thermal cycling with higher/lower cool-down and heat-up rates and without nominal operating dwell time in between.
  1. acceptance test

test to determine that a system, subsystem, component or functional part is capable of meeting performance requirements prescribed in purchase specifications or other documents specifying what constitutes the adequate performance capability for the item and to demonstrate the item is free from manufacturing defects

1. In this document acceptance is associated with specified requirements which have a defined acceptance safety factor with respect to requirements corresponding with the actual loads and environments
   1. delta qualification

qualification performed on an equipment which has undergone minor design modifications or has been qualified to operate in environments less severe than those specified

* 1. proto flight test

test requirements which have a defined qualification safety factor with respect to requirements corresponding with the actual loads and environments, but with limited test durations

* 1. qualification by similarity

process to demonstrate the ability to fulfil specified requirements by comparing a new design specification with a similar proven design specification

## Abbreviated terms

For the purpose of this standard, the abbreviated terms of ECSS-S-ST-00-01 and the following apply:

| Abbreviation | Meaning |
| --- | --- |
| **ADP** | acceptance data package |
| **AOCS** | attitude and orbit control system |
| **AM0** | air mass 0 (zero) |
| **APTC** | ambient pressure thermal cycling |
| **AR** | anti-reflection |
| **ARC** | anti-reflection coating |
| **ATOX** | atomic oxygen |
| **BOL** | beginning-of-life |
| **BSC** | bare solar cell |
| **BSR** | back surface reflector |
| **CIBD** | connector integrated blocking diode |
| **CIC** | connector integrated cell  NOTE: U.S. designation of SCA. |
| **CIDL** | configuration item data list |
| **CVCM** | collected volatile condensable material |
| **CVG** | coverglass |
| **DCR** | documentation change request |
| **DJF** | design justification file |
| **DRD** | document requirements definition |
| **DRB** | delivery review board |
| **DVG** | direct voltage gradient |
| **DVT** | design verification test |
| **EMC** | electromagnetic compatibility |
| **EOL** | end-of-life |
| **ELM** | electronluminescence |
| **EPD** | external protection diode |
| **ESD** | electrostatic discharge |
| **FIT** | failure in time |
| **FMECA** | failure modes, effects and criticality analysis |
| **GaAs** | gallium arsenide |
| **GEO** | geostationary orbit |
| **IC** | interconnected cell |
| **Ifw** | current in forward direction of the diode |
| **Imp** | maximum power current |
| **Iop** | current at operational voltage |
| **Irev** | current in reverse direction of the diode |
| **IPD** | integral protection diode |
| **IRR** | infrared reflector |
| **Isc** | short-circuit current |
| **IVG** | inverted voltage gradient |
| **LEO** | low Earth orbit |
| **LVDT** | linear voltage displacement transducer |
| **MLAR** | multi-layer anti-reflection coating |
| **NCR** | nonconformance report |
| **NRB** | nonconformance review board |
| **OSTC** | on station thermal cycling |
| **PAD** | part approval document |
| **PBD** | planar blocking diode |
| **PCDU** | power control and distribution unit |
| **PID** | process identification document |
| **PLM** | photoluminescence |
| **Pmax** | maximum power |
| **PMCF** | product manufacturing and control file |
| **PMP** | parts, materials and processes |
| **PSA** | permanent sustained arc |
| **PTH** | power transfer harness |
| **PVA** | photovoltaic assemblies |
| **r.m.s.** | root mean square |
| **RAMS** | reliability, availability, maintainability and safety |
| **RDC** | relative damage coefficients |
| **RML** | recovered mass loss |
| **S.C.** | solar constant |
| **S.C. (AM0)** | solar constant at air mass 0 |
| **SCA** | solar cell assembly |
| **SCD** | source control drawing |
| **SLAR** | single layer anti-reflection coating |
| **SMM** | spectral mismatch factor |
| **SWS** | secondary working standard |
| **Tamb** | ambient temperature |
| **TAT** | type approval test |
| **TBD** | to be defined |
| **TBS** | to be specified |
| **TML** | total mass loss |
| **TQCM** | thermal quartz crystal microbalance |
| **TSA** | temporary sustained arc |
| **UVR** | ultraviolet reflector |
| **Vfw** | voltage in forward direction of the diode |
| **Vmp** | maximum power voltage |
| **Voc** | open-circuit voltage |
| **Vop** | operational voltage |
| **Vrev** | voltage in reverse direction of the diode |
| **Vtest** | test voltage |
| **WRC** | World Radiation Centre in Davos |
| **Φe** | equivalent fluence used for electron irradiation |

## Nomenclature

The following nomenclature applies throughout this document:

1. The word “shall” is used in this Standard to express requirements. All the requirements are expressed with the word “shall”.
2. The word “should” is used in this Standard to express recommendations. All the recommendations are expressed with the word “should”.
3. It is expected that, during tailoring, recommendations in this document are either converted into requirements or tailored out.
4. The words “may” and “need not” are used in this Standard to express positive and negative permissions, respectively. All the positive permissions are expressed with the word “may”. All the negative permissions are expressed with the words “need not”.
5. The word “can” is used in this Standard to express capabilities or possibilities, and therefore, if not accompanied by one of the previous words, it implies descriptive text.
6. In ECSS “may” and “can” have completely different meanings: “may” is normative (permission), and “can” is descriptive.
7. The present and past tenses are used in this Standard to express statements of fact, and therefore they imply descriptive text.

# General

## Overview

### Objective and organization

The objectives of this Standard are:

* To specify the rules for the flow of technical requirements from a project solar array specification down to component level in order to guarantee that lower level components and sub-assemblies are qualified according to higher level specifications.
* To specify the set of requirements from component level up to solar panel level consisting of photovoltaic assemblies (PVA) and solar panel substrate (rigid or flexible) to achieve generic qualification for each level of assembly for about 90 % of the solar arrays within a given application domain; for example, deployable solar arrays for GEO or LEO applications.

This clause describes the organization of the requirements and how they are applied.

The philosophy behind this Standard is twofold in that respect that:

* Qualification of a specific level of assembly is based on the use of qualified components and sub-assemblies (generically) qualified at lower levels. The specification tree, of which panel substrates, photovoltaic assemblies (PVA) and their components form part is illustrated in Figure 4‑1.

OR

* Qualification of components for a specific application can be achieved at a sub-assembly level at which the qualification is unequivocally demonstrated. This means that certain types of qualification tests do not need to be duplicated at different lower level of assembly in case of a unique application of a dedicated design

This Standard specifies the requirements for qualification at each level from components, assemblies and up to and including PVA on Design Verification Test (DVT) coupons. Components, assemblies and coupons are built according to component, assemblies and PVA design requirements and are being qualified with the objective of demonstrating that the design and manufacturing processes are approved and verified for use on solar panels of a flight application.

Together with the PVA qualification on a specific substrate, a material database is needed in order to justify allowable values.

1. 1 For a sandwich CFRP type of substrate the material mechanical performance database is needed to complete ECSS-E-ST-32-08 Clause 4.6 and ECSS-E-HB-32-20\_Part 1A, including stiffness and strength data for CFRP sandwich structures that can be obtained by substrate elementary tests such as

* 4-point bending and/or edgewise compression stiffness and strength tests
* shear and/or skin +-45° tensile stiffness and strength tests
* sandwich flatwise tensile strength tests,
* inserts in-plane and out-of-plane strength tests,
* Kapton peel strength test.

For any other type of substrate, additional or different tests might be needed.

1. 2 By having this material data base upfront, potential failures in the substrate design at a late stage or incompatibilities of the design can be avoided.

Generally, with the substrate elementary tests and the solar array mechanical tests, a solar panel substrate is deemed to be mechanically qualified, up to the point of deployment.

In order to qualify a solar panel in view of thermal life time cycling, it is needed to perform a DVT coupon campaign (see clause 5) for qualifying the substrate, PVA and their combination.

The elementary substrate tests will need to be repeated after thermal cycling only if the solar array is subjected to substantial mechanical loading long after deployment, e.g. as a result of main engine firings, docking/undocking manoeuvres, etc.

Minor design modifications as described in the ECSS-E-HB-20-08 do not require the repetition of the DVT thermal life cycling. In the Handbook rules are given with which so-called qualification by similarity or delta qualification can be justified as acceptable for specific cases.

For many parameters in this standard the value to be specified as requirement is dependent on the mission concerning duration and environmental conditions or the implemented solar array design. These parameter values are derived from the higher level subsystem specification and reflected in a dedicated document. In this standard the source control drawing has been selected generically on every level of assembly as an example of a document to reflect the specific requirements. So the source control drawing or equivalent set of documentation is the reference list for physical characteristics, performance requirements and environmental conditions.

Full qualification of an application is not achieved after successful qualification of the solar panel substrate, PVA and its components at coupon level only. Robustness against certain environments can only be demonstrated in the final solar array configuration, that may comprise amongst others full size panel on-station thermal cycling and sine vibration, acoustic noise, and wing deployment testing at subsystem or spacecraft level.



Figure ‑: Specification hierarchy

### Interfaces with other areas

In the specification hierarchy (Figure 4‑1) only the components and assembly levels that are usually dedicated to solar arrays are shown. At every integration step, additional materials and components, not mentioned in the specification hierarchy, are used such as:

* adhesives,
* solder,
* interconnectors and busbars,
* diodes,
* resistors,
* thermistors,
* connectors, and
* wires.

Requirements for these materials and components can be found in their procurement specifications, and in EEE component specifications, which are reviewed as part of the qualification process. For EEE component specifications, see the ECSS-Q-ST-60 series of standards. For Materials Parts and processes specifications, see the ECSS-Q-ST-70.

The qualification of the use of these items is a pre-requisite for the qualification of the assembly they are part of (for example, coverglass adhesive at the SCA level and busbars at the qualification coupon level).

Non-PVA related solar array design, power subsystem interface and mission specific related topics such as grounding, electromagnetic compatibility, magnetic moment, spacecraft related geometrical loss factors and end-of-life performance prediction related topics, including loss factors, are not addressed in this Standard.

Specific design measures to support the solar array in order to satisfy the requirements of this Standard, such as grounding spots and blocking diodes, are however, taken into account.

Specific environmental conditions which can be a limitation in the qualification for general use, are not addressed in this Standard as these aspects are usually the subject of a project dedicated qualification (for example, the chemical contents in local ambient air).

## Physical properties

ECSS-E-ST-20-08\_0090001

The following physical properties of the components and materials shall be measured:

coefficient of thermal expansion

heat conductivity

specific heat

Young’s modulus and Poisson’s ratio

Flex strength

1. The objective is to establish the boundaries for the qualification test program over the full range of application by means of analysis.

ECSS-E-ST-20-08\_0090002

The data specified in requirement shall be determined during the development phase of a new component and need not be repeated during the qualification program.

## Test and storage

### Test environment

ECSS-E-ST-20-08\_0090003

The atmospheric conditions during all inspection, test operations and storage shorter than 6 months shall be as follows:

Pressure: (1 013,25 ± 33) hPa.

Temperature: (23 ± 5) C.

Average relative humidity: 40 % - 65 %.

1. A pressure of (1 013,25 ± 33) hPa is equivalent to (760 ± 25) mmHg.

ECSS-E-ST-20-08\_0091065

The room cleanliness level should be airborne particle count:   
Class 8 ISO 14644-1.

ECSS-E-ST-20-08\_0090005

Every deviation from requirements 4.3.1a and 4.3.1b during tests shall be recorded in the data documentation package (DDP).

1. 1 For DDP complete contents, refer to Annex G.
2. 2 Semiconductor devices (i.e. planar diodes) can short-circuit if no special precautions are taken during long storage periods under certain atmospheric conditions. This is because chlorine content, in combination with illumination, can produce metal contact migrations on these semiconductor devices.

ECSS-E-ST-20-08\_0091105

For long term storage longer than 6 months qualification coupons shall be kept in the dark in a dry nitrogen environment.

1. It is good practice to use light tight coverage to keep the DVT coupons in darkness during periods shorter than 6 months.

### Test tolerances and accuracies

ECSS-E-ST-20-08\_0090006

The accuracy of the instruments and test equipment used to control or measure test parameters shall be one order of magnitude higher than the tolerance on the variable to be measured.

1. Examples of where this cannot be achieved include measurements of electrical performance and temperatures.

ECSS-E-ST-20-08\_0090007

All instrumentation used for qualification and acceptance tests shall:

be calibrated, and

be within the specified calibration period at the time of test.

ECSS-E-ST-20-08\_0090008

Instrumentation whose calibration period runs out during the planned test time shall not be used.

ECSS-E-ST-20-08\_0090009

The maximum test temperature tolerances for thermal testing shall be as given in Table 4‑1.

ECSS-E-ST-20-08\_0090010

The accuracy of mass measurements shall be better than ±1 % or 0,01 g, whichever is higher.

ECSS-E-ST-20-08\_0090011

The test condition tolerances shall be applied to the nominal test values specified.

ECSS-E-ST-20-08\_0090012

The accuracy of the electrical performance test on PVA level shall be better than or equal to the calibration loss factor used in the power analysis.

ECSS-E-ST-20-08\_0091030

Table ‑: Test tolerances on temperature

|  |  |
| --- | --- |
| Temperature range (C) | tolerance (C) |
| around - 175 | -10 / +0 |
| around - 100 | -10 / +0 |
| around + 90 | -0 / +10 |
| Around +130 | -0 / +10 |

### <<deleted>>

ECSS-E-ST-20-08\_0090013

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## Critical materials

ECSS-E-ST-20-08\_0090014

The critical interface information shall be part of the PMP list.

1. For PMP, see ECSS-Q-ST-70 Annex B.

ECSS-E-ST-20-08\_0090015

Silver cladding shall be annealed and contain a minimum of 99,9 % pure silver.

ECSS-E-ST-20-08\_0090016

Pure tin, cadmium and zinc shall not be present in finished space-qualified solar panels.

1. Pure tin refers to a tin alloy with less than three atomic percent of an alloying metal, e.g. lead. Pure cadmium and zinc are metals used or applied in a non-mixed metal or unalloyed state.

ECSS-E-ST-20-08\_0090017

Solar panels containing Beryllium Oxide shall be clearly identified with the designation BeO.

# Photovoltaic assemblies

## Overview

### Description

The photovoltaic assembly (PVA) comprises the electrical parts to satisfy the requirements of the solar array specification.

This Clause applies to solar arrays using a planar design without concentration and based on crystalline solar cells.

In case of concentration, this Clause applies to the PVA without the optics, provided that the electrical performance tests are adapted to the light incidence and intensity imposed by the optics.

Usually, a PVA consists of parallel connected strings. A string is the smallest operational component at the PVA level. A string consists of a series interconnected solar cells connected to the spacecraft bus. These strings are supported by a solar array panel substrate or frame.

The parts comprising a PVA usually include:

* interconnected SCAs,
* bleed resistors,
* wiring,
* panel connectors,
* diodes (blocking and shunt),
* thermal sensors,
* telemetry indicator wiring, and
* grounding.

### Purpose and objective

In this Clause the design limits, including margins, and the responsibilities for PVA manufacturing are specified and include the:

* design requirements (refer to clause 5.3);
* mechanical and electrical interface;
* manufacturing requirements for PVA (refer to clause 5.4);
* qualification requirements for PVA (refer to clause 5.5.1);
* acceptance requirements for PVA (refer to clause 5.5.2).

The values specified for the SCA level are provided by the solar cell assembly supplier and confirmed during the SCA qualification tests (refer to clause 6.4).

In order to design and verify a solar array, data for the following parameters and characteristics at the SCA level or lower are used:

* characteristics of the SCA (Voc, Isc, Vmp and Imp);
* spectral response;
* reference calibration standard;
* inputs to describe radiation degradation such as relative damage coefficient and electron-proton equivalence or non-ionising energy loss, according to the approach used;
* temperature coefficients as a function of radiation fluences;
* reverse characteristics versus temperature;
* UV and Sun spectrum characteristics (reflectivity);
* capacitance versus temperature;
* optical properties (hemispherical emissivity, and solar absorptance, and cover gain or loss);
* behaviour with regard to specific mission environments:
* ATOX sensitivity,
* thruster erosion sensitivity,
* micro-meteoroids and debris sensitivity;
* loss factors for interconnecting the cells into a string.

## Conditions and method of test

ECSS-E-ST-20-08\_0090018

The conditions and methods of testing shall conform to the photovoltaic assembly source control drawing (SCD-PVA).

1. The PVA specification consists of two parts, the generic specification (this Standard) and the SCD. For the preparation of the SCD-PVA, refer to Annex A.

ECSS-E-ST-20-08\_0090019

The SCD-PVA shall be prepared by the supplier, in conformance with Annex A, and provided to the customer for reviewing and agreement.

ECSS-E-ST-20-08\_0090020

Any deviation from in-process, acceptance and qualification test shall be justified.

ECSS-E-ST-20-08\_0090021

Deviations from this Standard applicable to the SCD-PVA shall:

be agreed between the customer and the supplier;

include alternative requirements equivalent to those of this Standard;

not affect the reliability and performances of the photovoltaic assemblies;

be only those specified in requirement 5.2c.

## Photovoltaic assembly design

### Overview

The objective of this standard at the PVA level is to specify the requirements for the detail design, performance, qualification, manufacture and acceptance testing of coupons equipped with the PVA on the relevant substrate representing all design specifics (e.g. undisturbed area, re-enforced area, edge members, Holddowns, etc.). To cover all the aspects of the solar array, more than one coupon might be needed.

The inputs to these requirements are the solar array specification, which is prepared following the requirements of the mission specification, the ground test programme and the spacecraft design. In this clause the steps which influence specific design characteristics of the PVA have been listed. Requirements which merely determine the sizes of the PVA have not been taken into account, like intensity related loss factors and reliability requirements.

### Parameters related to parts, materials and processes (PMP)

#### Outgassing

ECSS-E-ST-20-08\_0090022

Flight hardware shall be constructed from space qualified materials having the following properties:

A recovered mass loss (RML) of 1 % or less.

1. See ECSS-Q-ST-70-02.

A collected volatile condensable material (CVCM) of 0,1 % or less when heated in a vacuum to 125 C and collected at 25 C.

ECSS-E-ST-20-08\_0090023

The PMP list shall include the RML and CVCM values for all materials used.

1. The mission specification can specify an absolute limit to the total mass loss and volatile condensable material of the solar array sub-system. The fulfilment of this system requirement can be verified either by analysis using the total amount of the applied materials, the individual material RML and CVCM data, outgassing field of view and temperature distribution, or by test of the representative subsystem and measurement of the outgassing product.

#### Toxicity

ECSS-E-ST-20-08\_0090024

Any material used in the construction of the PVA that is dangerous to the health of the personnel shall be identified.

ECSS-E-ST-20-08\_0090025

Preventive handling measures shall be taken in conformance with a standard approved by the customer.

#### Flammability

ECSS-E-ST-20-08\_0090026

Any flammable materials used in the construction of the PVA shall be identified.

#### Corrosion

ECSS-E-ST-20-08\_0090027

The supplier and customer shall agree on the measures to be taken to prevent corrosion during storage or in normal operational service.

ECSS-E-ST-20-08\_0091066

Standard atmospheric conditions may be assumed for general applications in the spacecraft, over a period of time that is agreed between the supplier and customer.

ECSS-E-ST-20-08\_0090029

To avoid electrolytic corrosion, a process, approved by the customer, shall be used.

#### Magnetism

ECSS-E-ST-20-08\_0090030

Permanent magnetic materials shall be avoided when specified by the mission.

ECSS-E-ST-20-08\_0091067

Non-magnetic materials should be used.

#### Erosion

ECSS-E-ST-20-08\_0090032

PVA materials shall be capable of tolerating a specified erosion level resulting from spacecraft operation without degradation in the nominal performance of the PVA, in conformance with the PVA specification.

1. Example: thruster plumes.

#### Atomic oxygen (ATOX)

ECSS-E-ST-20-08\_0090033

PVA materials shall be capable of tolerating a specified level of degradation resulting from an ATOX environment, without degradation in the nominal performance of the PVA, in conformance with the solar array specification.

ECSS-E-ST-20-08\_0090034

The ATOX resistivity shall be determined by the individual resistivities of the used materials and components in their configuration.

### Parameters related to design

#### Cell integration

ECSS-E-ST-20-08\_0090035

The solar cells shall be structured such that the PVA is capable of withstanding all phases of ground handling, transportation, qualification testing and acceptance testing, launch and orbit operations as to conform to the mission requirements.

ECSS-E-ST-20-08\_0090036

The capability for replacement of cracked, broken or damaged SCAs shall be included in the design.

ECSS-E-ST-20-08\_0090037

Repair method shall be feasible in horizontal and vertical panel positions.

#### Stringing

ECSS-E-ST-20-08\_0090038

As requested also in the ECSS-E-ST-20 requirement 5.5.2.o, at least individual blocking diodes connected to the end of the strings shall be applied in the design of the panel, consequently the strings of the DVT coupon are protected by blocking diodes in the same way.

1. String blocking diodes prevent failures due to power transients from the power sub-system or due to operation in shadow and they mitigate risks linked to ESD secondary arcing.

ECSS-E-ST-20-08\_0090039

To enable performance measurement at the lowest level of assembly at the coupon level, strings shall be measured individually.

ECSS-E-ST-20-08\_0090040

Potential parallel connections shall not prevent performance measurement specified in requirement 5.3.3.2b.

ECSS-E-ST-20-08\_0090041

If the dimensions of the coupon enables the accommodation, the full flight string length shall be represented on the qualification coupon.

ECSS-E-ST-20-08\_0090042

Coupon layout shall be as specified in an overall assembly drawing as part of the SCD-PVA.

#### Cell interspacing

ECSS-E-ST-20-08\_0090043

The cell interspacing shall be compatible, as a minimum, with the following mission requirements:

thermal expansion and contraction within the mission temperature extremes specified in the solar array specification;

panel geometry;

ESD requirements.

#### Sectioning

ECSS-E-ST-20-08\_0090044

Sections shall not be included at the coupon level.

ECSS-E-ST-20-08\_0091068

To test the technique of interconnecting strings, the negative ends of individual strings may be connected in a way that is representative for flight panels.

#### Reverse bias protection

ECSS-E-ST-20-08\_0090046

The solar cells that are potentially subject to reverse bias shall be protected by shunt diodes unless the solar cells are insensitive to the effects of reverse bias.

1. Types of reverse bias include:

* AOCS failure shadowing,
* self shadowing, and
* power management (including maximum power point tracker when direct energy transfer function is acting at BOL).

#### Insulation

ECSS-E-ST-20-08\_0090047

The following items shall be electrically insulated from each other:

Any solar cell circuits to substrate (the grounding reference of the coupon).

Solar cell circuits to solar cell circuits (if not connected at the negative ends).

Thermal sensor to the solar cell circuits and to the substrate (the grounding reference of the coupon).

Conductive coverglass grounding network, if used, to solar cell circuits.

1. For fulfilment of reliable insulation (also known as “double insulation”) requirements reference is made to ECSS-E-ST-20.

#### Derating

For the derating requirements of components, see ECSS-Q-ST-30-11.

#### Redundancy

For redundancy requirements, see ECSS-Q-ST-30.

For failure modes requirements, see ECSS-Q-ST-30-02.

#### Fault tolerance

ECSS-E-ST-20-08\_0090048

A FMECA shall be performed for the design of the solar array.

ECSS-E-ST-20-08\_0090049

The design consequences shall be implemented on the qualification coupon, including:

the photovoltaic assembly from solar cell strings to the connector, and

redundant bleed resistors and, if any, redundant PVA assemblies or components.

1. 1 Examples: Solar cell strings, blocking diodes, temperature sensors.
2. 2 For FMECA, see ECSS-Q-ST-30-02.

ECSS-E-ST-20-08\_0090050

No single fault shall result in the following:

The loss of integrity of the redundant parts indicated in requirement 5.3.3.9b.2.

The propagation of the fault causing permanent damage or loss of use of the units connected to the PVA.

1. Examples: solar array regulator unit, solar array drive mechanism.

ECSS-E-ST-20-08\_0090051

No failure shall be propagated from one solar array wiring group to another.

#### Fatigue resistance

ECSS-E-ST-20-08\_0090052

The effects of fatigue shall be verified by test as specified in 5.5.1.3.

ECSS-E-ST-20-08\_0090053

The design of the PVA shall include the result of the verification specified in requirement 5.3.3.10a.

#### Adherence to substrate

##### Measurement

ECSS-E-ST-20-08\_0090054

The adherence of SCAs to the substrate shall be measured using representative process samples.

##### Property

ECSS-E-ST-20-08\_0090055

The SCAs shall stay attached to the panel and conform to all requirements during the test campaign and all the phases of the mission.

ECSS-E-ST-20-08\_0090056

The adherence shall be such that the SCAs integrated on the substrate can be repaired, removed and replaced.

#### Adhesive uniformity

ECSS-E-ST-20-08\_0090057

The thickness boundaries, including manufacturing and repair tolerances, shall be specified by means of analysis or test.

ECSS-E-ST-20-08\_0090058

The boundary requirements on minimum and maximum thickness, in conformance with requirement 5.3.3.12a, shall be guaranteed by a controlled application process demonstrated on separate samples.

ECSS-E-ST-20-08\_0090059

The thermal conductance towards the panel substrate shall be such that the specified solar cell and protection diode temperature can be maintained.

#### Electrostatic discharge (ESD)

ECSS-E-ST-20-08\_0090060

The solar array design shall be such that it can survive the charging environment and operating conditions as specified by the mission.

ECSS-E-ST-20-08\_0090061

Requirement 5.3.3.13a shall be either demonstrated by analysis or by testing.

1. During and after launch, the spacecraft is surrounded by a low density plasma of high energy electrons and protons. On insulated surfaces of the spacecraft, the electrons build up a charge which discharges when breakdown of the insulating materials is reached.

#### Electromagnetic compatibility (EMC)

ECSS-E-ST-20-08\_0090062

The PVA shall be designed to meet the specific EMC requirements stated in the SCD-PVA.

#### Repairability

ECSS-E-ST-20-08\_0090063

The capability of repairing, removing and replacing items down to component level shall be provided.

1. For example, for single SCAs, diodes, thermal sensors, wires and connectors.

## PVA manufacturing

### Process validation

ECSS-E-ST-20-08\_0090064

The manufacturing and integration processes shall be validated for all the project specific design configurations and to meet the engineering design requirements.

### Defect acceptability

ECSS-E-ST-20-08\_0090065

The acceptability of defects at the PVA level shall be:

agreed with the customer;

specified in a production control document;

validated by qualification testing.

### In-process testing

#### Overview

The in-process tests are performed during the manufacturing of the PVA to detect or prevent deviations and defects as early as possible. This clause 5.4.3 lists the test to be performed during the manufacturing of the PVA.

#### Mass measurement

ECSS-E-ST-20-08\_0090066

To determine the add-on mass of the SCA laydown process, the mass of the substrate shall be measured before and after the substrate is equipped with the SCA’s and be in conformance with SCD-PVA.

#### Wet insulation test

ECSS-E-ST-20-08\_0090067

A wet insulation test shall be performed by the supplier to prove the integrity of the bare coupon insulation layer, as follows:

Verify continuity between the conductive layer under the insulation to the test connection point.

For the wet insulation test, use ethyl, isopropyl alcohol, or otherwise an equivalent fluid agreed with the customer, as contact fluid during the measurements.

Apply a voltage which corresponds to the breakthrough value for short term exposure of the applied insulation material (Espec V/m) times the minimum guaranteed thickness.

1. For example, for Espec= 20 V/m and a (50 ± 10) m insulation layer, a test voltage of 1000 V applies.

ECSS-E-ST-20-08\_0090068

The acceptance criteria shall be an insulation larger than 100 MΩ.

ECSS-E-ST-20-08\_0090069

In case of a failure, the coupon insulator layer shall be repaired.

#### Adherence to substrate

ECSS-E-ST-20-08\_0090070

The adherence of the SCAs to the substrate, shall be performed in parallelto panel laydown.

ECSS-E-ST-20-08\_0090071

The adherence to substrate shall be verified by means of one of the following two methods:

Method 1

Bond 3 SCAs following identical process to a representative PVA substrate of the following dimensions: 200 x 130 mm.

After the curing duration and temperature, as specified in the SCD-PVA perform a pull test, with a pull force equal or larger than 1 N/cm2.

Method 2

In case no solar cell assemblies and substrate are available, bond together 2 Kapton foils of the same material as used in representative PVA and with dimensions of 250 mm x 150 mm.

After specified curing duration and temperature, as specified in the SCD-PVA, perform a peel test of the foil according to EN 1464:2010.

Use a peel force equal or larger than 1,8 N/cm.

Ensure that the separation takes place within the adhesive for an area larger than 50 %.

#### Visual inspection

ECSS-E-ST-20-08\_0090072

A visual inspection shall be made before laydown.

1. This is to determine defects, at the latest as possible before bonding. For example: rear sides of solar cells defects, front sides of solar cells defects.

ECSS-E-ST-20-08\_0090073

The visual inspection procedure and criteria shall be agreed with the customer and be described in the SCD-PVA.

#### Continuity check

ECSS-E-ST-20-08\_0090074

The continuity of all strings shall be checked after stringing.

ECSS-E-ST-20-08\_0090075

Continuity of harness, wires and diodes shall be checked, and measured after final assembly.

ECSS-E-ST-20-08\_0090076

The maximum values of resistance shall be given in the SCD-PVA.

### Identification and traceability

ECSS-E-ST-20-08\_0090077

Components other than SCAs, bare cells and coverglasses shall be identified in conformance with the traceability requirements of Class 1 components, and PAD DRD of ECSS-Q-ST-60.

1. For requirements on the identification and traceability of parts and materials, see clauses 6.1.4, 7.1.3 and 8.3.3 for SCAs, bare cells and coverglass, respectively.

### Recording

ECSS-E-ST-20-08\_0090078

Before start manufacturing, all processes and process variables related to PVA manufacturing that have impact on the performance of the process, shall be identified by the supplier.

ECSS-E-ST-20-08\_0090079

The processes variables specified in requirement 5.4.5a shall be recorded during manufacturing.

## PVA tests

### Qualification tests

#### Purpose

Qualification tests are performed to check and qualify the design requirements.

#### Process

ECSS-E-ST-20-08\_0090080

Qualification tests shall be preceded by the acceptance tests as listed in clause 5.5.2, in order to be representative of the life of flight hardware.

ECSS-E-ST-20-08\_0090081

All results of the qualification test shall be reported in a qualification test report.

ECSS-E-ST-20-08\_0090082

Qualification margins shall not exceed component and material specifications unless agreed between supplier and customer.

ECSS-E-ST-20-08\_0090083

The following environmental test shall be performed for qualification of PVAs as applied on solar panels:

Fatigue thermal cycling test on the qualification coupon.

Humidity test performed on dedicated test sample, if specified by the solar array requirements specification.

ESD test on a dedicated ESD coupon, if specified by the solar array requirement specification.

Erosion of materials, due to thruster plume if specified by the solar array requirement specification.

1. The tests to be performed for each qualification are listed in Table 5‑1 and described in clauses 5.5.2 and 5.5.3.

ECSS-E-ST-20-08\_0090084

In cases where the same coupon is used for the fatigue thermal cycling test and the humidity test, in conformance with requirement 5.5.1.2d the humidity test sequence shall precede the fatigue thermal cycling test sequence.

ECSS-E-ST-20-08\_0090085

Except in conformance with requirement 5.5.1.2e, each type of test shall be performed on a dedicated qualification coupon built specifically for the test.

ECSS-E-ST-20-08\_0090086

The qualification coupon need not be the same size as the flight panels, but shall contain a representative number of components to enable reliable verification of flight panel processes and materials.

ECSS-E-ST-20-08\_0090087

The materials and processes used to build the qualification coupon shall be documented in a parts, materials and process (PMP) list to enable verification that the flight panels are built with identical manufacturers, processes, materials and configurations.

ECSS-E-ST-20-08\_0090088

Each qualification coupon shall be flight representative as far as allowed by the dimensions of the qualification coupon

ECSS-E-ST-20-08\_0090089

Facilities shall be available to safely store the qualification hardware (included failed samples) for a minimum of 6 years (equivalent to five years in storage and one year in orbit).

Table ‑: Qualification test plan for PVA

|  |  |  |  |
| --- | --- | --- | --- |
| Check | Fatigue thermal cycling | Humidity test | ESD test |
| Full visual inspection (5.5.3.2) | 1, 6, 9, 14 | 1, 5 | 1, 4 |
| Electrical health check and performance (5.5.3.3 and 5.5.3.4) | 2, 7, 10, 15 | 2, 6 | 2, 5 |
| Capacitance (5.5.3.5) | 3, (11), 16 |  |  |
| X-ray photo (5.5.3.9) | 4, (12), 17 |  |  |
| Reflectance (5.5.3.8) |  | 3, 7 |  |
| Vacuum thermal cycling (5.5.3.11) | 5, 13 |  |  |
| Substrate integrity (5.5.3.10) | 18 |  |  |
| Fatigue thermal cycling (5.5.1.3) | 8 |  |  |
| Humidity (5.5.1.4) |  | 4 |  |
| ESD test (5.5.1.5) |  |  | 3 |
| NOTE 1: The numbers in each column indicate the sequence in which the checks are performed for each test.  NOTE 2 Guidelines for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. | | | |

#### Fatigue thermal cycling test

##### Purpose

The purpose of the thermal cycling test is to demonstrate the life fatigue compatibility of all components and processes in an assembly.

##### General

ECSS-E-ST-20-08\_0090090

The PVA manufacturer shall demonstrate that lack of continuity is avoided at any time during cycles specified in requirement 5.5.1.3.4g, both on the solar cell and on the protection shunt diode circuits.

ECSS-E-ST-20-08\_0090091

The test conditions, specifically the thermal gradients through the test sample thickness, shall be representative of the distribution predicted in space so that the components are not over-stressed or under-stressed beyond specified limits.

ECSS-E-ST-20-08\_0090092

The temperature extremes of the thermal cycling shall be extended or a dedicated structural test be performed in cases where analysis demonstrates that the structural loading results in a greater stress than the thermal cycling.

1. For example, acoustic and noise can produce greater stress than thermal cycling in certain missions.

##### Qualification coupon

ECSS-E-ST-20-08\_0090093

The qualification coupon shall be defined by means of a representative drawing, document or matrix in the SCD-PVA.

1. It is good practice to maximize the number of applied solar cells on the coupon substrate available area. Depending on the complexity of the design and mission, heritage and TRL, the number of required solar cells might lead to more than one qualification coupon.

ECSS-E-ST-20-08\_0090094

The representation of the critical areas of the solar array on the qualification coupon shall be agreed with the customer.

1. For example, the substrate represents a worst-case stress part of the flight panels.

ECSS-E-ST-20-08\_0090095

The qualification coupon shall be manufactured using the same design, substrates, materials, processes and manufacturers as for the flight panel, furthermore, any deviation be identified by the PVA/Solar Array supplier.

1. The same materials means the same material specification, but is not linked to manufacturing batches or lots.

ECSS-E-ST-20-08\_0090096

In case the qualification coupon contains more than one PVA technology, fulfilling 5.5.1.2g, the coupon design shall allow to qualify those technologies separately ensuring that:

a failure of a given technology does not propagate to the other technologies, and

qualification testing is able to discriminate success of failure of each technology independently.

ECSS-E-ST-20-08\_0090097

The number of (non-cell) components shall correspond to the number in a flight configuration of the unit they belong to, but with a minimum of two.

1. For example, it can be one blocking diode per string, one shunt diodes per shunt interval, and two bleed resistors per panel, but in accordance with this requirement, in all these cases the minimum number is two.

ECSS-E-ST-20-08\_0091069

If space is available, additional components and technologies may be included to be tested as separate items.

ECSS-E-ST-20-08\_0090099

For every type of solar cell configuration (N-end tab, P-end tab or middle cell) one piece shall be repaired on the coupon after the acceptance test (only visual inspection and electrical health check), unless configurations are identical, in which case at least two cells shall be repaired.

ECSS-E-ST-20-08\_0090100

The production of the qualification coupons shall be representative of the full processing of the flight hardware.

ECSS-E-ST-20-08\_0090101

At least 3 thermocouples on the front side and 3 on the rearside of each qualification coupon shall be placed for temperature monitoring.

ECSS-E-ST-20-08\_0091106

The qualification coupon subjected to the fatigue thermal cycling test need not follow the acceptance test sequence.

ECSS-E-ST-20-08\_0090103

Dedicated electrical test points shall be included in the electrical design of the qualification coupon such that the capacitance of single strings can be measured.

##### Test

ECSS-E-ST-20-08\_0091070

The number of cycles and temperature deltas may be determined using one of the following criteria:

The number of cycles is four times the number of cycles that occur during the mission with 0 C temperature delta (at both upper and lower design temperature limit).

The number of cycles is equal to 1,5 times the number of cycles occurring during the mission with a temperature delta of 10 C at extremes (both upper and lower qualification temperature limit).

ECSS-E-ST-20-08\_0090105

If qualification margin temperature exceeds the brittle point of main elements of the PVA, the option to be used in conformance with requirement 5.5.1.3.4a shall be agreed with the customer.

ECSS-E-ST-20-08\_0090106

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ECSS-E-ST-20-08\_0090107

The following cycling profiles shall be used:

A temperature profile which envelopes the variation of temperature extremes during the mission.

The total profile can be divided into sub-profiles.

ECSS-E-ST-20-08\_0090108

The number of cycles, pressure limit, gas composition and temperature limits of requirements 5.5.1.3.4a and 5.5.1.3.4b shall be stated in the SCD-PVA.

ECSS-E-ST-20-08\_0090109

Monitoring of the insulation between the solar cell circuit and the substrate shall:

be performed in conformance with clause 5.5.3.3.3, and

take place during the cycles with the maximum temperature limits and for a minimum of two cycles at each test interval.

ECSS-E-ST-20-08\_0090110

Monitoring of the continuity of the solar cell circuits shall:

be performed in conformance with clause 5.5.3.3.2,

take place during cycles for the complete activity,

be performed on a regularly switching between two polarities, biasing change rate to be agreed with the customer.

be performed by measuring both cell circuit continuity, at the beginning and at the end of the cycles in conformance to the relevant percentage specified in requirement 5.5.1.3.4g.3.

ECSS-E-ST-20-08\_0090111

Insulation and continuity shall not be measured simultaneously.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090112

On completion the test, the following conditions shall be met:

there is electrical continuity (no open circuit), and

the power output of the test coupon and the insulation is within the limits stated in the SCD-PVA.

#### Humidity

##### Purpose

The purpose of the humidity test is to demonstrate the endurance of assembled PVA components in a real-life environment against standard environmental conditions using accelerated tests.

##### General

ECSS-E-ST-20-08\_0090113

If there are requirements on specific environmental conditions, they shall be stated in the SCD-PVA.

1. For example, chemical vapour requirements.

##### Test Sample

ECSS-E-ST-20-08\_0090114

The test sample shall be manufactured using the same qualified materials and processes as the flight panels.

ECSS-E-ST-20-08\_0090115

The production of the test sample shall be representative of the full processing of the flight hardware.

##### Test

ECSS-E-ST-20-08\_0090116

The test sample shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090117

The chamber temperature shall then be increased to 60 C minimum.

ECSS-E-ST-20-08\_0090118

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090119

The duration of the test shall be 30 days.

1. Aluminium containing layers are known to be sensitive to humidity.

ECSS-E-ST-20-08\_0090120

<<deleted>>

ECSS-E-ST-20-08\_0090121

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090122

Water condensation on the surface of the test sample shall be prevented.

ECSS-E-ST-20-08\_0090123

If there are requirements on specific environmental conditions, they shall be stated in the SCD-SCA.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090124

On completion the test, the following conditions shall be met:

there is electrical continuity (no open circuit), and

the power output of the test coupon and the insulation is within the limits stated in the SCD-PVA for the specified temperatures.

#### Electrostatic discharge (ESD) test

##### Purpose

The purpose of the ESD test is to demonstrate that the use of adequate design rules reduces the risk of ESD. This is done by demonstrating that ESD primary discharge does not lead to a secondary arc, which can lead to permanent losses of power and/or insulation in the solar array.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090125

No permanent sustained arc (PSA) shall occur during the testing of the conditions as specified in 5.5.1.5.3e.1, 5.5.1.5.3e.2, and 5.5.1.5.3e.3.

1. TSA max duration is here assuming a minimum 0,5 mm gap length between solar cells mounted on isolative substrate.

ECSS-E-ST-20-08\_0090126

Testing shall demonstrate that the occurred arcs, initiated under 5.5.1.5.3e.1, 5.5.1.5.3e.2 and 5.5.1.5.3e.3, do not produce damage to the cells or the insulation.

1. Damage to the cells has to be understood that electrical performance testing demonstrates that no degradation occur with respect to the values found before test (within typical uncertainties related to the reproducibility of the measurement, typically ±2‑3 %).

ECSS-E-ST-20-08\_0091107

During the testing of the worst case nominal operational conditions without margins, as specified in 5.5.1.5.3c, no failure, no permanent sustained arc (PSA) nor a temporary sustained arc (TSA) above 1,2 ms shall occur.

1. EMAGS3 European study demonstrated that flashover durations could last up to 800 µs on an 8 m² panel. This serves up to now as the common reference widely used for ESD testing including flashover. In case new studies, experiments or findings indicate that longer primary ESDs are practically possible on the solar generators, those conditions are currently not covered by this standard.

ECSS-E-ST-20-08\_0091108

Dark I-V measurement shall be performed in-situ as a minimum at the beginning and at the end of the ESD test campaign.

1. It is recommended to repeat dark I-V measurements after each ESD > 800µs to demonstrate that there is no damage.

##### Process

ECSS-E-ST-20-08\_0091109

The ESD tests shall be performed on solar array coupons using instrumentation specially designed for that purpose as described in clause 7 of ECSS-E-ST-20-06.

ECSS-E-ST-20-08\_0091110

The ESD tests shall cover **worst case nominal operational conditions** as specified in 5.5.1.5.3c and **worst case conditions** (not nominal) as specified in 5.5.1.5.3d and with safety factors as specified in 5.5.1.5.3e.

ECSS-E-ST-20-08\_0091111

The worst case nominal operational condition shall cover:

the minimum gap between adjacent strings occurring in the design including any tolerances;

the mission scenarios, whichever yield the highest calculated voltages or currents respectively, between adjacent strings within the PVA network;

the maximum voltage in the gap between any adjacent cells in consideration of the PVA lay-out design;

static operational modes only, without any short term peaks during switching;

shadow cases, partial or full, if any, with corresponding angle of incidence and associated current production;

light reflection cases, if any, which increase the generated current;

the solar array operational modes imposed by the solar array power regulator architecture;

the worst case possible combinations of gap, voltage and current.

1. 1 to item 1: Examples of mission scenarios are: best case BOL or worst case EOL).
2. 2 to item 3: e.g. parallel strings, U-shaped strings, anti-parallel strings.
3. 3 to item 7: e.g. S3R (typically operated between [0 V, Isc] and [Vop, Iop]) or MPPT (typically operated between [Vmp, Imp] and [Voc, 0 A]).
4. 4 to item 8: Combinations of gap, voltage and current can be within a section and between sections where different combinations apply.

ECSS-E-ST-20-08\_0091112

The worst case condition (not nominal) as specified by 5.5.1.5.2c shall consider the addition of the following:

a single hardware failure does not propagate to neighbouring components circuits or interfaces in an undetermined way;

the solar array is specified to provide the requested power and ensure the energy balance in each mission phase during operational life including any string loss tolerance defined by the customer, spacecraft charging effects and worst case conditions;

provision are made against potential failure propagation in case of short-circuit failure of a solar array section or short circuit of its connection to the power subsystem.

1. 1 This means that at least a single non-functionality of any component is part of the worst case condition. E.g. in a PVA design with one blocking diode per string only, the scenarios of a blocking diode being either in short or in open are part of the worst case.
2. 2 The solar array is designed to be single-failure tolerant at string level.

ECSS-E-ST-20-08\_0091113

ESD tests shall be started with the combination of gap, voltage and current as specified in 5.5.1.5.2c and 5.5.1.5.2d, followed by a gradual increase of either the parameter voltage or current, but not simultaneously, until the conditions as specified hereafter are met:

For 5.5.1.5.2c (worst case nominal operational condition) a safety factor of 2 or a margin of 50 V, whichever is lower, is demonstrated for the voltage while the current is nominal.

For 5.5.1.5.2c (worst case nominal operational condition) a safety factor of 1,2 is demonstrated for the current while the voltage is nominal.

For 5.5.1.5.2d (worst case condition) no additional margins need to be demonstrated.

1. 1 If the conditions as specified in 5.5.1.5.3e.1, 5.5.1.5.3e.2 and 5.5.1.5.3e.3 were reached without triggering a permanent sustained secondary arc, and after meeting the requirement 5.5.1.5.2c, the parameters voltage and current can be gradually increased until a permanent sustained secondary arc is triggered or until a major power degradation or loss of insulation is detected in order to derive the margin of the design. This can require a dedicated test coupon or a 2nd test campaign after the requirement 5.5.1.5.2c was verified.
2. 2 To derive the absolute margins of the design for current and voltage independently, 2 coupons per gap are needed, i.e. one with the worst case voltage fixed and corresponding current for triggering a permanent sustained arc and one with the worst case current fixed and corresponding voltage for triggering a permanent sustained arc, or a failure (dark IV degradation, loss of insulation). For this task (derivation of absolute margins) it is good practice to monitor the integrity of the hardware with respect to power and insulation by performing a dark-IV and insulation measurement after each ESD with a duration > 800 µs if any and as a minimum after every 10 ESDs.

#### Erosion of materials

ECSS-E-ST-20-08\_0090127

The test sequence, test definitions and requirements for the tests for erosion of material shall be agreed between the supplier and the customer and stated in the SCD-PVA.

#### EMC

ECSS-E-ST-20-08\_0090128

The test sequence, test definitions and requirements related to the EMC of the PVA shall be agreed between the supplier and the customer and given in the SCD-PVA.

### Acceptance tests for qualification coupons

#### Purpose

The acceptance tests are performed to check the workmanship of the supplier.

#### Applicability

ECSS-E-ST-20-08\_0091114

Qualification coupons shall follow the acceptance test program as shown in Table 5‑2, if not covered by qualification tests as specified in Table 5‑1.

1. 1 The thermal cycling acceptance testing, specified in 5.5.3.7, is typically covered by the vacuum thermal cycling, specified in 5.5.3.11, of the qualification test program.
2. 2 Flight hardware is subject to acceptance testing after qualification has been successfully completed, ref ECSS-E-ST-10-03.

#### Deliverables

ECSS-E-ST-20-08\_0090129

The deliverable documentation shall be agreed with the customer.

1. The acceptance is dependent on this test and the documentation delivered.

#### Process

ECSS-E-ST-20-08\_0090130

All acceptance tests shall be in conformance with clause 5.2.

ECSS-E-ST-20-08\_0090131

All results of the acceptance test shall be reported in the data documentation package (DDP).

1. For the DDP, see clause 5.7 and Annex G.

ECSS-E-ST-20-08\_0090132

The standard sequence of acceptance tests for PVA shall be as presented in Table 5‑2.

ECSS-E-ST-20-08\_0090133

The bake-out test shall be performed as part of the coupon acceptance test sequence only in the cases where the bake-out is included in the manufacturing process or in the acceptance test of the flight panels.

ECSS-E-ST-20-08\_0091031

Table ‑: Acceptance test plan

|  |  |
| --- | --- |
| Sequence number | Test |
| Add-on mass (5.5.3.1) | 0 |
| Full visual inspection (5.5.3.2) | 1, 6, 10 |
| Electrical health check (5.5.3.3) | 2, 7, 11 |
| Capacitance (5.5.3.5) | 3, 13 |
| Electrical performance (5.5.3.4) | 4, 8,12 |
| Bake-out (5.5.3.6) | 5 |
| Thermal cycling (5.5.3.7) | 9 |
| NOTE: See 5.5.2.4d | |

### Definition of tests and checks

#### Add-on mass measurement

ECSS-E-ST-20-08\_0090134

The mass of the panel shall be measured after the coupon is equipped with the PVA parts and the harness, and the add-on mass deduced.

ECSS-E-ST-20-08\_0090135

The add-on mass of both the PVA and the harness shall be in conformance with the value given the SCD-PVA.

#### Full visual inspection

##### Purpose

The full VI is performed to detect imperfections in the complete hardware.

##### Process

ECSS-E-ST-20-08\_0090136

A full visual inspection shall be performed against the inspection requirements stated in clauses 5.5.3.2.4 to 5.5.3.2.21, as follows:

Visually examine each component for workmanship, identification and finish.

Examine the deliverable items for conformance to general assembly drawings, with respect to critical dimensional parameters.

1. The inspection methods to be used include:

* electroluminescence (ELM) or photoluminescence (PLM)
* infrared inspection;
* inspection with the naked eye;
* inspection using microscopes;
* any equivalent methods.

ECSS-E-ST-20-08\_0090137

Training records of the personnel performing the visual inspection shall be made available to the customer under request.

##### General criteria

ECSS-E-ST-20-08\_0090138

The PVA supplier shall define the inspection criteria for the PVA components, to be agreed by the customer, and included in the SCD-PVA.

##### Visual inspection of dimensions, stay-out zones, and stand-offs

ECSS-E-ST-20-08\_0090139

The dimensions shall conform to the qualification coupon assembly drawing.

ECSS-E-ST-20-08\_0090140

Cells and components shall not enter the stay-out zones indicated on the qualification coupon assembly drawing.

ECSS-E-ST-20-08\_0090141

The stand-off distance of cells and components shall conform to the qualification coupon assembly drawing.

##### Visual inspection of the substrate

ECSS-E-ST-20-08\_0090142

Substrates shall be inspected for any damage due to coupon assembly, handling and testing.

ECSS-E-ST-20-08\_0090143

The insulator material shall show no evidence of delamination.

1. The insulator material is usually kapton.

ECSS-E-ST-20-08\_0090144

The integrity of the substrate shall not deviate from the coupon assembly drawing.

##### Visual inspection of the coverglass

ECSS-E-ST-20-08\_0090145

All the coverglass shall be inspected for defects in conformance with requirements 5.5.3.2.6b to 5.5.3.2.6e.

ECSS-E-ST-20-08\_0090146

No more than 5 % of the total number of coverglasses shall exhibit any of the following defects on the coupon, due to assembly, handling and acceptance:

For 100 % covered cells, or cells where the unprotected solar cell surface is covered with the coverglass adhesive up to a maximum of 5 % of the cell area, chips and nicks in the coverglass with the characteristics specified in clause 6.4.3.1.5.

Cracks on the coverglass, except if they meet the following conditions:

no visible separation (in conformance with clause 6.4.3.1.5);

no more than three per cover;

meeting cracks if they are separated by more than 2 mm at the non-meeting end.

ECSS-E-ST-20-08\_0090147

Any defect in conformance with requirement 5.5.3.2.6b, raised after acceptance shall be reported and traced throughout the qualification sequence.

ECSS-E-ST-20-08\_0090148

Covers with dirty and contaminated surfaces shall be cleaned.

ECSS-E-ST-20-08\_0090149

Coverglasses with any of the following defects shall be rejected at the end of acceptance:

Coverglasses installed upside down as indicated by improper location of the coating orientation mark in conformance with clause 8.3.3.

Coverglass which is not flush with or overhanging all four cell edges.

Coverglasses with dirty and contaminated surface if they cannot be cleaned.

Loose coverglasses.

Corner chip exceeding the limits specified in requirement 5.5.3.2.6b.1.

Edge chips exceeding the limits specified in clause 6.4.3.1.4.

Coverglasses with intersecting cracks exceeding the limits specified clause 6.4.3.1.4.

##### Visual inspection of the coverglass adhesive

ECSS-E-ST-20-08\_0090150

After coverglass or solar cell repair, there shall be no delamination or discoloration in the adhesive, except in the area opposite rear welds, where discoloration is allowed.

ECSS-E-ST-20-08\_0090151

After coverglass or solar cell repair, adhesive voids along the cover edge shall not exceed 0,6 mm in depth.

ECSS-E-ST-20-08\_0090152

After coverglass or solar cell repair, the maximum total projected area of additional bubbles shall not exceed 0,2 % of cell area, discounting:

bubbles less than 0,02 mm2 in the projected area, and

bubbles, discolorations and voids located at less than 2 mm from the interconnector edges.

##### Visual inspection of the solar cells

ECSS-E-ST-20-08\_0090153

No more than 2 % of the total quantity of solar cells or one cell, whichever is larger, per coupon shall exhibit any of the following defects:

More than the number of cracks per cell specified in the SCD-PVA.

Cracks crossing more than the number of different gridlines specified in the SCD-PVA.

Corner chips and edge chips greater than those specified in clause 6.4.3.1.4.

ECSS-E-ST-20-08\_0090154

Any imperfections listed in requirements 5.5.3.2.8a.1 to 5.5.3.2.8a.3, raised after acceptance shall be reported and traced throughout the qualification sequence.

ECSS-E-ST-20-08\_0090155

Solar cells with any of the following defects shall be rejected at the end of acceptance:

Cracks crossing more gridlines than specified in requirement 5.5.3.2.8a.2.

More cracks than specified in requirement 5.5.3.2.8a.1 on a single cell.

Cracks between the cell edges parallel to the gridlines and the outermost edges of the interconnectors.

Corner chip exceeding the limits specified in clause 6.4.3.1.4.

Edge chips exceeding the limits specified in clause 6.4.3.1.4.

1. to item 1: Multiple crossing of the same gridline can be present.

##### Visual inspection of the solar cell bypass diodes

ECSS-E-ST-20-08\_0090156

Cracks in the body of the diode, causing separation of the material, shall not be present.

ECSS-E-ST-20-08\_0091071

Tarnishing of the diode body or attachment serpentines may be present.

ECSS-E-ST-20-08\_0091115

The current leakage of by-pass diodes shall be evaluated by the inspection of reverse polarized by-pass diodes with a thermographic camera.

##### Visual inspection of the interconnectors

ECSS-E-ST-20-08\_0090158

No more than 2 % of the total number of interconnectors and no more than one interconnector per cell shall exhibit any of the following defects at the end of acceptance testing:

Deformation.

Solder or adhesive blocking, bridging, plugging or otherwise impeding the flexure of the stress relief loop.

Foreign matter or contamination on the interconnector or within the interconnector weld or solder joint or within the stress relief loop.

ECSS-E-ST-20-08\_0090159

Any imperfections listed in requirements 5.5.3.2.10a.1 to 5.5.3.2.10a.3, raised after acceptance shall be reported and traced throughout the qualification sequence.

ECSS-E-ST-20-08\_0090160

None of the interconnectors shall exhibit lifting tears, breaks or cracks.

ECSS-E-ST-20-08\_0091072

Interconnectors may be tarnished.

##### Visual inspection of the bus bars

ECSS-E-ST-20-08\_0090162

None of the bus bars shall exhibit any of the following defects at the end of acceptance testing:

Solder or adhesive blocking, bridging, plugging or otherwise impede the flexure of stress relief loops between solar cell strings.

Foreign matter, or contamination on the interconnector, within the interconnector weld or solder joint, or within the stress relief loop.

Tears, breaks or cracks.

ECSS-E-ST-20-08\_0090163

Any defect listed in requirements 5.5.3.2.11a.1 to 5.5.3.2.11a.3, raised after acceptance shall be reported and traced throughout the qualification sequence.

ECSS-E-ST-20-08\_0091073

Tarnishing may be present on the end terminations.

##### Visual inspection of the wiring

ECSS-E-ST-20-08\_0090165

None of the wiring shall exhibit any of the following defects at the end of acceptance testing:

Sharp bends, sharp twists, sharp buckles or creases in the wire.

Delamination or looseness of the wire attachment.

Chafing or abrasion of the wire insulation.

Cracks, breaks or nicks in the wire insulation or conductor.

Exposed shields on shielded wires.

ECSS-E-ST-20-08\_0090166

Any defects listed in requirements 5.5.3.2.12a.1 to 5.5.3.2.12a.5, raised after acceptance shall be reported and traced throughout the qualification sequence.

##### Visual inspection of the soldering

ECSS-E-ST-20-08\_0090167

Soldering of wires at string terminations and terminals shall be in conformance with a standard agreed with the customer

1. For soldering, see for instance ECSS-Q-ST-70-61.

##### Visual inspection of the welding

ECSS-E-ST-20-08\_0090168

Welding of wires at string terminations and terminals shall be in conformance with the SCD-PVA.

##### Visual inspection of the crimping

ECSS-E-ST-20-08\_0090169

Crimping of wires shall be in conformance with a standard agreed with the customer.

1. For crimping, see for instance ECSS-Q-ST-70-26.

##### Visual inspection of the attachment materials

ECSS-E-ST-20-08\_0090170

Attachments based on bonding techniques shall be fully cured and not exhibit any tackiness.

##### Visual inspection of the feed-throughs

ECSS-E-ST-20-08\_0090171

Feed-throughs shall be firmly bonded.

ECSS-E-ST-20-08\_0090172

Feed-throughs shall conform to the locations specified on the top assembly drawing.

##### Visual inspection of the marking

ECSS-E-ST-20-08\_0090173

All identification markings specified by the customer shall be firmly adhered to the locations identified on the assembly drawing.

ECSS-E-ST-20-08\_0090174

Identification markings shall be clearly legible.

##### Visual inspection of the hardware

ECSS-E-ST-20-08\_0090175

Terminal board locations shall conform to the qualification coupon assembly drawing.

ECSS-E-ST-20-08\_0090176

Stand-off of all components shall conform to the qualification coupon assembly drawing.

ECSS-E-ST-20-08\_0090177

For mounted components (temperature sensor, resistors and diodes), the following shall be performed:

Verify the status of the following items:

fixation on the substrate;

body aspect and absence of cracks;

connections;

shrinkage tube.

Ensure that conformal coating of the components,:

consist of a uniform layer of the specified adhesive, and

encapsulate the components.

ECSS-E-ST-20-08\_0090178

For the connectors, the status of the following items shall be verified:

fixing on the substrate;

absence of cracks;

connections;

shrinkage tube.

##### Visual inspection of the bonding integrity

ECSS-E-ST-20-08\_0090179

100 % of the solar cells shall be inspected for bond integrity.

ECSS-E-ST-20-08\_0090180

Any loose cells shall not be used unless an engineering disposition, specifying that it can be used, is issued.

##### Visual inspection of the cleanliness

ECSS-E-ST-20-08\_0090181

When visually examined with the unaided eye, the coupon shall appear clean.

ECSS-E-ST-20-08\_0090182

There shall be no loose material on the coupon.

#### Electrical health check

##### Purpose

All tests specified in this clause are part of the electrical health check. The purpose of the electrical health check together with the electrical performance measurement is to detect faults in the electrical functions of the electrically active parts of the PVA.

##### Electrical continuity check

ECSS-E-ST-20-08\_0090183

All electrical circuits of the PVA shall be checked to ensure electrical continuity, and the test conditions are stated in the SCD-PVA.

##### Insulation resistance

ECSS-E-ST-20-08\_0090184

An insulation test shall be performed at the voltage stated in the SCD-PVA to measure the insulation between the following:

the structure ground or substrate (+) and the solar cell circuits (-) including soldering and wiring;

adjacent solar cell strings if not parallel connected;

the thermal sensor (+) and the substrate (-);

the thermal sensor (+) and cell strings (-);

the cover glass network (-) to cell strings (+) if the coverglass network is grounded;

the cover glass network (+) to cell strings (-) if the coverglass network can be disconnected,

the cover glass network (-) to structure ground or substrate (+) if each coverglass is connected to each cell.

1. 1 (+) is understood as the positive polarity of the megohmmeter and the (-) is the negative polarity of the megohmmeter.
2. 2 Examples are:

* for item 1: at 500 V: > 100 MΩ at Tamb
* for item 2: at +/-250 V: > 100 MΩ at Tamb
* for item 3: at 500 V: > 100 MΩ at Tamb
* for item 4: at 500 V: > 100 MΩ at Tamb
* for item 5: at 150 V or Voc, whichever is higher: > 100 MΩ at Tamb
* for item 6: at 150 V or Voc, whichever is higher: > 100 MΩt Tamb
* for item 7: at 500 V: > 100 MΩ at Tamb

ECSS-E-ST-20-08\_0090185

The insulation shall be in conformance with that stated in the SCD-PVA.

##### Grounding resistance test

ECSS-E-ST-20-08\_0090186

All resistance at grounding spots shall be measured.

ECSS-E-ST-20-08\_0090187

The grounding resistance shall be the value stated in the SCD-PVA.

##### Bleed resistor test

ECSS-E-ST-20-08\_0090188

The resistance of the bleed resistor shall be measured.

ECSS-E-ST-20-08\_0090189

The resistance shall be the value stated in the SCD-PVA.

##### Blocking diode test

ECSS-E-ST-20-08\_0090190

The reverse current of the blocking diode shall be measured of at a voltage equal to the predicted maximum Voc during the mission.

ECSS-E-ST-20-08\_0090191

The reverse current measured shall be negligible with respect to the string current (usually less than 5 mA).

ECSS-E-ST-20-08\_0090192

The forward voltage drop of the blocking diode shall be measured with the string at maximum Isc current.

ECSS-E-ST-20-08\_0090193

Test conditions and requirements shall be stated in the SCD-PVA.

##### Shunt diode test

ECSS-E-ST-20-08\_0090194

When all the cells are protected by shunt diodes, the forward voltage of shunt diodes shall be measured by reverse mode measurement of the interconnected string at the maximum operating current and the measured voltage be equal ±1 % to the sum of the individual diode forward voltages at the maximum current.

ECSS-E-ST-20-08\_0090195

When all the cells are protected by shunt diodes, the supplier shall provide the test method and precautions to be taken.

ECSS-E-ST-20-08\_0090196

When all the cells are protected by shunt diodes, during the test, the temperature increase of the shunt diode shall be uniform and not exceed the value stated in the SCD-PVA.

1. If the measured voltage is outside the sum of the individual diode forward voltages at the maximum current ±1 %, techniques such as thermographic photo recordings can be used to locate the failed shunt diodes.

##### Thermal sensor test

ECSS-E-ST-20-08\_0090197

The thermal sensor resistance shall be measured at room temperature.

ECSS-E-ST-20-08\_0090198

The thermal sensor resistance shall be the value stated in the SCD PVA.

##### Resistance measurement

ECSS-E-ST-20-08\_0090199

The resistance of the harness shall be measured at the interface connector by measuring the redundant coupon wiring in series (i.e. positive end to positive end and negative end to negative end).

ECSS-E-ST-20-08\_0090200

Test conditions and requirements shall be described in the SCD-PVA.

#### Electrical performance measurement

##### Purpose

The power output is measured in order to be able to detect any degradation before and after testing.

##### Process

ECSS-E-ST-20-08\_0090201

The electrical power performance at the string level shall be measured at a reference temperature of 25 C at the interface connector.

ECSS-E-ST-20-08\_0090202

The performance measurement shall be made under 1 S.C. (AM0).

1. The characteristics of the Sun simulator are given in clause 10.

ECSS-E-ST-20-08\_0090203

The results shall be in conformance with those stated in the SCD-PVA.

ECSS-E-ST-20-08\_0090204

The inaccuracies in current, voltage and power shall be specified in the SCD-PVA and include:

spectral mismatch;

uniformity of the test area;

dynamic electrical effects of the test item

inaccuracies of the temperature sensors.

1. to item 3: Example: capacitance.

ECSS-E-ST-20-08\_0090205

Calibration shall be done with an agreed primary standard reference and secondary working standard (SWS) in conformance with clause 10.

ECSS-E-ST-20-08\_0090206

Pre-test and post-test measurements shall be made with the same test set‑up.

#### Capacitance test

##### Purpose

The purpose of the test is to measure the capacitance of the PVA by measuring the string capacitance in order to characterise the electrical dynamical behaviour of the PVA in interaction with the power regulator. Different types of power regulator require different measurement techniques. The methods described in clause 5.5.3.5.2 are applicable only to PVA interacting with a sequential switching shunt regulator.

##### Process

ECSS-E-ST-20-08\_0090207

One of the following methods shall be followed for capacitance measurement:

frequency domain single junction solar cell capacitance measurement as described in clause 11.1,

Time domain capacitance measurement as described in clause 11.2.

1. to item 1: No method available for multi-junction measurement at the time being.

ECSS-E-ST-20-08\_0090208

The method for measuring the capacitance shall be stated in the SCD‑PVA.

ECSS-E-ST-20-08\_0090209

The capacitance shall be measured at room temperature and averaged operational temperature.

ECSS-E-ST-20-08\_0091074

The measurement at averaged operational temperature may be replaced by measurement of the SCA capacitance at operational temperature.

#### Bake-out

ECSS-E-ST-20-08\_0090211

Measures to prevent outgassing, to be taken before exposure to thermal vacuum test, shall be agreed with the customer and specified in the SCD-PVA.

1. If not specified in SCD-PVA the ECSS-Q-ST-70-01 is not automatically applicable concerning bake-out.

ECSS-E-ST-20-08\_0090212

Bake-out shall be performed in vacuum.

1. Monitoring of outgassing during bake-out can be done with TQCM in case specified by the project.

ECSS-E-ST-20-08\_0090213

Temperature and test conditions shall be specified in SCD-PVA.

#### Thermal cycling acceptance test

##### Purpose

The thermal cycle acceptance tests assess the reliability of the PVA under stress and verify the workmanship of the supplier. In this way infant mortality stresses are identified and these parts can be replaced.

##### General

ECSS-E-ST-20-08\_0091075

Thermal vacuum cycling should be used.

ECSS-E-ST-20-08\_0090215

If gaseous cycling tests are used, the supplier shall demonstrate the equivalence of the test method by testing.

1. The demonstration of equivalence is achieved, when all possible vacuum related defects were represented on the items under test for demonstration.

ECSS-E-ST-20-08\_0090216

The temperature extremes of the thermal cycling shall be extended or a dedicated structural test be performed in cases where analysis demonstrates that the structural loading results in a greater stress than the thermal cycling.

##### Process

ECSS-E-ST-20-08\_0090217

The coupons shall be exposed to the number of thermal cycles for acceptance in accordance with ECSS-E-ST-10-03 Table 5-4.

ECSS-E-ST-20-08\_0090218

The number of cycles specified in requirement 5.5.3.7.3a shall be between 3 and 10.

ECSS-E-ST-20-08\_0090219

The temperature profile shall be the worst-case nominal temperature profile with a 5 C margin.

ECSS-E-ST-20-08\_0090220

During thermal cycling, the electrical insulation shall be measured.

ECSS-E-ST-20-08\_0090221

During thermal cycling, the continuity shall be measured at least during the last cycle.

ECSS-E-ST-20-08\_0090222

Continuity and insulation shall not be measured simultaneously.

ECSS-E-ST-20-08\_0090223

Acceptance criteria shall be:

A maximum increment of IOP, and a minimum isolation, as stated in the SCD-PVA.

The existence of electrical continuity (no open circuit).

At the end of the test, less than a 2 % increase in cracked cells or one cracked cell, whichever is higher, not cumulative with the results of the bake-out test and which can have an impact on the electrical performance of the string.

#### Reflectance

ECSS-E-ST-20-08\_0090224

The reflectance of the solar cell surface shall be measured before and after the humidity test to determine the possible degradation of the coverglass coatings.

ECSS-E-ST-20-08\_0090225

The reflectance shall be measured over a range from 280 nm to 2  500 nm.

ECSS-E-ST-20-08\_0090226

The reflectance shall not change during testing more than as stated in the SCD-PVA.

#### X-Ray

ECSS-E-ST-20-08\_0090227

X-ray photographs shall be taken of all busbars, wire collection strips and diode boards on the qualification coupons.

ECSS-E-ST-20-08\_0090228

The acceptance criteria shall be stated in the SCD-PVA.

1. Defects that cannot be detected by means of visual inspections (e.g. internal structural deformations or alterations in busbars and wire connections) can be traced by X-ray photographs.

#### Substrate integrity

##### Process

ECSS-E-ST-20-08\_0090229

The structural integrity of the substrate shall be inspected after thermal cycling.

ECSS-E-ST-20-08\_0091076

A non-destructive test method should be used for the inspection specified in requirement 5.5.3.10.1a.

ECSS-E-ST-20-08\_0090231

If requirement 5.5.3.10.1b cannot be satisfied, a destructive test shall be applied.

ECSS-E-ST-20-08\_0090232

The test method shall be described in the SCD-PVA.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090233

The pass-fail criteria shall be those stated in the SCD-PVA.

#### Vacuum thermal cycling

##### Purpose

Vacuum thermal cycling is performed in order to verify the integrity of components, assemblies and interfaces in a vacuum environment.

##### Process

ECSS-E-ST-20-08\_0090234

The components to be checked for electrical continuity shall be identified in the SCD-PVA.

ECSS-E-ST-20-08\_0090235

The qualification coupon shall be exposed to vacuum thermal cycling.

ECSS-E-ST-20-08\_0090236

The qualification coupon shall be exposed to 10 vacuum thermal cycles

ECSS-E-ST-20-08\_0090237

The pressure shall be lower than 2 × 10-3 Pa.

ECSS-E-ST-20-08\_0090238

The temperature profile shall be the worst-case nominal temperature profile including uncertainty, being the predicted temperature, and addition of acceptance margin of 5 K and qualification margin of 5 K, leading to a nominal margin of 10 K to reach qualification.

1. Allowed deviations from this requirement for temperatures below ‐170 °C, or above 120 °C are specified in requirements 5.5.3.11.2i and 5.5.3.11.2j.

ECSS-E-ST-20-08\_0090239

During vacuum thermal cycling the electrical continuity of the components identified in requirement 5.5.3.11.2a, including if present (at least) strings, diodes, thermal sensors and resistors, shall be recorded.

ECSS-E-ST-20-08\_0090240

The insulation resistance of the strings against the substrate shall be recorded for a minimum of 2 cycles, without performing electrical continuity.

ECSS-E-ST-20-08\_0091116

The hot and cold plateau shall be maintained for a duration of 2 hours.

1. The plateau starts when the average of the thermocouples on the front side reach the target temperature.

ECSS-E-ST-20-08\_0091117

For temperatures below ‐170 °C, lower acceptance and qualification margin as specified 5.5.3.11.2e, may be used in agreement with the customer.

ECSS-E-ST-20-08\_0091118

For temperatures above +120 °C, higher acceptance and qualification margin as specified 5.5.3.11.2e may be used in agreement with the customer.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090241

The qualification coupon electrical performance and insulation resistance shall not degrade more than as stated in the SCD-PVA.

ECSS-E-ST-20-08\_0090242

No open circuit conditions shall be recorded during continuity testing.

ECSS-E-ST-20-08\_0090243

There shall be less than a 2 % increase in cracked cells or one cracked cell, whichever is higher, not cumulative with the results of the fatigue thermal cycling test, and which can have an impact on the electrical performance of the string.

## Failure definition

### Failure criteria

ECSS-E-ST-20-08\_0090244

The following shall constitute PVA failures:

Coupons that fail during subgroup tests for which the pass-fail criteria are inherent in the test method.

Coupons failing to conform to the requirements of the visual inspection as listed in the SCD-PVA.

Coupons that fail to conform to stress requirements as listed in the SCD-PVA.

Coupons that, when subjected to electrical performance measurements after qualification tests in conformance with the SCD-PVA, fail one or more of the stated limits, measurement accuracy included.

### Failed qualification coupons

ECSS-E-ST-20-08\_0090245

A coupon shall be considered as failed if it exhibits one or more of the failure modes detailed in requirement 5.6.1a.

ECSS-E-ST-20-08\_0090246

Failure analysis of these coupons shall be performed by the supplier and the results provided to the customer, as part of an NRB documentation.

1. For NRB, see ECSS-Q-ST-10-09.

## Data documentation

ECSS-E-ST-20-08\_0090247

The supplier shall provide a data documentation package (DDP) in conformance with Annex G for the qualification approval records for each coupon.

## Delivery

ECSS-E-ST-20-08\_0090248

All deliverable hardware specified in the order shall be delivered together with documentation in conformance with clause 5.7.

ECSS-E-ST-20-08\_0090249

One set of documents shall be sent to the customer.

## Packaging, packing, handling and storage

For packaging, dispatching, handling and storage of components see ECSS-Q-ST-20-08.

# Solar cell assemblies

## General

### Testing

ECSS-E-ST-20-08\_0090250

Qualification testing of solar cell assemblies (SCAs) shall comprises acceptance and qualification tests.

ECSS-E-ST-20-08\_0090251

Testing of previously qualified SCAs shall comprises acceptance tests and delta qualification tests in conformance with requirement 6.4.1f.4.

### Conditions and methods of test

ECSS-E-ST-20-08\_0090252

The conditions and methods of testing shall conform to the SCA source control drawing (SCD-SCA).

1. The SCA specification consists of two parts, the generic specification (this Standard) and the SCD-SCA. For the preparation of the SCD-SCA, refer to Annex B.

ECSS-E-ST-20-08\_0090253

The SCD-SCA shall be prepared by the supplier in conformance with Annex B, and provided to the customer for reviewing and agreement.

ECSS-E-ST-20-08\_0090254

Any deviation from the required in-process, acceptance and qualification test shall be justified in the documentation package.

ECSS-E-ST-20-08\_0090255

Deviations from this Standard applicable to the SCD-SCA shall:

be agreed between the customer and the supplier;

not affect the reliability and performances of the SCAs;

only be those specified in requirement 6.1.2c.

### Deliverable components

ECSS-E-ST-20-08\_0090256

Delivered solar cell assemblies shall be produced and inspected in conformance with the requirements of the process identification document (PID) specified in clause 6.2, and

ECSS-E-ST-20-08\_0090257

Delivered solar cell assemblies shall have completed all tests and inspections included in the SCD-SCA.

### Identification and traceability

ECSS-E-ST-20-08\_0090258

All delivered solar cell assemblies shall be permanently marked with a code to enable traceability of the cells at the level stated in the PID.

1. For the PID, see clause 6.2.

## Production control (process identification document)

ECSS-E-ST-20-08\_0090259

A process identification document (PID) for the SCA to be qualified shall be prepared by the supplier in conformance with Annex F.

ECSS-E-ST-20-08\_0090260

The supplier shall do the following:

maintain configuration control of all documents;

keep the issues of the documents effective at the date of acceptance by the customer;

provide the PID to the customer for review;

submit to the customer for review and approval any modifications or changes to documents in the PID with any quality and reliability implications.

## Acceptance tests

### General

ECSS-E-ST-20-08\_0090261

Acceptance tests shall be performed on the following:

components for delivery;

components used for qualification.

ECSS-E-ST-20-08\_0090262

Acceptance tests shall consist of the following:

visual inspection (100 % of the SCAs), in conformance with clause 6.4.3.1.

dimension and weight inspection (1 % of the SCAs), in conformance with clause 6.4.3.2.

electrical performance measurement (100 % of the SCAs), in conformance with clause 6.3.3.

diode characterization (100 % of the SCAs), in conformance with clause 9.4.5.2.

ECSS-E-ST-20-08\_0090263

The data documentation corresponding to the tests referred to in requirement 6.3.1b shall be delivered together with the delivered SCAs and the qualification test lot as part of the DDP.

1. For the DDP, see clause 6.6.

### Test methods and conditions

ECSS-E-ST-20-08\_0090264

The test methods and conditions specified in clause 6.4.3 shall be applied.

### Electrical performance acceptance test (EPA)

#### Purpose

The purpose of the EPA test is to measure the electrical performance of the SCA for current class grading.

#### Process

ECSS-E-ST-20-08\_0090265

The electrical current of SCA under 1 S.C. (AM0) shall be measured at operational voltage (Iop) at a solar cell temperature of 25 °C or operating temperature.

ECSS-E-ST-20-08\_0090266

The predicted operational voltage (Vop) shall be specified in the SCD‑SCA.

ECSS-E-ST-20-08\_0090267

The accuracy of Iop and Vop shall be provided to the customer.

ECSS-E-ST-20-08\_0090268

During measurement, the SCAs shall be kept at a constant temperature.

ECSS-E-ST-20-08\_0090269

Continuous or pulsed light source calibrated in conformance with clause 10 shall be used to verify the requirements given in clause 6.3.3.3 for electrical characterization.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0090270

The pass fail criteria shall be indicated in the SCD-SCA.

## Qualification tests

### General

ECSS-E-ST-20-08\_0090271

All SCA procurement lots shall be qualified.

ECSS-E-ST-20-08\_0090272

Qualification of SCAs shall be granted by the customer.

ECSS-E-ST-20-08\_0090273

The qualification plan shall consist of the tests specified in Table 6‑1.

ECSS-E-ST-20-08\_0090274

The following requirements shall apply to the qualification plan:

Ensure that welding parameters, the material and dimensions of the interconnectors, cementing conditions, adhesive and coverglass for the following activities in Table 6‑1, are in conformance with the production process for solar panels that applies to the supplier of the SCA:

Front interconnect welding

Coverglass bonding

Rear interconnect welding

Perform UV test (step 16 in Table 6‑1) in subgroup B on a minimum of 6 SCAs.

ECSS-E-ST-20-08\_0091032

Table ‑: Qualification test plan for SCA

| Test | Symbol | Method | Bare cells (40 samples) | | Solar cell assemblies  (74 samples) | | | |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| A (20) | E (20) | B (20) | C (24) | D (10) | F(20) |
| Front Interconnect Welding | FIW |  | 4 | 4 |  |  |  |  |
| Coverglass Bonding | CB |  |  | 6 |  |  |  |  |
| Rear Interconnect Welding | RIW |  |  | 8 |  |  |  |  |
| Full Visual inspection including ELM | VI | 6.4.3.1 | 1,5,9,13 | 1,9,13,17 | 1,15,18 | 1,11 | 1,5,9,11,13 | 1,4 |
| Dimension and weight | DW | 6.4.3.2 |  |  | 2 |  |  |  |
| Electrical performance | EP | 6.4.3.3 | 2,6,10 | 2,5,7,10,14 | 4,7,9,12,16 | 3,9,14,20 | 2,6,14 | 2,5 |
| Temperature coefficients | TC | 6.4.3.4 |  |  |  | 5/16 |  |  |
| Diode Temperature Behaviour | TB | 9.6.14 |  |  |  | 6,17 |  |  |
| Spectral response | SR | 6.4.3.5 |  |  |  | 2,13 |  |  |
| Thermo-optical data | TO | 6.4.3.6 |  |  | 13,17 | 21 |  |  |
| Thermal cycling | CY | 6.4.3.7 | 8 | 12 |  |  |  |  |
| Humidity and Temperature | HT1 | 6.4.3.8 |  |  |  |  | 4 |  |
| Coating adherence | CA | 6.4.3.9 |  |  |  |  | 12 |  |
| Interconnector adherence | IA | 6.4.3.10 | 12 | 16 |  |  |  |  |
| Electron irradiation | EI | 6.4.3.11 |  |  |  | 10 | 8 |  |
| Photon irradiation and temperature annealing | PH | 6.4.3.12 |  |  | 8 | 12 | 10 |  |
| Surface conductivity | SC | 6.4.3.13 |  |  |  |  | 3,7,15 |  |
| Diode characterization | DC | 9.6.15 | 3,7,11 | 3,11,15 | 5,10, | 4,15 |  |  |
| Cell reverse bias test | RB | 6.4.3.14 |  |  | 11 | 8,19 |  |  |
| Ultraviolet exposure | UV | 6.4.3.15 |  |  | 14 |  |  |  |
| Capacitance | CT | 6.4.3.16 |  |  | 6 |  |  |  |
| Flatness | FT | 6.4.3.17 |  |  | 3 |  |  |  |
| Long Duration - Life Test | LT | 6.4.3.18 |  |  |  |  |  | 3 |
| Angular Measurement | AM | 6.4.3.19 |  |  |  | 7,18 |  |  |
| NOTE 1 The numbers in the subgroup columns indicate the sequence in which the tests are performed; e.g. for subgroup A, the 1st test is VI, the 2nd test EP, the 3rd is DC, and so on.  NOTE 2 The reason for dividing the test samples into subgroups is to generally test for the following:  - Subgroup A: Front interconnector adherence; - Subgroup E: Rear interconnector adherence; - Subgroup B: BOL performance data and ultraviolet exposure; - Subgroup C: EOL performance data; - Subgroup D: Surface conductivity and humidity on SCA (for coverglasses with conductive coating only) - Subgroup F: Long duration - Life Test  NOTE 3 The number of test samples are indicated between brackets e.g. A (20)  NOTE 4 For additional requirements, refer to requirement 6.4.1d.  NOTE 5 Guidelines for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. | | | | | | | | |

ECSS-E-ST-20-08\_0090275

The supplier shall provide details of the outcome of the qualification programme to the customer.

ECSS-E-ST-20-08\_0091119

For a procurement lot of a previously qualified SCA, the qualification tests need not be repeated if the following conditions are satisfied:

No changes are made to the design, function or electrical or mechanical parameters of the solar cell assembly.

The same source control drawing is applicable.

No changes are made to the PID.

Delta qualification tests are performed to cover the requirements imposed by the new application.

ECSS-E-ST-20-08\_0090277

For 6.4.1f.4, the new requirements shall be included in a new version of the SCD-SCA.

### Qualification

#### Production and test schedule

ECSS-E-ST-20-08\_0090278

Before starting production of the qualification lot, the manufacturer shall compile a production test schedule, showing by date and duration, production and test activities, including all major processing operations and key stages in the production and testing.

ECSS-E-ST-20-08\_0090279

A production flow chart, process schedules and inspection procedures shall be provided.

#### Qualification test samples

ECSS-E-ST-20-08\_0090280

The solar cell assemblies for qualification testing shall conform to the PID.

ECSS-E-ST-20-08\_0090281

The supplier shall provide access to the customer to monitor the manufacture of the test samples in conformance with a procedure agreed with the customer.

ECSS-E-ST-20-08\_0090282

The test samples shall be chosen statistically and at random from the first manufacturing lots of the procurement lot.

1. For sampling, see ISO 2859.

ECSS-E-ST-20-08\_0090283

Facilities shall be available to safely store the qualification lot (included failed samples) for a minimum of 6 years (equivalent to five years in storage and one year in orbit).

ECSS-E-ST-20-08\_0091120

The qualification lot shall be a production lot of at least 200 bare solar cells or the number of solar cell assemblies to be integrated on the solar array, whichever is lower.

ECSS-E-ST-20-08\_0091121

The total number of samples shall be divided into three equal groups, referred to as high-grade, mid-grade and low-grade according to their current at operating voltage and be agreed with the customer.

1. The grading can be also performed for other parameters (e.g. subcell current of the EOL limiting subcell) if agreed by the customer.

#### Qualification testing

ECSS-E-ST-20-08\_0090284

Qualification testing shall proceed as given in Table 6‑1.

ECSS-E-ST-20-08\_0090285

The total quantity of test samples shall be a minimum of 104 or 114 SCAs depending on previous testing, in conformance with requirement 6.4.3.11.2e.

1. The number of samples per subgroup can be increased, but all samples have to follow the complete test sequence. The only aim is to allow for possible losses of qualification samples e.g. mishandling while maintaining the minimum required number.

ECSS-E-ST-20-08\_0090286

The qualification tests shall be divided into subgroups of tests, and the samples assigned to a subgroup be subjected to the tests in that subgroup in the sequence specified.

ECSS-E-ST-20-08\_0090287

A failure in any subgroup shall constitute a failure in the qualification.

1. For a definition of failure see clause 6.5.

### Test methods, conditions and measurements

#### Full visual inspection including ELM (VI)

##### Applicability

The requirements on visually observable defects specified in this clause apply to granting qualification approval to high quality solar cell assemblies.

##### Test process

ECSS-E-ST-20-08\_0090288

The SCAs shall be inspected with an equipment with a resolution which is 5 times higher than the minimum allowed defect size and furthermore the solar cell be inspected by means of ELM, PLM or equivalent qualified methods to verify requirements on the following:

defects on cell;

coverglass;

adhesive;

contacts;

interconnector.

##### Deviations

ECSS-E-ST-20-08\_0090289

Any deviation from the visual inspection requirements on defects shall:

not affect performance or reliability,

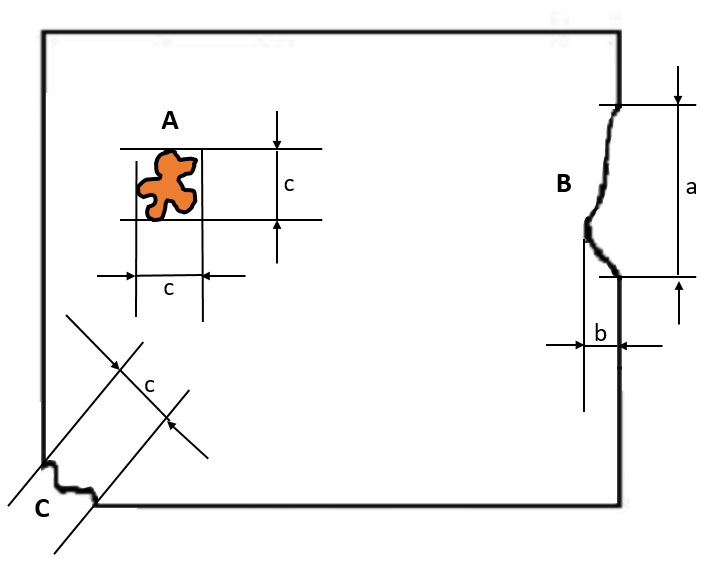
be agreed with the customer, and

be justified.

##### Solar cell defects

ECSS-E-ST-20-08\_0090290

The location and maximum dimensions of edge chips, corner chips and surface nicks shall be in conformance with Figure 6‑1 and Table 6‑2.



A = surface nick

B = edge chip

C = corner chip

61

62

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ECSS-E-ST-20-08\_0090291

The cumulative area of all defects of the types specified in requirement 6.4.3.1.4a shall not exceed 5 % of the total solar cell area.

ECSS-E-ST-20-08\_0090292

Defects of the types specified in requirement 6.4.3.1.4a occurring in the contact weld area shall be prevented.

ECSS-E-ST-20-08\_0090293

Cracks or fingerprints shall not be present on solar cells.

ECSS-E-ST-20-08\_0090294

The total area of anti-reflection coating voids shall not exceed 3 % of the total active area of the cell.

##### Coverglass defects

ECSS-E-ST-20-08\_0090295

The coverglasses shall be inspected to ensure 100 % coverage of the bare surface of the cells.

ECSS-E-ST-20-08\_0091077

Chips and nicks may be present on coverglasses if the bare surface of the solar cell is 100 % covered.

ECSS-E-ST-20-08\_0090297

Covers with dirty and contaminated surfaces shall be rejected.

ECSS-E-ST-20-08\_0090298

The total area of ARC and conductive coating voids, including evaporation jig marks, shall not exceed 3 % of the area of the coverglass.

ECSS-E-ST-20-08\_0090299

The coverglass shall not contain bubbles having a projected area larger than 0,02 mm2.

ECSS-E-ST-20-08\_0090300

Coverglasses shall be rejected if they contain cracks with any one of the following characteristics:

there is a visible separation between cracks;

there are more than three per cover;

meeting cracks are separated by more than 2 mm at the non-meeting end.

##### Coverglass adhesive defects

ECSS-E-ST-20-08\_0090301

There shall be no delamination or discolouration in the adhesive, except in the area opposite rear welds, where discolouration is allowed.

ECSS-E-ST-20-08\_0090302

Adhesive voids along the cover edge shall not exceed 0,6 mm in depth.

ECSS-E-ST-20-08\_0090303

The maximum total projected area of additional bubbles shall not exceed 0,2 % of the cell area, discounting the following:

bubbles less than 0,02 mm2 in the projected area, and

bubbles, discolourations and voids located less than 2 mm from the interconnector edges.

##### Front contact defects

ECSS-E-ST-20-08\_0090304

Interruptions and delaminations in the front contact shall be prevented.

ECSS-E-ST-20-08\_0090305

Over-coating (coating exceeding the area of the contact) along one side of each welding pad shall not exceed 0,1 mm.

ECSS-E-ST-20-08\_0090306

The maximum total length of missing grids, short grids or non-continuous grids shall not exceed the total length of 3 grids.

##### Rear contact defects

ECSS-E-ST-20-08\_0090307

For the rear side contact, outside the welding area, the following conditions shall be met:

Drops and spatter do not exceed 0,1 mm in diameter and 0,05 mm in height.

The maximum deep of edge delaminations do not exceed 0,75 mm.

Other defects do not exceed a total of 2 % of the cell contact area.

The area of worm shaped bulges is 3 % of the total cell contact area, or less.

The maximum length of the hypotenuse of the triangular area of visible semiconductor at the corners of the solar cell (c) is in conformance with Table 6‑2.

ECSS-E-ST-20-08\_0090308

In the interconnector weld area, clause 7.5.1.5.2 shall apply.

##### Interconnector defects

ECSS-E-ST-20-08\_0090309

Breaking, tearing or deformation of the interconnector shall be prevented.

#### Dimensions and weight (DW)

ECSS-E-ST-20-08\_0090310

The overall lateral dimensions of the SCA and the interconnector position shall be inspected for compliance with the dimensions and tolerances stated in the SCD-SCA.

ECSS-E-ST-20-08\_0090311

The lateral dimensions of the coverglasses shall be such as to ensure 100 % coverage of the bare surface of the cells.

ECSS-E-ST-20-08\_0090312

The weight of the SCA shall be verified by determining the average weight per qualification lot to ensure that this conforms to the value stated in the SCD-SCA.

#### Electrical performance (EP)

##### Purpose

The purpose of the EP test is to assess the corresponding electrical parameters of the SCA and to provide data for the design of the solar generator.

##### Process

ECSS-E-ST-20-08\_0090313

The electrical current of SCA under 1 S.C. (AM0) shall be measured and recorded digitally at least at 50 points, at a solar cell temperature of 25  °C +/- 0,5 °C or operating temperature.

ECSS-E-ST-20-08\_0090314

The electrical parameters measured or processed from requirement 6.4.3.3.2a and identified in Figure 6‑2 shall be

derived from the full curve, and

delivered to the customer together with:

their average and standard deviation, and

digital data of the full curve.

  
NOTE: Iop and Vop are equal to the Itest and Vtest of the SCD SCA

ECSS-E-ST-20-08\_0091035

Figure ‑: Test points for electrical performance measurement

ECSS-E-ST-20-08\_0090315

The accuracy of the SCA measured parameters (Isc, Itest, Vtest Voc and Pmax) shall be provided to the customer.

ECSS-E-ST-20-08\_0090316

During measurement, the SCAs shall be kept at a constant temperature +/- 0,5 °C.

ECSS-E-ST-20-08\_0090317

A continuous or pulsed light source calibrated in conformance with clause 10 shall be used to verify the requirements given in for electrical characterization during both qualification and acceptance testing.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090318

The minimum current requirement for solar cell assemblies before and after electron radiation testing shall be stated in the SCD-SCA.

ECSS-E-ST-20-08\_0090319

The maximum deviation in current measured at Vtest before and after CY for subgroups A and E (in conformance with Table 6‑1) shall be 2 % for each individual cell.

ECSS-E-ST-20-08\_0090320

After qualification tests, the maximum degradation of electrical performance shall be in conformance with requirements 6.4.3.3.3a and 6.4.3.3.3b.

#### Temperature coefficients (TC)

ECSS-E-ST-20-08\_0091123

Temperature coefficient measurement at SCA level need not be performed if already performed during qualification at bare cell level.

ECSS-E-ST-20-08\_0090322

Temperature coefficients of all 1 MeV electron samples in subgroup C shall be measured.

ECSS-E-ST-20-08\_0090323

The test described in clause 6.4.3.3 shall be repeated at three equidistant solar cell temperatures covering the range of operational temperatures and three temperatures close to extremes t1 and three temperatures close to extreme t2, specified as follows, and stated in the SCD-SCA:

t 1 = highest operating temperature (without margins) predicted for the application.

t 2 = lowest operating temperature (without margins) predicted for the application.

1. The three temperatures close to the extremes to be chosen at equidistance of 10 K to 20 K depending on the limitations of the test facility with at least one measurement at the extreme temperature.

ECSS-E-ST-20-08\_0090324

Data for all electrical performance parameters at the different solar cell temperatures shall be provided.

ECSS-E-ST-20-08\_0090325

The temperature coefficients of short-circuit current, open circuit voltage, voltage at maximum power and current at maximum power shall be derived by least-square curve fitting.

ECSS-E-ST-20-08\_0090326

The coefficient of determination for the electrical parameters obtained from the curve fit, specified in 6.4.3.4e shall be included.

ECSS-E-ST-20-08\_0091124

The number of test items for the low temperature part of TC shall be agreed with the customer depending on the facility dimension.

#### Spectral response (SR)

##### Purpose

Spectral response data is used for the verification of the Sun simulator (see clauses 10.1.1 and 10.1.2) for performance measurement error calculation, and for the characterization of the spectral response spread of production SCAs.

##### Process

ECSS-E-ST-20-08\_0090327

Spectral response shall be measured in subgroup C on half of the samples before irradiation, by comparing the short-circuit current of the test SCAs against the output of a spectral standard of known relative spectral response under monochromatic irradiation.

ECSS-E-ST-20-08\_0090328

Subgroup C samples where spectral response has been measured shall be later irradiated to the highest dose and subsequently submitted to spectral response test

ECSS-E-ST-20-08\_0090329

The monochromatic irradiation shall be generated by one of the following methods:

With the aid of narrow-band interference filters, having the following characteristics:

for silicon solar cells, at least, at 14 discrete wavelength intervals between 0,3 μm and 1,1 m;

for single-junction GaAs solar cells at least, at 14 discrete wavelength intervals between 0,3 m and 1,1 m and at least 3 narrow band interference filters in the range 0,75 m to 1,1 m.

for multi-junction GaAs solar cells, the number of narrow band interference filters and their wavelength are stated in the SCD-SCA.

By means of a high-intensity monochromator for continuous recording between 0,3 m and at least 1,8 m.

ECSS-E-ST-20-08\_0090330

The irradiation intensity at all wavelengths shall be such as to ensure that the measurement is made in the region where the cell response short-circuit current versus irradiance is linear.

ECSS-E-ST-20-08\_0090331

For multi-junction solar cells, it shall be ensured that the measurements are performed on the current limiting subcell, and that it is working close to short-circuit conditions.

#### Thermo-optical data (TO)

##### Overview

Thermo-optical data is used for computation of the solar panel operational temperature.

##### Process

ECSS-E-ST-20-08\_0090332

For Subgroup B, in conformance with Table 6‑1, the solar absorptance and the hemispherical emittance shall be measured in accordance with ECSS-Q-ST-70-09 Annex C.2 and C.4/C.5 respectively on all samples to be subjected to UV exposure.

ECSS-E-ST-20-08\_0091078

For subgroups B and C the thermo-optical data after UV exposure and electron irradiation shall be measured in accordance with one of the following two options:

the solar absorptance and the hemispherical emittance in accordance with ECSS-Q-ST-70-09 Annex C.2 and C.4/C.5 respectively, be measured on all samples of Subgroup B after UV exposure and as a minimum on 5 samples per electron radiation group.

the absorptance, measured following the comparative test method, and the normal emittance in accordance with ECSS-Q-ST-70-09 Annex C.3 and C.6 respectively be measured on all Subgroup B and C samples, provided that in addition to 6.4.3.6.2a, the absorptance, measured following the comparative test method, and the normal emittance are measured in subgroup B samples before being subjected to UV exposure.

ECSS-E-ST-20-08\_0091079

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##### Pass-fail criteria

ECSS-E-ST-20-08\_0090335

Pass-fail criteria for the SCAs thermo-optical properties shall be as stated in the SCD-SCA.

#### Thermal cycling (CY)

##### Purpose

The purpose of this test is to assess the reliability of test samples under a thermal stress equivalent to the number of eclipses that occur during one year in orbit for LEO missions, 1 000 thermal cycles for GEO missions or the complete lifetime cycling for interplanetary or other mission types.

##### Process

ECSS-E-ST-20-08\_0090336

The number of cycles and the extreme temperatures shall be as stated in the SCD-SCA.

ECSS-E-ST-20-08\_0091125

Additional cycles, to the ones specified in 6.4.3.7.2a, shall be added to cover mission phases with low occurrence but very extreme temperatures and agreed with the customer.

#### Humidity and temperature (HT1)

##### Purpose

This test is an accelerated shelf-life test to monitor the coverglass conductive coating in a humid atmosphere.

##### Process

ECSS-E-ST-20-08\_0090337

All SCAs in subgroup D shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090338

The chamber temperature shall then be increased to 60 C minimum.

ECSS-E-ST-20-08\_0090339

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090340

The duration of the test shall be 30 days.

ECSS-E-ST-20-08\_0090341

In the case of solar cells with aluminium content window layers, the HT test shall be extended to simulate on-ground expected duration and humidity and temperature conditions.

ECSS-E-ST-20-08\_0090342

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090343

Water condensation on the surface of the SCAs shall be prevented.

ECSS-E-ST-20-08\_0090344

If there are requirements on specific environmental conditions, they shall be stated in the SCD-SCA.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

#### Coating adherence (CA)

##### Purpose

This test is performed to verify the durability of the coverglass conductive coating.

##### Process

ECSS-E-ST-20-08\_0090345

All SCAs of subgroup D shall be subjected to a coating adherence test on the full coverglass SCA face.

ECSS-E-ST-20-08\_0090346

Test conditions shall be established according to a standard which is mutually agreed with the customer.

1. Example of standards that can be used for the test conditions of the coating adherence test are MIL-M-13508; ISO 9211-4 and ECSS-Q-ST-70-13.

ECSS-E-ST-20-08\_0090347

The adhesive tape used for this test shall be clear in colour with an adhesive strength on steel of at least 0,28 N/mm width.

1. Example of standard that can be used to measure to the adhesive strength is EN 1939.

ECSS-E-ST-20-08\_0090348

Any visible delamination of parts of the coverglass coating shall not exceed the limits specified in requirement 6.4.3.1.4e.

#### Interconnector adherence (IA)

##### Purpose

The purpose of this test is to monitor the bond strength of interconnectors under mechanical and thermal stress and to verify the electrical stability after interconnector welding.

##### Process

ECSS-E-ST-20-08\_0090349

A gradually increasing pull force shall be applied to the interconnector separately for each interconnector tab at a pull speed stated in the SCD-SCA.

ECSS-E-ST-20-08\_0090350

The ultimate pull strength of each tab shall be as stated in the SCD-SCA, considering the number of pulled tabs and their widths.

ECSS-E-ST-20-08\_0090351

The pull direction shall:

be either 0°, 45° or 90°;

be as stated in the SCD-SCA.

ECSS-E-ST-20-08\_0091126

The type of interconnector adherence failure shall be recorded in the data documentation package (DDP) as specified in clause 6.6.

#### Electron irradiation (EI)

##### Purpose

EI test is an accelerated life test to check the solar cell performance degradation under electron particle irradiation.

##### Process

ECSS-E-ST-20-08\_0090352

The SCAs shall be subjected to 1 MeV electron irradiation.

1. ISO 23038 outlines a methodology to perform this test.

ECSS-E-ST-20-08\_0090353

The flux density and energy shall be uniform over the cell area to within ±10 %.

ECSS-E-ST-20-08\_0090354

During irradiation, the cells shall be protected from oxidation using either a vacuum (below 10-3 Pa) or a dry atmosphere of nitrogen or argon at a temperature of (20 ± 10) C.

ECSS-E-ST-20-08\_0090355

The nominal rate shall be lower than or equal to 5 × 1011e- cm-2 s-1.

1. It is good practice, especially for high fluences, to decrease the rate to avoid unwanted effects in the cover glass adhesive.

ECSS-E-ST-20-08\_0090356

Selection of solar cell assemblies for electron irradiation shall be performed as follows:

three fluences as stated in the SCD-SCA are applied;

for each fluence, and in conformance with 6.4.2.2f, a minimum of the following SCA’s numbers are tested:

2 high-grade cells;

4 mid-grade cells;

2 low grade cells.

ECSS-E-ST-20-08\_0090357

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ECSS-E-ST-20-08\_0090358

After combined electron and photon irradiation and temperature annealing, the SCAs shall conform to the requirements stated in the SCD-SCA.

ECSS-E-ST-20-08\_0090359

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#### Photon irradiation and temperature annealing (PH)

##### Purpose

This test is to verify the stability of SCA performance under the equivalent light and temperature of 1 S.C. (AM0).

1. It is good practice to perform “electrical performance” at the samples directly after proton/electron irradiation but before “Photon irradiation and temperature annealing” to check the effect of annealing.

##### Process

ECSS-E-ST-20-08\_0090360

During the test, SCAs in subgroups B and C shall be subjected to the following:

irradiated with 1 S.C. (AM0) for 48 h;

be kept at (25 ± 5) C;

arranged in an open circuit condition.

ECSS-E-ST-20-08\_0090361

Multi-junction solar cells shall be subsequently temperature annealed for 24 h at 60 C in darkness.

ECSS-E-ST-20-08\_0090362

After the tests the SCAs shall be kept at temperatures below 50 C until they are electrically measured.

#### Surface conductivity (SC)

##### Purpose

This test is to verify the average conductivity of conductive coverglasses across the total surface.

##### Process

ECSS-E-ST-20-08\_0090363

The surface conductivity of coverglasses for SCAs of subgroup D shall be measured.

ECSS-E-ST-20-08\_0090364

The measurement specified in requirement 6.4.3.13.2a shall be performed between the cover contact dots or by the method described in the SCD-SCA.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090365

The average conductivity across the total surface shall conform to the requirements stated in the SCD-SCA.

#### Solar Cell Reverse Bias Test (RB)

##### Purpose

The purpose of solar cell reverse bias test is to check for performance degradation of the SCA due to reverse bias.

##### Process

ECSS-E-ST-20-08\_0090366

For SCAs without a protection diode or with a protection diode electrically isolated from the cell, the reverse I/V characteristics of the SCA under illumination of 1 S.C. (AM0) with a limiting power supply (to avoid destructive breakdown) shall be measured.

ECSS-E-ST-20-08\_0090367

For SCAs with a protection diode electrically connected to the cell, solar cell reverse bias test shall not be performed.

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090368

The parameters of reverse I/V characteristics measurement shall be as stated in the SCD-SCA concerning temperature, hold time, current limitation, maximum reverse bias (voltage).

#### Ultraviolet exposure test (UV)

##### Purpose

The ultraviolet exposure test is an accelerated life test with the purpose of checking the stability of the solar cells assembly under ultraviolet light exposure.

This test is only applicable for established material combinations, qualified before, of which the long duration degradation effect is known.

Specific UV tests for scientific and planetary missions and for new material combinations are specified in clause 6.4.3.15.4. The UV test conditions for these test are normally elaborated together with the customer.

##### Process

ECSS-E-ST-20-08\_0090369

The integrated intensity of the photons between 200 nm to 400 nm shall be measured at the location of the test item.

ECSS-E-ST-20-08\_0090370

For photons with a wavelength between 200 nm to 400 nm, the integrated intensity shall be used to determine total Sun-hours of UV exposure taking into account that:

the UV test consists of four intervals of 250 Sun-hours, for GEO and LEO missions, while for other missions, the duration of the UV test is agreed with the customer;

the UV intensity is increased to accelerate the test to a maximum of 5 Suns and not leading to temperature increase of more than 10 K above the corresponding operational temperature.

1. UV light sources generally emit significant levels of visible and infrared radiation which causes heating of the SCA. It is good practice to consider this when defining the thermal control strategy for the SCAs during the exposure. The maximum UV acceleration factor which can be applied is sometimes limited in order to keep the SCAs within the specified temperature limits for the test.

ECSS-E-ST-20-08\_0090371

Spectral Irradiance for UV light sources shall be performed in conformance with ECSS-Q-ST-70-06.

ECSS-E-ST-20-08\_0090372

The test shall be performed in a vacuum (i.e. pressure less than 10-3 Pa).

ECSS-E-ST-20-08\_0090373

The temperature of the SCAs shall be the nominal operational temperature ±10 K, in conformance with SCD-SCA.

ECSS-E-ST-20-08\_0090374

The short circuit current resulting from the applied UV light source of at least one of the SCA’s shall be continuously monitored and recorded.

1. It is good practice to measure the open circuit voltage of samples to observe sudden temperature changes especially in the transient periods of the intervals stated in 6.4.3.15.2b.1 where the stabilization of the testing is not achieved yet.

ECSS-E-ST-20-08\_0090375

The SCA IV curve shall be measured in situ by means of a stable light source, to be agreed between the test house and the customer, before the start and at each test time interval and the ELM inspection be done in situ in combination with the IV measurement.

ECSS-E-ST-20-08\_0090376

For the UV exposure test the following cleanliness requirement shall apply:

The test equipment fulfils the cleanliness requirements as specified in ECSS-Q-ST-70-01, regarding pre-test contamination level and blank test of 24 hours before start of the exposure of the samples.

Control samples are included in the UV chamber in order to identify potential contaminations occurring during the test.

Contamination of the window during the test is taken into account in the calculation of the equivalent sun hours.

Cross-contamination of the test samples due to UV exposure is taken into account as degradation.

1. Cross-contamination means contamination occurring from flight representative materials in the samples.

ECSS-E-ST-20-08\_0091127

The number of test items shall be agreed with the customer depending on the facility dimension.

##### Pass-Fail Criteria

ECSS-E-ST-20-08\_0090377

To confirm that the solar cell assembly was stable throughout the UV test, specified in 6.4.3.15.2g, the maximum degradation in short-circuit current measured after UV test, in conformance with Table 6‑1, shall be less than 2 % for each individual cell.

ECSS-E-ST-20-08\_0090378

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ECSS-E-ST-20-08\_0090379

The short circuit current derived from SCA IV curves measurements in 6.4.3.15.2g at the intervals specified in requirement 6.4.3.15.2b.1 shall demonstrate an exponential decay.

##### Specific UV tests

ECSS-E-ST-20-08\_0091128

Specific UV tests shall be performed to verify the SCAs performance for scientific and planetary missions, where the solar arrays are exposed to high UV intensity levels and operated at high inclination angles.

ECSS-E-ST-20-08\_0091129

The UV test conditions for the tests specified in 6.4.3.15.4a shall be agreed with the customer.

ECSS-E-ST-20-08\_0091130

For new material combinations an engineering program, comprising a long duration exposure, shall be executed before qualification.

1. If successfully performed, a new qualification UV exposure test including updated process and pass/fail criteria can be derived from this engineering campaign.

ECSS-E-ST-20-08\_0091131

The engineering program and the new qualification UV exposure test, as a result of 6.4.3.15.4c, shall be agreed with the customer.

#### Capacitance test (CT)

##### Purpose

The purpose of this test is to gather data for the panel level by extrapolating the data obtained on the capacitance of the SCA.

##### Process

ECSS-E-ST-20-08\_0090380

One of the following methods shall be followed for capacitance measurement:

Frequency domain single junction solar cell capacitance measurement as described in clause 11.1.

1. No method available for multi-junction measurement at the time being.

Time domain capacitance measurement as described in clause 11.2.

ECSS-E-ST-20-08\_0090381

The method for measuring the capacitance shall be stated in the SCD‑SCA.

ECSS-E-ST-20-08\_0090382

The capacitance shall be measured at SCA level in conformance with the method referred in requirement 6.4.3.16.2b at the temperature range stated in the SCD-SCA.

#### Flatness test (FT)

##### Purpose

The purpose of this test is to determine the flatness of the SCA.

##### Process

ECSS-E-ST-20-08\_0090383

The flatness shall be determined by measuring the maximum deflection of the SCA measured on an optically flat surface.

##### Pass/fail criteria

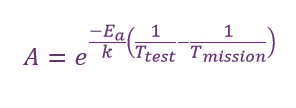
ECSS-E-ST-20-08\_0090384

The deflection of the SCA shall be lower than the deflection value, d in Figure 8‑6, stated on the SCD-SCA.

#### Long Duration - Life test (LT)

##### Purpose

The purpose of this test is to determine the stability of the solar cell assembly under worst case operation conditions for long duration. This test is an accelerated test covering the duration of the complete mission. The test duration depends on the temperature profile of the mission, the test temperature and the activation energy for the failure mechanism in the solar cell assembly. The acceleration factor *A* is calculated applying Arrhenius’ law:



with

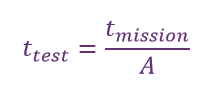
E*a* activation energy (in eV)

k Boltzmann constant (8.617·10-5 eV/K)

T*test* test temperature

T*mission* mission temperature

The test duration t*test* is reduced using A as follows:



with the total mission duration t*mission* where the solar array is illuminated.

##### Process

ECSS-E-ST-20-08\_0090385

One of the following four methods shall be proposed and described by the supplier as long duration - life test:

For standard GEO missions with solar arrays based on deployable panels and maximum duration of 15 years, perform a 1000 hours test at 140 °C.

For standard LEO missions with solar arrays based on deployable panels and maximum duration of 10 years, perform a 3000 hours test at 150 °C.

For any GEO and LEO, Science, Planetary and Exploration mission, demonstrate by assuming an activation energy of 0,7 eV that the stability is not affected within the duration of the mission.

Determine the activation energy by measuring the time to failure at several temperatures.

1. 1 to item 3: An activation energy different from 0,7eV can be proposed, however it has to be fully justified (see 6.4.3.18.2a.4) and accepted by the customer.
2. 2 to item 4: From this activity, it is going to be evident whether the SCA will remain stable for the mission in question.

ECSS-E-ST-20-08\_0090386

The Long Duration – Life test environment shall at least comprise vacuum conditions, illumination and cell operation at a working point.

ECSS-E-ST-20-08\_0091132

The SCA shall be biased for 80 % of the time in forward and 20 % in reverse mode.

ECSS-E-ST-20-08\_0091133

The number of test items shall be agreed with the customer depending on the facility dimension.

##### Pass/fail criteria

ECSS-E-ST-20-08\_0091134

The performance of solar cells shall not degrade more than 2 % in maximum power throughout the Long Duration - Life Test.

#### Angular Measurement (AM)

##### Purpose

The purpose of this test is to characterize and/or confirm the angular performance behaviour (e.g. modified cosine law) of the SCA for missions with nominal operation at high inclination angles >60°.

##### Process

ECSS-E-ST-20-08\_0091135

The performance of the SCA shall be measured for the specified spectrum at

0°, 30°, 45°, 60°

incremental and step angle increase starting from 60° up to the angle specified in the SCD-SCA or SCD-PVA.

1. 1 For validating the adequacy of the setup, the performance is normally measured at 90°, for which the SCA should not generate any power.
2. 2 The incremental and step angle increase can be in 5° or 10° steps.

ECSS-E-ST-20-08\_0091136

The angular measurement at the angles stated in 6.4.3.19.2a shall be carried out at the temperatures as stated in the SCD-SCA.

ECSS-E-ST-20-08\_0091137

The light intensity variation on the SCA shall be less than 2 % for all angles.

## Failure definition

### Failure criteria

ECSS-E-ST-20-08\_0090387

The following shall constitute SCA failures:

SCAs which fail during subgroup tests for which the pass-fail criteria are inherent in the test method.

SCAs failing to conform to the requirements of the visual inspection specified in clause 6.4.3.1.

Components whose marking fails to conform to the requirements of clause 6.1.4.

SCAs that, when subjected to electrical performance measurements after qualification tests in conformance with the SCD-SCA, fail one or more of the specified limits, measurement accuracy included.

### Failed SCAs

ECSS-E-ST-20-08\_0090388

An SCA shall be considered as failed if it exhibits one or more of the failure modes detailed in clause 6.5.1.

ECSS-E-ST-20-08\_0090389

Failed SCAs shall be identified as such and be included in the delivery.

ECSS-E-ST-20-08\_0090390

Failure analysis of these SCAs shall be performed by the supplier and the results provided to the customer, as part of an NRB documentation.

1. For NRB, see ECSS-Q-ST-10-09.

## Data documentation

ECSS-E-ST-20-08\_0090391

The supplier shall provide a data documentation package in conformance with Annex G for the qualification approval records and for each SCA delivery lot.

## Delivery

ECSS-E-ST-20-08\_0090392

All deliverable hardware specified in the order shall be delivered together with documentation in conformance with the requirements specified in clause 6.6.

ECSS-E-ST-20-08\_0090393

One set of documents shall be sent to the customer.

## Packing, dispatching, handling and storage

### Overview

For packaging, dispatching, handling and storage of components see ECSS-Q-ST-20-08.

### ESD Sensitivity

ECSS-E-ST-20-08\_0090394

If a SCA is sensitive to ESD according to clause 5.2 of ESCC 23800 Issue 1 then it shall be handled and stored according to ESCC 24900 Issue 2 clause 10.

# Bare solar cells

## Testing, deliverable components and marking

### Testing

#### Tests for qualification and procurement

ECSS-E-ST-20-08\_0090395

Testing for the qualification of bare solar cells (BSCs) shall comprise acceptance and qualification testing.

ECSS-E-ST-20-08\_0090396

Testing for the procurement of qualified solar cells shall comprise acceptance tests and delta qualification tests in conformance with clause 7.4.1e.4.

#### Conditions and methods of tests

ECSS-E-ST-20-08\_0090397

The conditions and methods of testing shall conform to the bare solar cell source control drawing (SCD-BSC).

1. The bare solar cell specification consists of two parts, the generic specification (this Standard) and the SCD-BSC. The SCD-BSC contains the technical specification for a cell type relevant to acceptance testing, as well as for the qualification testing. For the preparation of the SCD-BSC for bare solar cells, refer to Annex C.

ECSS-E-ST-20-08\_0090398

The SCD-BSC shall be prepared by the supplier in conformance with Annex C and provided to the customer for reviewing and agreement.

ECSS-E-ST-20-08\_0090399

Any deviation from in-process, acceptance and qualification test procedures shall be justified in the SCD-BSC.

ECSS-E-ST-20-08\_0090400

Deviations from this Standard applicable to the SCD-BSC shall:

be agreed between the customer and the supplier;

include alternative requirements equivalent to those of this Standard;

not affect the reliability and performances of the BSCs;

only be those specified in requirement 7.1.1.2c.

#### Responsibility of supplier for the performance of tests and inspections

ECSS-E-ST-20-08\_0090401

The supplier shall ensure that the tests and inspections are performed.

ECSS-E-ST-20-08\_0090402

The tests and inspections specified in requirement 7.1.1.3a shall be performed at the manufacturer’s plant or at a facility approved by the customer.

1. For test house requirements, see ECSS-Q-ST-20-07.

#### Preliminary characterization

ECSS-E-ST-20-08\_0090403

Before starting a qualification, the manufacturer shall verify the BOL and EOL solar cell characteristics on a representative production lot.

ECSS-E-ST-20-08\_0090404

The approach followed for the RDC determination shall be defined and the availability of a consistent data set demonstrated.

ECSS-E-ST-20-08\_0090405

The manufacturer shall propose a sampling method and procedure for customer approval.

1. No pass fails are foreseen during the execution of the sampling

### Deliverable components

ECSS-E-ST-20-08\_0090406

Delivered solar cells shall be processed and inspected in conformance with the requirements of the process identification document (PID) specified in requirement 7.2:

ECSS-E-ST-20-08\_0090407

Delivered solar cells shall have completed all tests and inspections specified herein in conformance with the SCD-BSC.

### Marking

ECSS-E-ST-20-08\_0090408

All delivered solar cells shall be permanently marked with a code to enable traceability of the cells at the level specified in the PID

## Production control (process identification document)

ECSS-E-ST-20-08\_0090409

The process identification document (PID) for the bare solar cell (BSC) to be qualified shall be prepared by the supplier in conformance with Annex F.

ECSS-E-ST-20-08\_0090410

The supplier shall do the following:

maintain configuration control of all documents;

keep the issues of the documents effective at the date of acceptance by the customer;

provide the PID to the customer for review;

submit to the customer for review and approval any modifications or changes to documents in the PID with any quality and reliability implications.

## Acceptance tests

### General

ECSS-E-ST-20-08\_0090411

Acceptance tests shall be performed on the following:

components for delivery;

components used for qualification.

ECSS-E-ST-20-08\_0090412

Acceptance tests shall consist on the tests specified in Table 7‑1.

ECSS-E-ST-20-08\_0090413

The generic specification to be used for each of the tests specified in Table 7‑1 shall be agreed with the customer.

ECSS-E-ST-20-08\_0090414

The sample size shall be in conformance with Table 7‑1, or according to the specific project requirements as stated in SCD-BSC.

ECSS-E-ST-20-08\_0090415

The data documentation corresponding to the tests referred to in requirement 7.3.1b shall be delivered together with the delivered cells and the qualification test lot.

ECSS-E-ST-20-08\_0090416

For cells with integral diode the acceptance tests described in Table 9‑1 shall be performed.

ECSS-E-ST-20-08\_0091036

Table ‑: Acceptance test matrix

|  |  |  |  |
| --- | --- | --- | --- |
| Test | Symbol | Verification method | Sample Size |
| Visual inspection | VI | 7.5.1 | 100 % |
| Dimension and weight | DW | 7.5.2 | 1 % |
| Flatness | FT | 7.5.19 | 2 cells |
| Surface Finish | SF | 7.5.11 | 2 cells |
| Contact thickness | CT | 7.5.10 | 1 % |
| Solar Cell Reverse Bias test | RB | 7.5.16 | 100 % |
| Electrical performance | EPA | 7.3.2.2 | 100 % |
| Hemispherical reflectance (a) | HR | 7.5.6.2 | 1 % |
| Humidity and temperature | HT | 7.5.7.2 | 1 % |
| Coating adherence | CA | 7.5.8 | 1 % |
| Humidity and temperature, and pull | HT/PT | 7.5.7.2 and 7.5.12 | 1 % |
| Coverglass gain - loss |  | 7.5.6.3 | 1 % |
| (a) only for BSR solar cells. | | | |

### Test methods and conditions

#### Test other than electrical performance

ECSS-E-ST-20-08\_0090417

Except for electrical performance, the test methods and conditions for acceptance shall conform to clause 7.5.

#### Electrical performance

##### Purpose

The purpose of the EPA test is to measure the electrical parameters of the BSC.

##### Process

ECSS-E-ST-20-08\_0090418

The electrical current of BSC under 1 S.C. (AM0) shall be measured at short circuit (Isc) and at specified test voltage, (Itest) at a solar cell temperature of 25 °C +/- 0,5 °C or operating temperature.

ECSS-E-ST-20-08\_0090419

The specified test voltage (Vtest) shall be specified in the SCD-BSC.

ECSS-E-ST-20-08\_0090420

The open circuit voltage of the BSC under 1 S.C. shall be measured at a solar cell temperature of 25 °C +/- 0,5 °C or operating temperature.

ECSS-E-ST-20-08\_0090421

The accuracy of the BSC measured parameters (Isc, Voc, Itest and Vtest) shall be provided to the customer.

ECSS-E-ST-20-08\_0090422

During measurement, the BSCs shall be kept at a constant temperature +/- 0,5 °C.

ECSS-E-ST-20-08\_0090423

Continuous or pulsed light source calibrated in conformance with clause 10 shall be used to verify the requirements given in 7.3.2.2.3 for electrical characterization.

##### Pass-Fail Criteria

ECSS-E-ST-20-08\_0090424

The pass fail criteria shall be indicated in the SCD-BSC.

##### Electrical grading in acceptance tests

ECSS-E-ST-20-08\_0090425

The BSCs tested in conformance with clause 7.3.2.2.2 and accepted shall be graded for Itest. performance

ECSS-E-ST-20-08\_0090426

The grading intervals (in mA) shall be stated in the SCD-BSC.

### Documentation

ECSS-E-ST-20-08\_0090427

Documentation on acceptance tests shall conform to clause 7.7.

## Qualification tests

### General

ECSS-E-ST-20-08\_0090428

Qualification of BSCs shall be granted by the customer.

ECSS-E-ST-20-08\_0090429

The qualification plan shall consist of the tests specified in Table 7‑2.

ECSS-E-ST-20-08\_0090430

During the qualification, all cells in subgroup A shall be equipped with front and rear interconnectors, in conformance with clause 7.5.10.2, and after step 6 in conformance with Table 7‑2.

1. The presence of coverglasses inhibits the pull test on the front side interconnects, then Subgroup A can be split into two equal cell groups, one group with front interconnectors and the other with rear interconnectors.

ECSS-E-ST-20-08\_0090431

The supplier shall provide details of the outcome of the qualification programme to the customer.

ECSS-E-ST-20-08\_0091037

Table ‑: Qualification test plan for bare solar cells

| Test | Symbol | Method | Bare cells (180) | | | | |
| --- | --- | --- | --- | --- | --- | --- | --- |
| A (20) | B (20) | C (60)\*  \* see 7.5.13.2i | O (20) | P (60)\*  \* see 7.5.14.2e.1 |
| Interconnect Welding | IW |  | 6 |  |  |  |  |
| Visual inspection incl. ELM | VI | 7.5.1 | 1,7,9 | 1,12 | 1,9,19 | 1,5,9,13 | 1,8,17 |
| Dimensions and weight | DW | 7.5.2 |  | 2 |  |  |  |
| Electrical performance | EP | 7.5.3 | 2 | 5,8,11 | 3,12,18 | 2,6,10 | 3,11,16 |
| Temperature coefficient | TC | 7.5.4 |  |  | 6,15 |  | 5,13 |
| Diode Temperature Behaviour | TB | 9.6.14 |  |  | 7,16 |  | 6,14 |
| Spectral response | SR | 7.5.5 |  |  | 2,11 |  | 2,10 |
| Optical properties | OP | 7.5.6 |  |  | 5,14 |  |  |
| Humidity and temperature 1 | HT1 | 7.5.7.1 |  |  |  | 4 |  |
| Humidity and temperature 2 | HT2 | 7.5.7.2 | 8 |  |  |  |  |
| Coating adherence | CA | 7.5.8 |  |  |  | 12 |  |
| Contact uniformity | CU | 7.5.9 | 4 |  |  |  |  |
| Surface Finish | SF | 7.5.11 | 5 |  |  |  |  |
| Pull | PT | 7.5.12 | 10 |  |  |  |  |
| Electron Irradiation | EI | 7.5.13 |  |  | 8 |  |  |
| Proton irradiation | PI | 7.5.14 |  |  |  |  | 7 |
| Photon irradiation | PH | 7.5.15 |  | 7 | 10 |  | 9 |
| Diode characterisation | DC | 9.6.15 | 3 | 6,9 | 4,13 | 3,7,11 | 4,12 |
| Solar Cell reverse bias test | RB | 7.5.16 |  | 10 | 17 |  | 15 |
| Thermal cycling | CY | 7.5.17 |  |  |  | 8 |  |
| Active-passive interface | IF | 7.5.18 |  | 3 |  |  |  |
| Flatness | FT | 7.5.19 |  | 4 |  |  |  |
| NOTE 1 The numbers in the subgroup columns indicate the sequence in which the tests are performed; e.g. for subgroup O, the 1st test is VI, the 2nd test DW, the 3rd is EP, the 4th is DC and so on.  NOTE 2 The reason for dividing the test samples into subgroups is to generally test for the following: - Subgroup A: contact adherence (front and rear side) - Subgroup B: BOL performance - Subgroup C: Electron irradiation - Subgroup O: Extended storage simulation - Subgroup P: Proton irradiation  NOTE 3 For additional requirements, refer to 7.4.1c.  NOTE 4 Test IF is only applicable to single junction GaAs-Ge solar cells, refer to 7.5.18.1.  NOTE 5 For EOL solar cells, only Coverglass Loss (GL) is applicable, refer to 7.5.6.3.  NOTE 6 Guidelines for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. | | | | | | | |

ECSS-E-ST-20-08\_0091138

For a procurement lot of previously qualified solar cells, the qualification tests need not to be repeated if the following conditions are satisfied:

No changes are made to the design, function or electrical or mechanical parameters of the bare solar cell.

The same source control drawing is applicable.

No changes are made to the PID.

Delta qualification tests are performed to cover the requirements imposed by the new application.

ECSS-E-ST-20-08\_0090433

The new requirements referred to in 7.4.1e.4 shall be included in a new version of the SCD-BSC.

### Qualification

#### Production and test schedule

ECSS-E-ST-20-08\_0090434

Before starting production of the qualification lot, the manufacturer shall compile a production test schedule showing by date and duration of the production and test activities, including all major processing operations and key stages in the production and testing.

ECSS-E-ST-20-08\_0090435

A production flow chart, process schedules and inspection procedures shall be provided.

#### Qualification test samples

ECSS-E-ST-20-08\_0090436

The solar cells for qualification testing shall conform to the PID.

ECSS-E-ST-20-08\_0090437

The test samples shall be chosen statistically and at random from the qualification lot

1. For sampling see ISO 2859.

ECSS-E-ST-20-08\_0090438

The qualification lot shall be a production lot of at least 400 cells or the number of cells to be integrated on the solar array, whichever is lower.

ECSS-E-ST-20-08\_0090439

The total number of samples shall be divided into three equal groups, referred to as high-grade, mid-grade and low-grade according to:

their current at operating voltage, or

the subcell current of the EOL limiting subcell or other electrical performance parameter, if agreed by the customer.

ECSS-E-ST-20-08\_0090440

Facilities shall be available to safely store the qualification lot including failed samples for a minimum of 6 years (equivalent to five years in storage and one year in orbit).

#### Qualification testing

ECSS-E-ST-20-08\_0090441

Qualification testing shall proceed as given in Table 7‑2.

ECSS-E-ST-20-08\_0090442

The total quantity of test samples shall be a minimum of 180 bare solar cells.

1. The number of samples per subgroup can be increased, but all samples have to follow the complete test sequence. The only aim is to allow for possible losses of qualification samples e.g. mishandling while maintaining the minimum required number.

ECSS-E-ST-20-08\_0090443

The qualification tests shall be divided into subgroups of tests, and the samples assigned to a subgroup subjected to the tests in that subgroup in the sequence specified.

ECSS-E-ST-20-08\_0090444

A failure in any subgroup shall constitute a failure in the qualification.

1. For a definition of failure see clause 7.6.

## Test methods, conditions and measurements

### Visual inspection including ELM (VI)

#### Applicability

The requirements on visually observable defects specified in this clause apply to granting qualification approval to a high quality bare solar cell.

#### Test process

ECSS-E-ST-20-08\_0090445

Solar cells shall be inspected with an equipment with a resolution which is 5 times higher than the minimum allowed defect size and by ELM, PLM or equivalent qualified methods to verify the requirements for defects on solar cell and contacts.

#### Deviations

ECSS-E-ST-20-08\_0090446

Any deviation from the visual inspection requirements on defects specified in clauses 7.5.1.4 and 7.5.1.5 shall:

not affect performance or reliability,

be agreed with the customer, and

be justified.

#### Solar cell defects

##### Edge chips, corner chips and surface nicks

ECSS-E-ST-20-08\_0090447

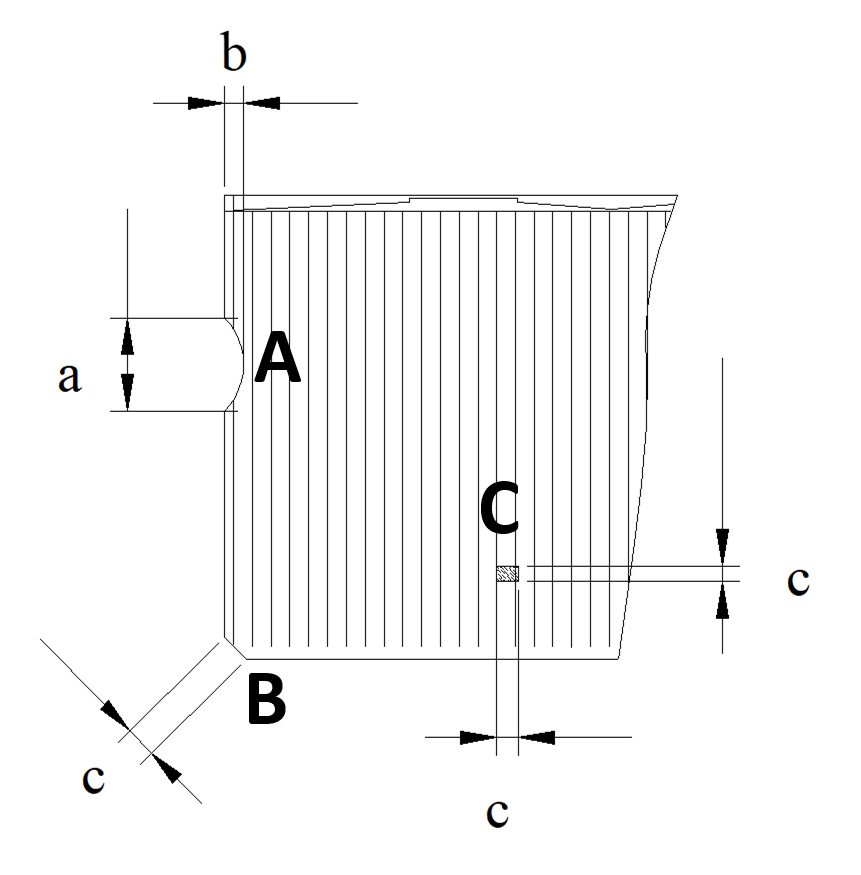
The location and maximum dimensions for allowable defects related to edge chips, corner chips and surface nicks shall be in conformance with Figure 7‑1 and Table 7‑3.

ECSS-E-ST-20-08\_0090448

The cumulative area of all edge chips, corner chips and surface nicks shall not exceed 5 % of the total cell area.

ECSS-E-ST-20-08\_0090449

Edge chips, corner chips and surface nicks shall not be present in the contact weld area.



A = edge chip B = corner chip C = surface nick

ECSS-E-ST-20-08\_0091038

Figure ‑: Definition of bare solar cell defects

ECSS-E-ST-20-08\_0091039

Table ‑: Maximum dimensions of corner chips, edge chips and surface nicks

|  |  |  |  |
| --- | --- | --- | --- |
| Cell area (cm2) | Dimensions of defects (mm) | | |
| a | b | c |
| 4 | 4 | 0,7 | 1,5 |
| 8 | 6 | 0,8 | 2 |
| 12 | 8 | 0,9 | 2,5 |
| 25 | 10 | 1 | 4 |
| 32 | 12 | 1,1 | 5 |

##### AR coating

ECSS-E-ST-20-08\_0090450

For acceptance and qualification, the maximum value of the total uncoated area, and the value of spatter and voids shall be 3 %.

ECSS-E-ST-20-08\_0091080

The AR coating may contain discolourations.

##### Cracks and fingerprints

ECSS-E-ST-20-08\_0090452

Cracks and fingerprints shall not be present.

#### Solar cell contact area defects

##### General

ECSS-E-ST-20-08\_0090453

The solar cell contact area shall be free of digs, scratches, and probe prints, unless metallization is still present.

ECSS-E-ST-20-08\_0090454

Peeling, blistering and delamination of contacts shall not be present.

##### Front and rear side contact welding area

ECSS-E-ST-20-08\_0090455

The maximum dimension of voids or bubbles shall be 0,25 mm in diameter.

ECSS-E-ST-20-08\_0090456

The maximum dimension of drops and spatter shall be 0,1 mm in diameter and 0,03 mm in height.

ECSS-E-ST-20-08\_0090457

Over-coating (coating exceeding the area of the contact on the frontside only) along one side of each pad shall not exceed 0,1 mm.

ECSS-E-ST-20-08\_0090458

Digs or depressions deeper than 0,025 mm shall not be present.

ECSS-E-ST-20-08\_0090459

The cumulative area of voids, bubbles, drops and spatter shall not exceed 2 % of the total welding area.

##### Front bus bar and grids

ECSS-E-ST-20-08\_0090460

There shall be no interruptions in the front bus bar.

ECSS-E-ST-20-08\_0090461

The maximum total length of missing grids, short grids or non-continuous grids shall not exceed the total length specified in the SCD-BSC.

##### Rear side contact outside the welding area

ECSS-E-ST-20-08\_0090462

Drops and spatter shall not exceed 0,1 mm in diameter and 0,05 mm in height.

ECSS-E-ST-20-08\_0090463

The cumulative area of voids, bubbles and drops shall not exceed 2 % of the total area.

ECSS-E-ST-20-08\_0090464

Edge delaminations shall not be deeper than 0,75 mm.

ECSS-E-ST-20-08\_0090465

The maximum area of worm shaped bulges shall be 3 % of total cell contact area.

ECSS-E-ST-20-08\_0090466

The maximum length of the hypotenuse of the triangular area of visible semiconductor at the corners, shall be included in the SCD-BSC.

### Dimensions and weight (DW)

ECSS-E-ST-20-08\_0090467

The overall lateral dimensions of the cell (including thickness), contact dimensions and interconnector position shall conform to the requirements stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090468

The weight of the solar cell shall be verified by determination of the average weight per qualification lot or weight per contacts vacuum evaporation batch (sample base).

### Electrical performance (EP)

#### Purpose

The purpose of the EP test is to assess the corresponding electrical parameters of the solar cells and to provide data for the design of the solar generator.

#### Process

ECSS-E-ST-20-08\_0090469

The electrical current of solar cells under 1 S.C. (AM0) shall be measured and recorded digitally, at least at 50 points, at a solar cell temperature of 25 C or operating temperature.

ECSS-E-ST-20-08\_0090470

The electrical parameters measured or processed from requirement 7.5.3.2a and identified in Figure 6‑2 shall

be derived from the full curve, and

delivered to the customer together with:

their average and standard deviation values, and

digital data of the full curves.

ECSS-E-ST-20-08\_0090471

The accuracy of the bare solar cell measured parameters (Isc, Voc and Pmax) shall be provided to the customer.

ECSS-E-ST-20-08\_0090472

During measurement, the cells shall be kept at a constant temperature (+/- 0,5 °C).

ECSS-E-ST-20-08\_0090473

A continuous or pulsed light source calibrated in conformance with clause 10 shall be used to verify the requirements given in the SCD-BSC for electrical characterization.

ECSS-E-ST-20-08\_0090474

There shall be a maximum of 3 % deviation in the current at the test voltage Vt, from the measurements before test, after the humidity and thermal cycling test in subgroup O.

### Temperature coefficients (TC)

ECSS-E-ST-20-08\_0090475

Temperature coefficients of all 1 MeV electron samples in subgroup C shall be measured.

ECSS-E-ST-20-08\_0090476

The test described in clause 7.5.3 shall be repeated at three equidistant solar cell temperatures covering the range of operational temperatures and three temperatures close to extremes t1 and three temperatures close to extreme t2, defined as follows, and stated in the SCD-BSC:

t1 = highest operating temperature (without margins) predicted for the application

t2 = lowest operating temperature (without margins) predicted for the application

1. The 3 temperatures close to the extremes to be chosen at equidistance of 10 K to 20 K depending on the limitations of the test facility with at least one measurement at the extreme temperature.

ECSS-E-ST-20-08\_0090477

Data for all electrical performance parameters at the different solar cell temperatures shall be provided.

ECSS-E-ST-20-08\_0090478

The temperature coefficients of short-circuit current, open circuit voltage, voltage at maximum power and maximum power shall be derived by least-square curve fitting.

ECSS-E-ST-20-08\_0090479

The coefficient of determination for the electrical parameters specified in requirement 7.5.4d, obtained from the curve fit specified in requirement 7.5.4d shall be included.

ECSS-E-ST-20-08\_0091139

For the 3 MeV electron samples of subgroup C as well as all samples of subgroup P only measurement at 60 °C and 90 °C shall be performed.

### Spectral response (SR)

#### Purpose

Spectral response data is used for the verification of the sun simulator (see clauses 10.1.1 and 10.1.2) for performance measurement error calculation, for the characterization of the spectral response spread of production cells, for EOL degradation evaluation and for current matching investigation in multi-junction solar cells.

#### Process

ECSS-E-ST-20-08\_0090480

Spectral response shall be measured on half of the samples of subgroup C and P, by comparing the short-circuit current of the test cells against the output of a spectral standard of known relative spectral response under monochromatic irradiation.

ECSS-E-ST-20-08\_0090481

The monochromatic irradiation shall be generated by one of the following methods:

The irradiation shall be generated with the aid of narrow-band interference filters, having the following characteristic:

for silicon solar cells, at least, at 14 discrete wavelength intervals between 0,3 m and 1,1 m;

for single-junction GaAs solar cells at least, at 14 discrete wavelength intervals between 0,3 m and 1,1 m and at least 3 narrow band interference filters in the range 0,75 m to 1,1 m.

for multi-junction GaAs solar cells, the number of narrow band interference filters and their wavelength are stated in the SCD-BSC.

By means of a high intensity monochromator for continuous recording between 0,3 m and at least 1,8 m.

ECSS-E-ST-20-08\_0090482

The irradiation intensity at all wavelengths shall be such as to ensure that the measurement is made in the region where the cell response short-circuit current versus irradiance is linear.

ECSS-E-ST-20-08\_0090483

For multi-junction solar cells, it shall be ensured that the measurements are performed on the current limiting subcell, and that it is working close to short-circuit conditions.

### Optical properties (OP)

#### Overview

Hemispherical reflectance is used for the definition of acceptance criteria for silicon BSR solar cells only. Coverglass gain loss, is measured to provide input for the performance of the SCA. Solar absorptance of the cell is measured to provide data on the operational temperature of the SCA.

#### Hemispherical reflectance (HR)

ECSS-E-ST-20-08\_0090484

Hemispherical reflectance shall be measured in the wavelength region from 250 nm to 2 500 nm.

ECSS-E-ST-20-08\_0090485

The reflectance value for the acceptance of silicon BSR solar cells at 1,5 m shall be stated in the SCD-BSC.

#### Coverglass gain-loss (GL)

ECSS-E-ST-20-08\_0090486

For single junction solar cells, the coverglass gain-loss stated in the SCD-BSC shall be determined by using n-Amyl alcohol in order to simulate the optical properties of the adhesive.

ECSS-E-ST-20-08\_0090487

For multi-junction solar cells, the agent to be used to simulate the optical properties of the adhesive shall be stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090488

The coverglass as stated in the SCD-BSC shall be used.

ECSS-E-ST-20-08\_0090489

The solar cells shall be submitted to an electrical performance test before and after applying the coverglass, as specified in requirements 7.5.6.3a to 7.5.6.3c, according to clause 7.5.3 under the following test conditions:

at an illumination of 1 S.C. (AM0);

a temperature, as stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090490

The pass-fail criteria shall be stated in the SCD-BSC.

#### Solar absorptance (as)

ECSS-E-ST-20-08\_0090491

The solar absorptance shall be measured according to ECSS-Q-ST-70-09.

### Humidity and temperature (HT)

#### HT1 for qualification testing (subgroup O)

##### Purpose

This test is an accelerated shelf-life test to monitor the stability of contacts, anti-reflection coatings and integrated diode in a humid atmosphere.

##### Process

ECSS-E-ST-20-08\_0090492

All cells in subgroup O shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090493

The chamber temperature shall then be increased to 60 C minimum.

ECSS-E-ST-20-08\_0090494

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090495

The duration of the test shall be 30 days.

ECSS-E-ST-20-08\_0090496

In the case of solar cells with Aluminium content window layers, this test shall be extended to simulate on-ground expected duration, and humidity and temperature conditions.

ECSS-E-ST-20-08\_0090497

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090498

Water condensation on the surface of the cells shall be prevented.

ECSS-E-ST-20-08\_0090499

If there are requirements on specific environmental conditions, they shall be stated in the SCD-BSC.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

#### HT2 for qualification (subgroup A) and acceptance testing

##### Purpose

This test is to verify the adherence of the contacts to the solar cell and diode, if available.

##### Process

ECSS-E-ST-20-08\_0090500

All cells shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090501

The chamber temperature shall then be increased to 95 C minimum.

ECSS-E-ST-20-08\_0090502

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090503

The duration of the test shall be 24 h.

ECSS-E-ST-20-08\_0090504

High-purity water in accordance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090505

Water condensation on the surface of the cells shall be prevented.

ECSS-E-ST-20-08\_0090506

If there are requirements on specific environmental conditions, they shall be stated in the SCD-BSC.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

### Coating adherence (CA)

#### Purpose

This test is performed to verify the durability of the anti-reflection coating, the contacts of cell and integrated diode.

#### Process

ECSS-E-ST-20-08\_0090507

The test samples shall be subjected to a coating adherence test on both full sample faces.

ECSS-E-ST-20-08\_0090508

Test method shall be established according to a standard which is mutually agreed with the customer.

1. For the test conditions of the coating adherence test, MIL-M-13508, ISO 9211-4 and ECSS-Q-ST-70-13 can be used.

ECSS-E-ST-20-08\_0090509

The adhesive tape used for this test shall be clear in colour with an adhesive strength on steel of at least 0,28 N/mm.

1. For measuring the adhesive strength on steel, EN 1939 can be used.

ECSS-E-ST-20-08\_0090510

Any visible delamination of parts of the contacts or the anti-reflection coating shall not exceed the limits specified in clauses 7.5.1.4 and 7.5.1.5.

### Contact uniformity (CU)

#### Purpose

The contact uniformity test verifies the uniformity of the thickness of the solar cell contacts during qualification.

#### Process

ECSS-E-ST-20-08\_0090511

The uniformity of the thickness of the metal contact in the interconnector weld area shall be checked with a step-height profiler for instance a betascope or a similar instrument as stated in the SCD-BSC.

#### Pass fail criteria

ECSS-E-ST-20-08\_0090512

The uniformity of the contact thickness of the metal layers of the cell contact shall conform to the requirements of the interconnection process (as stated in the SCD-BSC).

### Contact thickness (CT)

#### Purpose

The contact thickness test verifies the thickness of the solar cell contacts during acceptance test.

#### Process

ECSS-E-ST-20-08\_0090513

The thickness of the solar cell metal contact in the interconnector weld area or on dedicated in-process test samples shall be checked with a step-height profiler, as stated in the SCD-BSC.

1. For example, with a betascope or a similar instrument.

#### Pass fail criteria

ECSS-E-ST-20-08\_0090514

The thickness of the metal layers of the cell contact shall conform to the requirements of the interconnection process (as stated in the SCD-BSC).

### Surface finish (SF)

#### Purpose

The surface finish test verifies the surface finish of the solar cell contacts during qualification test.

#### Process

ECSS-E-ST-20-08\_0090515

The surface finish in the interconnector weld area shall be checked with a micro surface-roughness tester.

#### Pass fail criteria

ECSS-E-ST-20-08\_0090516

The surface finish of the metal layers of the cell contact shall conform to the requirements of the interconnection process (as stated in the SCD‑BSC).

### Pull test (PT)

#### Purpose

The objective of the pull test is to check the bond strength of the front and rear side contacts under mechanical and environmental stress.

#### Process

ECSS-E-ST-20-08\_0090517

A gradually increasing pull force shall be applied to the interconnector separately for each interconnector tab at a pull speed as stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090518

The ultimate pull strength of each tab shall be as stated in the SCD-BSC, considering the number of pulled tabs and their widths.

ECSS-E-ST-20-08\_0090519

The pull direction shall:

be either 0°, 45° or 90°;

be as stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090520

The type of failure shall be recorded in the data documentation package (DDP) as specified in clause 7.7.

### Electron irradiation (EI)

#### Purpose

This test is an accelerated life test to check the solar cell performance degradation under electron particle irradiation.

1. The irradiation tests defined in the following represent the minimum data set that is required for performing solar cell degradation prediction. Hereby, it is assumed that the solar cells are III-V based direct semiconductors and that the energy dependence of the damage inside the solar cells is derived from a NIEL (non-ionizing energy loss) calculation. The NIEL curve can be equivalently applied within the displacement damage dose approach but also in the equivalent fluence method where the NIEL curve is directly proportional to the relative damage coefficients (RDCs).

#### Process

ECSS-E-ST-20-08\_0090521

The solar cells shall be subjected to 1 MeV and 3 MeV electron irradiation or at energies agreed by the customer.

1. ISO 23038 outlines a methodology to perform this test.

ECSS-E-ST-20-08\_0090522

The flux density and energy shall be uniform over the cell area within ±10 %.

ECSS-E-ST-20-08\_0090523

During irradiation, the cells shall be protected from oxidation, using either vacuum (below 10-3 Pa) or a dry atmosphere of nitrogen or argon at a temperature of (20 ± 10) C.

ECSS-E-ST-20-08\_0090524

The nominal flux shall be lower than 5 × 1011 e- cm-2 s-1, except for fluences beyond 1 × 1015 e cm‑2 where the flux can be increased up to 1,5 × 1012 e cm‑2 s‑1.

ECSS-E-ST-20-08\_0090525

Selection of solar cells of subgroup C shall be done as follows:

apply five fluences per energy, as stated in the SCD-BSC, for specific cell types and to cover typical applications;

test for each fluence, in conformance with requirement 7.4.2.2d, a minimum of the following bare solar cell numbers:

2 high-grade cells;

2 mid-grade cells;

2 low-low grade cells;

perform as a minimum 4 energy/fluence combinations with cells of nominal size.

ECSS-E-ST-20-08\_0090526

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ECSS-E-ST-20-08\_0090527

After electron irradiation, photon irradiation and temperature annealing, the requirements in requirement 7.5.3.2e shall be satisfied.

ECSS-E-ST-20-08\_0090528

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ECSS-E-ST-20-08\_0091140

The electron irradiation may be performed on smaller cell sizes than the nominal ones under the following conditions:

the cells are manufactured from the same substrate dimension as the nominal cell size,

the cells reflect a representative production distribution,

at least 12 smaller size cells are submitted to two energy-fluence combinations to which cells of nominal size are irradiated.

1. to item 2: i.e. not only cells from one wafer or one epitaxial growth run or location on the wafer.

### Proton irradiation (PI)

#### Purpose

The purpose of this test is to monitor the degradation of solar cell performance under proton particle irradiation.

1. The irradiation tests defined in the following represent the minimum data set that is required for performing solar cell degradation prediction. Hereby, it is assumed that the solar cells are III-V based direct semiconductors and that the energy dependence of the damage inside the solar cells is derived from a NIEL (non-ionizing energy loss) calculation. The NIEL curve can be equivalently applied within the displacement damage dose approach but also in the equivalent fluence method where the NIEL curve is directly proportional to the relative damage coefficients (RDCs).

#### Process

ECSS-E-ST-20-08\_0090529

The solar cells shall be subjected to proton irradiation with two different proton energies 1MeV and 3MeV, or at energies agreed by the customer.

1. ISO 23038 outlines a methodology to perform this test.

ECSS-E-ST-20-08\_0090530

The flux density and energy shall be uniform over the cell area within ±10 %.

ECSS-E-ST-20-08\_0090531

During irradiation, the cells shall be protected from oxidation, using either vacuum below 10-3 Pa, or a dry atmosphere of nitrogen or argon at a temperature of (20 ± 10) °C.

ECSS-E-ST-20-08\_0090532

The nominal flux to be stated in the SCD-BSC, shall be low enough not to heat the cells during irradiation above 30 °C to avoid annealing.

1. Typically the flux is between 1E09cm-2s-1 and 6E10cm-2s-1.

ECSS-E-ST-20-08\_0091141

The selection of solar cells of subgroup P shall be as follows:

apply five fluences per energy, as stated in the SCD-BSC, for specific cell types and to cover typical applications;

test for each fluence, in conformance with requirement 7.4.2.2d a minimum of:

2 high-grade cells;

2 mid-grade cells;

2 low-grade cells;

perform as a minimum 4 energy/fluence combinations with cells of nominal size.

ECSS-E-ST-20-08\_0091142

The proton irradiation may be performed on smaller cell sizes than the nominal size, specified in 7.5.14.2e.3, if all the following conditions are met:

the smaller cells used are manufactured from the same substrate dimension as the nominal cell size;

solar cells of smaller size reflect a representative production distribution and are not only cells from one wafer or one epitaxial growth run or one location on the wafer;

at least 12 smaller size cells are submitted to two energy/fluence combinations to which cells of nominal size are irradiated.

ECSS-E-ST-20-08\_0091143

After proton irradiation, photon irradiation and temperature annealing, the requirements in 7.5.3.2e shall be satisfied.

### Photon irradiation and temperature annealing (PH)

#### Purpose

This test is to verify the stability of solar cell performance under the equivalent light and temperature of 1 S.C. (AM0).

1. It is good practice to do “electrical performance” at the samples directly after proton/electron irradiation but before “Photon irradiation and temperature annealing” to check the effect of annealing.

#### Process

ECSS-E-ST-20-08\_0090533

During the test, solar cells of subgroups B, C and P shall be subjected to the following:

irradiated with 1 S.C. (AM0) for 48 h;

be kept at (25 ± 5) C;

be in an open circuit condition.

ECSS-E-ST-20-08\_0090534

The cells shall be subsequently temperature annealed for 24 h at 60 C in darkness.

ECSS-E-ST-20-08\_0090535

After the tests, the cells shall be kept at temperatures below 50 C until they are electrically measured.

### Solar cell reverse bias test (RB)

#### Purpose

The purpose of solar cell reverse bias test is to check for performance degradation of the solar cell due to reverse bias.

#### Process

ECSS-E-ST-20-08\_0090536

For solar cells without a protection diode or with a protection diode electrically isolated from the cell, the process shall be as follows:

Measure the reverse I/V characteristics of the bare solar cell under illumination of 1 S.C. (AM0) with a limiting power supply (to avoid destructive breakdown).

Ensure that the parameters of reverse I/V characteristics measurement are as stated in the SCD-BSC concerning temperature, hold time, current limitation, maximum reverse bias (voltage).

ECSS-E-ST-20-08\_0090537

For solar cells with a protection diode electrically connected to the cell, solar cell reverse bias test shall not be applied.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0090538

Solar cell reverse bias test shall satisfy the pass-fail criteria stated in the SCD-BSC.

### Thermal cycling (CY)

#### Purpose

The purpose of this test is to assess the reliability of test samples under a thermal stress equivalent to the number of eclipses that occur during one year in orbit for LEO missions, 1000 thermal cycles for GEO missions or the complete lifetime cycling for interplanetary or other mission types.

#### Process

ECSS-E-ST-20-08\_0090539

The number of cycles and the extreme temperatures shall be those as stated in the SCD-BSC.

ECSS-E-ST-20-08\_0091144

Additional cycles, to the ones specified in requirement 7.5.15.2a, shall be added to cover mission phases with low occurrence but very extreme temperatures, and agreed with the customer.

### Active-passive interface evaluation test (IF)

#### Purpose

This test is performed to determine if the single junction GaAs-Ge cell has got an active or passive interface layer.

#### Process

ECSS-E-ST-20-08\_0090540

Test in clause 7.5.3 shall be repeated using a non infrared-rich simulator having a maximum deviation of the total energy in the spectral region of 0,8 m to 1,1 m (as described in clause 10.1.1) of a percentage value stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090541

The delta value of the open circuit voltage of bare cells with an active interface under the two solar simulator conditions (1 S.C (AM0) and non- infrared rich) shall be less than the value stated in the SCD-BSC.

### Flatness test (FT)

#### Purpose

The purpose of this test is to determine the flatness of the bare solar cell.

#### Process

ECSS-E-ST-20-08\_0090542

The flatness shall be determined by measuring the maximum deflection, d, of the bare solar cell measured on an optically flat surface with an orientation and method as stated in the SCD-BSC.

#### Pass/fail criteria.

ECSS-E-ST-20-08\_0090543

The deflection of the bare cell shall be lower than the deflection value stated on the SCD-BSC.

## Failure definition

### Failure criteria

ECSS-E-ST-20-08\_0090544

The following shall constitute failures:

Components that fail during subgroup tests for which the pass-fail criteria are inherent in the test method.

Components failing to conform to the requirements of visual inspection stated in the SCD-BSC.

Components whose marking fails to conform to the requirements of clause 7.1.3.

Components that, when subjected to electrical performance measurements after acceptance tests in conformance with the SCD-BSC, fail to meet one or more of the specified limits, measurement accuracy included.

### Failed components

ECSS-E-ST-20-08\_0090545

A component shall be considered to have failed if it exhibits one or more of the failure modes specified in clause 7.6.1.

ECSS-E-ST-20-08\_0090546

Failed components shall be identified as such and included in the delivery.

ECSS-E-ST-20-08\_0090547

Failure analysis of these components shall be performed by the supplier and the results provided to the customer as part of an NRB documentation.

1. For NRB, see ECSS-Q-ST-10-09.

## Data documentation

ECSS-E-ST-20-08\_0090548

The supplier shall provide a data documentation package (DDP) in conformance with Annex G, for the qualification approval records and for each component delivery lot.

## Delivery

ECSS-E-ST-20-08\_0090549

All deliverable hardware specified in the order shall be delivered together with documentation in conformance with the requirements specified in clause 7.7.

ECSS-E-ST-20-08\_0090550

One set of documents shall be sent to the customer.

## Packing, dispatching, handling and storage

### Overview

For packaging, dispatching, handling and storage of components see ECSS-Q-ST-20-08.

### ESD Sensitivity

ECSS-E-ST-20-08\_0090551

If a bare cell is sensitive to ESD according to clause 5.2 of ESCC 23800 Issue 1 then it shall be handled and stored according to ESCC 24900 Issue 2, clause 10.

# Coverglasses

## Overview

### Purpose

This Clause specifies the generic requirements for the manufacture, test and qualification of coated coverglasses (CVG) for solar cell photovoltaics in the space environment and the requirements to guarantee the performance of a manufacturing lot.

This Clause, along with the source control drawing for coverglasses (SCD-CVG) and process identification document, specifies the performance requirements for the coverglass component.

### Description

The coverglasses are designed for use as a transparent protective shield for a range of solar cells.

Coverglass substrates are either made of fused silica or a borosilicate microsheet. The latter has a nominal concentration of cerium dioxide to increase the radiation stability of the coverglass and selectively filter out the short wavelength ultraviolet radiation to protect the underlying coverglass bonding adhesive. In the case of fused silica, a UV reflective coating is used to protect the underlying adhesive.

The glass is defined by its elemental composition, which is measured throughout the production cycle to ensure consistent physical characteristics.

## Interfaces

ECSS-E-ST-20-08\_0090552

The design of the coverglasses shall enable bonding to solar cells with space qualified adhesives.

## Testing, deliverable components and marking

### Testing

#### Tests for qualification and procurement

ECSS-E-ST-20-08\_0090553

Tests for qualification of coverglasses shall comprise acceptance and qualification tests.

ECSS-E-ST-20-08\_0090554

Tests for procurement of qualified coverglasses shall comprise acceptance tests.

#### Conditions and methods of tests

ECSS-E-ST-20-08\_0090555

The conditions and methods of testing shall conform to the coverglass source control drawing (SCD-CVG).

1. The coverglass specification consists of two parts, this Standard and the SCD-CVG. For the preparation of the SCD-CVG, refer to Annex D.

ECSS-E-ST-20-08\_0090556

The SCD-CVG shall be prepared by the supplier in conformance with Annex D and provided to the customer for reviewing and agreement.

ECSS-E-ST-20-08\_0090557

Any deviation from in-process, acceptance and qualification test procedures shall be justified in the SCD-CVG.

ECSS-E-ST-20-08\_0090558

Deviations from this Standard applicable to the SCD-CVG shall:

be agreed between the customer and the supplier;

include alternative requirements equivalent to those of this Standard;

not affect the reliability and performances of the coverglasses;

only be those specified in requirement 8.3.1.2c.

#### Responsibility of supplier for the performance of tests and inspections

ECSS-E-ST-20-08\_0090559

The supplier shall ensure that the tests and inspections are performed.

ECSS-E-ST-20-08\_0090560

These tests and inspections shall be performed at the plant of the manufacturer or at a facility approved by the customer.

1. For test house requirements, see ECSS-Q-ST-20-07.

### Deliverable components

ECSS-E-ST-20-08\_0090561

Delivered coverglasses shall be processed and inspected in conformance with the requirements of the process identification document (PID) specified in clause 8.4, and the requirements of the acceptance test specified in clause 8.5.

ECSS-E-ST-20-08\_0090562

Delivered coverglasses shall have completed all tests and inspections stated in the SCD-CVG.

### Marking (coating orientation)

ECSS-E-ST-20-08\_0090563

The coated face of the component shall be identified.

1. This requirement can be satisfied using for instance one of the methods shown in Figure 8‑1. or equivalent.

ECSS-E-ST-20-08\_0090564

The orientation method along with associated dimensional tolerances shall be stated in the SCD-CVG.



etch symbol ink stain corner crop

Figure ‑: Methods of defining coverglass orientation

## Production control (Process identification document)

ECSS-E-ST-20-08\_0090565

A process identification document (PID) for the coverglasses to be qualified shall be prepared by the supplier in conformance with Annex F.

ECSS-E-ST-20-08\_0090566

The supplier shall do the following:

maintain configuration control of all documents;

keep the issues of the documents effective at the date of acceptance by the customer;

provide the PID to the customer for review;

submit to the customer for review and approval any modifications or changes to documents in the PID with any quality and reliability implications.

## Acceptance test

### Acceptance test samples

ECSS-E-ST-20-08\_0090567

A minimum of 40 test samples shall be selected statistically and at random from the shipment lot.

ECSS-E-ST-20-08\_0091081

Sample size may be modified depending on specific project requirements, as stated in SCD-CVG.

1. For sampling see ISO 2859.

### Acceptance test sequence

ECSS-E-ST-20-08\_0090569

Acceptance tests shall be performed on the following:

components for delivery;

components used for qualification.

ECSS-E-ST-20-08\_0090570

Acceptance tests shall consist on the following:

Submit 50 % of the samples (as selected in clause 8.5.1) to the following tests:

transmission into air;

dimensions;

weight;

thickness.

flatness

Submit the remaining 50 % of the samples (as selected in clause 8.5.1) to the following tests:

visual inspection and transmission into air;

humidity and temperature HT4;

visual inspection and transmission into air;

abrasion resistance;

visual inspection;

thermal cycling;

coating adhesion;

visual inspection.

ECSS-E-ST-20-08\_0090571

The data documentation corresponding to the tests referred in requirement 8.5.2b shall be delivered together with the delivered coverglasses and the qualification test sub-lot.

### Test methods and conditions

ECSS-E-ST-20-08\_0090572

The test methods and conditions shall conform to clause 8.7.

### Documentation

ECSS-E-ST-20-08\_0090573

Documentation on acceptance tests shall conform to clause 8.9.

## Qualification tests

### General

ECSS-E-ST-20-08\_0090574

Qualification of CVGs shall be granted by the customer.

ECSS-E-ST-20-08\_0090575

All coverglass procurement lots shall be qualified.

ECSS-E-ST-20-08\_0091145

If a purchase order is placed for a procurement lot of a previously qualified coverglass, the qualification tests need not to be repeated if the following conditions are satisfied:

No changes are made to the design, function or mechanical parameters of the coverglass.

The same SCD-CVG is applicable.

No changes are made to the PID.

ECSS-E-ST-20-08\_0090577

Qualification shall consist of the tests specified in Table 8‑1.

ECSS-E-ST-20-08\_0090578

The supplier shall provide details of the outcome of the qualification programme to the customer.

### Qualification

#### Production and test schedule

ECSS-E-ST-20-08\_0090579

Before starting production of the qualification lot, the manufacturer shall compile a production test schedule, showing by date and duration, production and test activities, including all major processing operations and key stages in the production and testing.

ECSS-E-ST-20-08\_0090580

Process schedules and inspection procedures shall be provided.

#### Qualification test samples

ECSS-E-ST-20-08\_0090581

The supplier shall provide access to the customer to monitor the manufacture of the coverglass qualification set.

ECSS-E-ST-20-08\_0090582

The coverglass qualification set shall be chosen statistically and at random from the first coating lots, as stated in the SCD-CVG.

1. For sampling see ISO 2859.

#### Qualification testing

ECSS-E-ST-20-08\_0090583

Qualification testing shall proceed as given in Table 8‑1, with the following conditions:

The total quantity of test samples (in Table 8‑1) shall be agreed between the customer and supplier.

The qualification tests shall be divided into subgroups of tests.

The samples assigned to a subgroup shall be subjected to the tests in that subgroup in the sequence specified.

1. 1 For example, 20 coverglasses for each subgroup and 5 for every radiation dose.
2. 2 The number of samples per subgroup can be increased, but all samples have to follow the complete test sequence. The only aim is to allow for possible losses of qualification samples e.g. mishandling while maintaining the minimum required number.

ECSS-E-ST-20-08\_0090584

A failure in any subgroup shall constitute a failure in the qualification.

ECSS-E-ST-20-08\_0091040

Table ‑: Qualification test plan for coverglasses

| Test | Symbol | Method | Un-coated | Coated or uncoated coverglasses | | | | | | |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| A (20) | B (20) | U (20) | O (20) | V (20) | C (20) | P (20) | S (10) |
| Visual inspection | VI | 8.7.1 | 1 | 1 | 1,4 | 1,4,7,10,12 | 1,4 | 1,4 | 1,4 |  |
| Transmission into air | TA | 8.7.2 | 2 | 2 | 2,5 | 2,5, 8 | 2,5 | 2,5 | 2,5 |  |
| Electro-optical properties | EO | 8.7.3 | 3 | 3 |  |  |  |  |  |  |
| Mechanical properties | MP | 8.7.4 |  | 4 |  |  |  |  |  |  |
| Reflectance properties | OP | 8.7.5 |  | 5 |  |  |  |  |  |  |
| Normal emittance | NE | 8.7.6 |  | 6 |  |  | 6 | 6 | 6 |  |
| Surface resistivity | SC | 8.7.7 |  | 7 |  |  | 7 | 7 | 7 |  |
| Flatness | FT | 8.7.8 |  | 8 |  |  |  |  |  |  |
| Transmission into adhesive | TH | 8.7.9 |  | 9 |  |  |  |  |  |  |
| Boiling water | BW | 8.7.10 |  |  | 3 |  |  |  |  |  |
| Humidity and temperature 3 | HT3 | 8.7.11.1 |  |  |  | 3 |  |  |  |  |
| UV exposure | UV |  |  |  |  |  | 3 |  |  |  |
| Electron irradiation | EI | 8.7.13 |  |  |  |  |  | 3 |  |  |
| Proton irradiation | PI | 8.7.14 |  |  |  |  |  |  | 3 |  |
| Breaking strength | BS | 8.7.15 |  |  |  |  |  |  |  | 1 |
| Thermal cycling | CY | 8.7.16 |  |  |  | 6 |  |  |  |  |
| Abrasion resistance | AE | 8.7.17 |  |  |  | 9 |  |  |  |  |
| Coating adhesion | TD | 8.7.18 |  |  |  | 11 |  |  |  |  |
| NOTE 1 The numbers in the subgroup columns indicate the sequence in which the tests are performed; e.g. for subgroup A, the 1st test is VI, the 2nd test TA, the 3rd is EO, and so on.  NOTE 2 The reason for dividing the test samples into subgroups is to generally test for the following: - Subgroup A: Physical properties of coverglass substrate material - Subgroup B: Mechanical properties and BOL data - Subgroup U: Coating adherence (Solubility) - Subgroup O: Humidity and temperature coating stability - Subgroup V: UV exposure - Subgroup C: Electron irradiation - Subgroup P: Proton irradiation - Subgroup S: Breaking strength  NOTE 3 Guidelines for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. | | | | | | | | | | |

## Test methods, conditions and measurements

### Visual inspection (VI)

#### General

ECSS-E-ST-20-08\_0090585

All the coverglasses shall be visually inspected with the naked eye to verify the requirements for defects on coverglasses in conformance with clause 8.7.1.2.

#### Deviations

ECSS-E-ST-20-08\_0090586

Any deviation from the visual inspection requirements on defects in clause 8.7.1.3 shall:

not affect performance or reliability,

be agreed with the customer, and

be justified.

#### Defects

##### Coated coverglasses

ECSS-E-ST-20-08\_0090587

The coated area shall have a uniform appearance, with no visible evidence of pinholes, voids or spatter.

1. See MIL-PRF-13830.

ECSS-E-ST-20-08\_0090588

For a coated coverglass, the uncoated area due to coating tools shall not exceed 1 % of the total coverglass area or 8 mm2, whichever is greater.

##### Scratch and dig

ECSS-E-ST-20-08\_0090589

The maximum dimensions of scratches and digs shall be stated in the SCD-CVG.

1. See MIL-PRF-13830.

##### Bubbles and inclusions

ECSS-E-ST-20-08\_0090590

The projected area of any bubble or inclusions in the coverglass shall not be larger than 0,02 mm2.

1. See MIL-PRF-13830.

##### Edge chips

ECSS-E-ST-20-08\_0090591

The projection into the coverglass face, defined by “b” in Figure 8‑2, shall not exceed 0,25 mm.

ECSS-E-ST-20-08\_0090592

The length of the chip, defined by “a” in Figure 8‑2, shall not exceed 0,6 mm.

ECSS-E-ST-20-08\_0091082

Edge chips with a dimension of the projection into the coverglass face of b < 0,1 mm and a length of the chip a < 0,2 mm (in conformance with Figure 8‑2) may be ignored.



ECSS-E-ST-20-08\_0091041

Figure ‑: Edge chip parameters

##### Corner chips

ECSS-E-ST-20-08\_0090594

The length of the hypotenuse, as defined by “d” in Figure 8‑3, of any corner chip in the coverglass, shall not exceed 0,75 mm.

ECSS-E-ST-20-08\_0090595

The SCD-CVG shall state a requirement specifying the maximum number of chips per coverglass.



ECSS-E-ST-20-08\_0091042

Figure ‑: Corner chip parameters

##### Cracks

ECSS-E-ST-20-08\_0090596

Surface, edge or corner cracks shall not be present on a coverglass.

1. For further information, see MIL-PRF-13830.

##### Dirty and contaminated surfaces

ECSS-E-ST-20-08\_0090597

Coverglasses shall not have dirty or contaminated surfaces.

1. For further information, see MIL-PRF-13830.

### Transmission into air (TA)

ECSS-E-ST-20-08\_0090598

The transmission into air of the coverglass shall be measured (for λ and T in conformance with requirement 8.7.2b) using a calibrated spectro-photometer as follows:

at an incidence angle of less than 10,

with a wavelength tolerance of (λ ± 2) nm, and

an absolute transmission tolerance of (T ± 1) %.

ECSS-E-ST-20-08\_0090599

The transmission values, before and after testing at discrete wavelengths and in spectral ranges, representing the cut-on and spectral ranges of the individual junctions, shall be specified in the SCD-CVG, depending on the solar cell type.

### Electro-optical properties (EO)

#### Bulk and surface resistivity

ECSS-E-ST-20-08\_0090600

The values and tolerances of the bulk resistivity and surface resistivity, derived from an electrical measurement made between two geometrically defined, evaporated electrical contacts on the glass substrate, shall be stated in the SCD-CVG.

#### Refractive index

ECSS-E-ST-20-08\_0090601

The values and tolerances of the refractive index, measured using the following V-block refractometer method, shall be stated in the SCD‑CVG:

Prepare the samples by cutting 22 mm × 22 mm square samples and clamp them together to give a small block approximately 6 mm in thickness.

Place this block into the V of a V-block prism made of a glass of refractive index similar to that of the sample under test.

To achieve the optical contact, use a matching refractive index fluid.

Measure first a reference block of known refractive index in order to calibrate the apparatus.

Use a sodium d-line as the light source.

1. To item 4.: The instrument gives an absolute measurement referenced to this Standard with an accuracy better than ±10-4 over the range of 1,47 to 1,65.

### Mechanical properties (MP)

#### Dimension and weight

ECSS-E-ST-20-08\_0090602

The dimensions and associated tolerances of the coverglass shall be stated in the SCD-CVG and conform to the tolerance limits defined in Figure 8‑4.

ECSS-E-ST-20-08\_0090603

The values and tolerances of the weight of the coverglass, verified by determining the average weight per shipping lot, shall be as stated in the SCD-CVG.



ECSS-E-ST-20-08\_0091043

Figure ‑: Coverglass manufacturing tolerance limits

#### Density

ECSS-E-ST-20-08\_0090604

The density and tolerances of a sample of the glass, weighed in air and water using an analytical balance at 25 C, shall conform to the requirements stated in the SCD-CVG.

1. Density is calculated from the measured specific gravity and the density of water at 25 C.

#### Thickness

ECSS-E-ST-20-08\_0090605

The coverglass thickness along with the associated tolerances shall be as stated in the SCD-CVG.

ECSS-E-ST-20-08\_0090606

The thickness shall be measured using a calibrated micrometer.

#### Edge parallelism

ECSS-E-ST-20-08\_0090607

The edge parallelism shall be as stated in the SCD-CVG.

ECSS-E-ST-20-08\_0090608

The edge parallelism shall be measured using a calibrated micrometer.

#### Perpendicularity of sides

ECSS-E-ST-20-08\_0090609

The perpendicularity of the sides of the coverglass shall be measured using an optical instrument with a reference normal.

ECSS-E-ST-20-08\_0090610

The perpendicularity shall be as stated in the SCD-CVG.

### Reflectance properties (OP)

#### Reflectance

ECSS-E-ST-20-08\_0090611

The reflectance shall be measured using a calibrated spectro-photometer using a W-reflectance method or integrating sphere.

ECSS-E-ST-20-08\_0090612

The wavelength tolerance shall be λ ± 2 nm and a reflectance tolerance of (R ± 1) %, where λ and R are as stated in the SCD-CVG.

#### Reflectance cut-on

##### General

The reflectance cut-on is the wavelength that corresponds to 50 % absolute measured reflectance in the low wavelength side of the reflectance band.

##### Purpose

The reflectance cut-on is used to measure high reflectance bands.

1. There can be more than one high reflectance band in the coated coverglass component.

##### Requirement

ECSS-E-ST-20-08\_0090613

The reflectance cut-on shall be as stated in the SCD-CVG.

#### Reflectance cut-off

##### General

The reflectance cut-off is the wavelength that corresponds to 50 % absolute measured reflectance in the high wavelengths range of the reflectance band.

##### Purpose

The reflectance cut-off is used to measure high reflectance bands.

1. There can be more than one high reflectance band in the coated coverglass component.

##### Requirement

ECSS-E-ST-20-08\_0090614

The reflectance cut-off shall be as stated in the SCD-CVG.

#### Reflectance bandwidth

##### General

The reflectance bandwidth is the width in nanometres measured between the reflectance cut-on and cut-off divided by the centre wavelength of the reflectance band which is defined with the following equation;



where

λc is centre wavelength of the reflectance band;

λ1 is the reflectance cut-on;

λ2 is the reflectance cut-off.

##### Requirement

ECSS-E-ST-20-08\_0090615

The reflectance bandwidth shall be as stated in the SCD-CVG.

### Normal emittance (NE)

ECSS-E-ST-20-08\_0090616

The normal emittance (εn) shall be measured according to ECSS-Q-ST-70-09.

ECSS-E-ST-20-08\_0090617

The normal emittance (εn) shall be as stated in the SCD-CVG.

### Surface resistivity (SC)

ECSS-E-ST-20-08\_0090618

When a conductive coating is incorporated in the coverglass, the surface resistivity shall be measured, using the equipment stated in the SCD‑CVG, as follows:

Measure the resistance between two indium-tin soldered buzzbars applied to the coverglass, as shown in Figure 8‑5.

Calculate the surface resistivity from the resistance and the length a, and b, defined in Figure 8‑5 using the following equation:



where

*R* is the measured resistance;

*RS* is the surface resistivity.

ECSS-E-ST-20-08\_0090619

The surface resistivity shall conform to the requirements specified in the SCD-CVG.



ECSS-E-ST-20-08\_0091044

Figure ‑: Schematic for calculating surface resistivity

### Flatness or bow (FT)

ECSS-E-ST-20-08\_0090620

Flatness or bow shall be measured by measuring the maximum deflection, d (as stated in the SCD-CVG) of the coverglass measured on an optically flat surface in the orientation shown in Figure 8‑6.

ECSS-E-ST-20-08\_0090621

For localized flatness deformations, the maximum displacement of the coverglass from an optically flat surface over a specified distance shall not exceed the values stated in the SCD-CVG.



ECSS-E-ST-20-08\_0091045

Figure ‑: Definition of coverglass flatness

### Transmission into adhesive (TH)

ECSS-E-ST-20-08\_0090622

The transmission into the adhesive shall be measured as in clause 8.7.2, using a fused silica or uncoated coverglass backing piece laminated onto the coverglass component and a matching fluid with a refractive index of 1,41.

ECSS-E-ST-20-08\_0090623

The transmission shall be corrected for reflectance losses at the backing piece-air interface by using Fresnel’s equation as stated in the SCD-CVG.

ECSS-E-ST-20-08\_0090624

The transmission into adhesive values shall be as stated in the SCD-CVG.

### Boiling water test (BW)

ECSS-E-ST-20-08\_0090625

The single-coated coverglass shall be immersed in boiling de-ionized water for a minimum continuous period of:

5 minutes for multi-layer coated coverglasses;

15 minutes in any other case.

### Humidity and temperature

#### HT3 for qualification testing (subgroup O)

##### Purpose

This test is an accelerated shelf-life test to monitor the stability of the coverglass coatings stability in a humid atmosphere.

##### Process

ECSS-E-ST-20-08\_0090626

All coverglasses of subgroup O shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090627

The chamber temperature shall then be increased from ambient temperature to 50 C at a minimum.

ECSS-E-ST-20-08\_0090628

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090629

The duration of the test shall be 10 days.

ECSS-E-ST-20-08\_0090630

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090631

Water condensation on the surface of the coverglasses shall be prevented.

ECSS-E-ST-20-08\_0090632

If there are requirements on specific environmental conditions they shall be stated in the SCD-CVG.

1. For example, requirements on chemical vapours.

#### HT4 for acceptance testing

##### Purpose

This test is to verify the adherence of coatings to the coverglass.

##### Process

ECSS-E-ST-20-08\_0090633

All coverglasses shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090634

The chamber temperature shall then be increased from ambient temperature to 50 C at a minimum.

ECSS-E-ST-20-08\_0090635

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090636

The duration of the test shall be 72 h.

ECSS-E-ST-20-08\_0090637

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090638

Water condensation on the surface of the cells shall be prevented.

ECSS-E-ST-20-08\_0090639

If there are requirements on specific environmental conditions, they shall be stated in the SCD-CVG.

1. For example, requirements on chemical vapours.

### UV exposure (UV)

#### Purpose

This test is an accelerated shelf-life test with the purpose of checking the stability of the coverglass coatings under ultraviolet light exposure.

#### Process

ECSS-E-ST-20-08\_0090640

The integrated intensity of the photons shall be measured with a Sun-blind photo-diode.

ECSS-E-ST-20-08\_0090641

For photons with a wavelength between 200 nm to 400 nm, the integrated intensity at the end of test shall be as follows:

equal to (1000 - 1500) Sun-hours or 1 % of the mission life, whichever is the longer period;

have an UV irradiation acceleration factor of less than 10 S.C. (AM0).

1. For photons with a wavelength between 200 nm to 400 nm, spectral irradiance requirements for UV light sources are specified in ECSS-Q-ST-70-06.

ECSS-E-ST-20-08\_0090642

The test shall be performed in a vacuum (i.e. pressure less than 10-3 Pa).

ECSS-E-ST-20-08\_0090643

The temperature of the coverglass shall be kept below 60 C during the test.

ECSS-E-ST-20-08\_0090644

Control samples shall be included the UV chamber in order to identify potential contaminations occurring during the test.

### Electron irradiation (EI)

#### Purpose

This test is an accelerated shelf-life test with the purpose of checking coverglass coating stability under electron particle irradiation.

1. In order to determine the transmission loss for a specific mission the cover glass and its coating are exposed to a representative total ionizing dose (TID) depth profile simulated by a combination of suitable particles for example electrons and protons.

#### Process

ECSS-E-ST-20-08\_0090645

The coverglasses shall be subjected to 1 MeV electron irradiation.

ECSS-E-ST-20-08\_0090646

If the front surface coating is tested, low electron energies shall be used.

ECSS-E-ST-20-08\_0090647

The flux density and energy shall be uniform over the coverglass area to within ±10 %.

ECSS-E-ST-20-08\_0090648

The nominal rate shall be lower than the value stated in the SCD-CVG.

ECSS-E-ST-20-08\_0090649

Tests shall be performed in vacuum (pressure below 10-3 Pa) or in inert gas atmosphere.

ECSS-E-ST-20-08\_0090650

The irradiation shall be performed at doses representative of LEO and GEO mission environments and at least 2 × Φe, as stated in the SCD-CVG.

### Proton irradiation (PI)

#### Purpose

This test is an accelerated shelf-life test with the purpose of verifying the stability of coverglass and its coatings under proton particle irradiation.

1. In order to determine the transmission loss for a specific mission the cover glass and its coating are exposed to a representative total ionizing dose (TID) depth profile simulated by a combination of suitable particles for example electrons and protons.

#### Process

ECSS-E-ST-20-08\_0090651

The coverglasses shall be subjected to a proton irradiation of high and low energies according to dose and energy values stated in the SCD‑CVG.

ECSS-E-ST-20-08\_0090652

The proton energy shall be uniform over the coverglass area within ±10 %.

ECSS-E-ST-20-08\_0090653

The nominal flux (p+ cm-2 s-1.) shall be uniform within ±10 % and be lower than or equal to the value stated in the SCD-CVG.

ECSS-E-ST-20-08\_0090654

Tests shall be performed in a vacuum (pressure below 10-3 Pa).

### Breaking strength (BS)

ECSS-E-ST-20-08\_0090655

The coverglass breaking strength shall exceed the limits set in the SCD‑CVG.

ECSS-E-ST-20-08\_0090656

The breaking strength test method shall be as stated in the SCD-CVG.

### Thermal cycling (CY)

ECSS-E-ST-20-08\_0090657

The coverglasses shall be exposed to the number of cycles over the range of temperature (both as stated in the SCD-CVG) with a total cycle duration not greater than 10 minutes.

ECSS-E-ST-20-08\_0090658

After exposure, the coverglasses shall show no signs of physical degradation when inspected in conformance with a standard agreed with the customer

1. Example of such a standard is MIL-PRF-13830.

ECSS-E-ST-20-08\_0090659

The coverglasses shall show no degradation in the measured optical performance.

### Abrasion resistance (coated surface) (AE)

ECSS-E-ST-20-08\_0090660

The coverglass shall be subjected to 20 strokes with a 6 mm diameter pencil type eraser conforming to MIL-E-12397B, loaded to 10 N.

ECSS-E-ST-20-08\_0090661

The coverglass shall show no evidence of physical degradation.

### Coating adhesion (TD)

ECSS-E-ST-20-08\_0090662

The coverglass shall be subjected to an adhesion test in conformance with a standard agreed with the customer.

1. An example of such a standard is ECSS-Q-ST-70-13.

ECSS-E-ST-20-08\_0090663

The coating shall show no evidence of delamination.

1. For further guidance, see also MIL-M-13508.

## Failure definition

### Failure criteria

ECSS-E-ST-20-08\_0090664

The following shall constitute failures:

Components that fail during subgroup tests for which the pass-fail criteria are inherent in the test method.

Components failing to conform to the requirements of visual inspection stated in the SCD-CVG.

Deviation between the group B, transmission into air, normal emittance and surface resistivity characterization (BOL) and the identical test after exposure in subgroups V, C and P, that are not within the measurement accuracy of the used characterization equipment.

### Failed components

ECSS-E-ST-20-08\_0090665

A component shall be considered as failed if it exhibits one or more of the failure modes specified in clause 8.8.1.

ECSS-E-ST-20-08\_0090666

Failed components shall be identified as such and included in the delivery.

ECSS-E-ST-20-08\_0090667

Failure analysis of these components shall be performed by the supplier and the results provided to the customer as part of an NRB documentation.

1. For NRB, see ECSS-Q-ST-10-09.

## Data documentation

ECSS-E-ST-20-08\_0090668

The supplier shall provide a data documentation package (DDP) in conformance with Annex G for the qualification approval records and for each component delivery lot.

## Delivery

ECSS-E-ST-20-08\_0090669

All deliverable hardware specified in the order shall be delivered together with documentation in conformance with the requirements specified in clause 8.9.

ECSS-E-ST-20-08\_0090670

One set of documents shall be sent to the customer.

## Packing, dispatching, handling and storage

For packaging, despatching, handling and storage of components see ECSS-Q-ST-20-08.

# Solar cell protection diodes

## Overview

Multi-junction solar cells are protected with shunt diodes for safe performance in solar cell strings applied on solar panels for use in space. These protection diodes can be applied in different configurations:

* A separate external diode shunting the cell junctions
* An integral diode consisting of the same epitaxial design as the bare solar cell and connected to the next solar cell in the string
* An integral diode consisting of dedicated epitaxial design to be connected to the bare solar cell using interconnectors
* An integral diode consisting of dedicated epitaxial design which has been connected to the cell as part of the solar cell production process. This is called a monolithic protection diode

This clause gives guidelines for the specification of external and integral protection diodes, but does not take into account the monolithic protection diodes.

An integral protection diode cannot be considered as a separate entity. All the tests and inspections done on the bare cell with which the diode forms an integral part are also applied to the diode. This chapter deals with the additional aspects of qualification and acceptance of the protection diode.

In this document BSC refers to Bare Solar Cell plus integral protection diode. EPD refers to external protection diode.

In case “SCD-BSC or SCD-EPD” is stated, it refers to the one applicable, i.e. to SCD-BSC in the case of integrated protection diode, or SCD-EPD in the case of external protection diode.

## Testing, deliverable components and marking

### Testing

#### Tests for qualification and procurement

ECSS-E-ST-20-08\_0090671

The qualification test programme for the protection diodes shall comprise both acceptance and qualification testing.

ECSS-E-ST-20-08\_0090672

Testing for the procurement of qualified protection diodes shall comprises acceptance tests and delta qualification tests in conformance with requirement 9.5.2g.

#### Conditions and methods of tests

##### Integral protection diodes (IPD)

ECSS-E-ST-20-08\_0090673

For internal protection diodes, the test conditions and methods for BSC specified in clause 7.1.1.2 shall apply.

##### External protection diodes (EPD)

ECSS-E-ST-20-08\_0090674

The conditions and methods of external protection diode testing shall conform to the external protection diode source control drawing (SCD‑EPD).

1. The external protection diode specification consists of two parts, the generic specification (this Standard) and the SCD-EPD. The SCD-EPD contains the technical specification for a diode type relevant to acceptance testing, as well as for the qualification testing. For the preparation of the SCD-EPD for external protection diodes, refer to Annex E, checklist for SCD-EPD.

ECSS-E-ST-20-08\_0090675

The SCD-EPD shall be prepared by the supplier in conformance with Annex E and provided to the customer for reviewing and agreement.

ECSS-E-ST-20-08\_0090676

Any deviation from the required in-process, acceptance and qualification test s shall be justified..

ECSS-E-ST-20-08\_0090677

Deviations from this Standard applicable to the SCD-EPD shall:

be agreed between the customer and the supplier;

include alternative requirements equivalent to those of this Standard;

not affect the reliability and performances of the EPDs;

only be those specified in requirement 9.2.1.2.2c.

#### Responsibility of supplier for the performance of tests and inspections

ECSS-E-ST-20-08\_0090678

The supplier shall ensure that the tests and inspections specified in clauses 9.4 and 9.5 are performed.

ECSS-E-ST-20-08\_0090679

The tests and inspections specified in clauses 9.4 and 9.5 shall be performed at the manufacturer’s plant or at a facility approved by the customer.

1. For test house requirements, see ECSS-Q-ST-20-07.

### Deliverable components

#### Integral protection diodes

ECSS-E-ST-20-08\_0090680

Delivered integral protection diodes shall be processed and inspected in conformance with the requirements of the process identification document (PID) specified in clause 7.2, and

ECSS-E-ST-20-08\_0090681

Delivered integral protection diodes shall have completed all tests and inspections specified in the SCD-BSC.

#### External protection diodes

ECSS-E-ST-20-08\_0090682

Delivered external protection diodes shall be processed and inspected in conformance with the requirements of the process identification document (PID) specified in clause 9.3, and

ECSS-E-ST-20-08\_0090683

Delivered external protection diodes shall have completed all tests and inspections specified in the SCD-EPD.

### Marking

ECSS-E-ST-20-08\_0090684

All delivered external protection diodes shall be marked in conformance with one of the following approaches, agreed with the customer:

permanently marked with a code to enable traceability of the diodes at the level specified in the SCD-EPD.

marked reduced to delivery batch level.

## Production control (process identification document)

### Integral protection diodes

ECSS-E-ST-20-08\_0090685

For integral protection diodes, requirements in clause 7.2 shall apply.

### External protection diodes

ECSS-E-ST-20-08\_0090686

The process identification document (PID) for the external protection diodes to be qualified shall be prepared by the supplier in conformance with Annex F.

ECSS-E-ST-20-08\_0090687

The supplier shall do the following:

maintain configuration control of all documents;

keep the issues of the documents effective at the date of acceptance by the customer;

provide the PID to the customer for review;

submit to the customer for review and approval any modifications or changes to documents in the PID

## Acceptance tests

### General

ECSS-E-ST-20-08\_0090688

Acceptance tests shall be performed on the following:

components for delivery;

components used for qualification.

### Integral protection diodes

ECSS-E-ST-20-08\_0090689

Acceptance tests for integral protection diodes shall consist of the tests specified in Table 9‑1.

ECSS-E-ST-20-08\_0090690

The humidity, temperature and contact pull tests of Table 7‑1 shall also be performed on the integral protection diodes.

ECSS-E-ST-20-08\_0091046

Table ‑: Acceptance test matrix IPD

|  |  |  |  |
| --- | --- | --- | --- |
| Test | Symbol | Verification method | Sample Size |
| Visual inspection | VI | 9.6.2 | 100 % |
| Dimension | DW | 9.6.3 | 1 % |
| Contact thickness | CT | 9.6.8 | 1 % |
| Surface finish | SF | 9.6.9 | 2 samples per delivery lot |
| Humidity and temperature, and pull | HT/PT | 7.5.7.2 and 7.5.12 | 1 % |
| Diode characterization | DCA | 9.4.5.2 | 100 % |

### External protection diodes

ECSS-E-ST-20-08\_0090691

Acceptance tests for external protection diodes shall consist of the tests specified in Table 9‑2.

ECSS-E-ST-20-08\_0091047

Table ‑: Acceptance test matrix EPD

|  |  |  |  |
| --- | --- | --- | --- |
| Test | Symbol | Verification method | Sample Size |
| Visual inspection | VI | 9.6.2 | 100 % |
| Dimension and weight | DW | 9.6.3 | 1 % |
| Contact Thickness | CT | 9.6.8 | 1 % |
| Surface finish | SF | 9.6.9 | 2 samples per delivery lot |
| Humidity and temperature | HT2 | 9.6.6 | 1 % |
| Pull test | PT | 9.6.11 | 1 % |
| diode characterisation | DCA | 9.4.5.2 | 100 % |

### External and integral diodes

ECSS-E-ST-20-08\_0090692

The generic specification to be used for acceptance tests shall be agreed with the customer.

ECSS-E-ST-20-08\_0090693

The sample size shall be in conformance with Table 9‑1 (for IPD) or Table 9‑2 (for EPD).

ECSS-E-ST-20-08\_0090694

If requirement 9.4.4b is not met, as the sample size shall be stated in SCD‑BSC or SCD-EPD.

ECSS-E-ST-20-08\_0090695

The data documentation of acceptance tests shall be delivered together with the delivered cells/diodes and the qualification test lot.

### Test methods and conditions

#### Production and test schedule

ECSS-E-ST-20-08\_0090696

The test methods and conditions shall conform to 9.6 except of DCA.

#### Diode characterization for acceptance (DCA)

##### Purpose

The purpose of diode characterization tests is to check the electrical performance of the diode.

##### Process

ECSS-E-ST-20-08\_0090697

The forward and reverse I/V characteristic of the diode shall be recorded

in darkness.

with a limiting power supply (to avoid destructive breakdown), and

with temperature control imposed (to avoid thermal runaway),

ECSS-E-ST-20-08\_0090698

Provision 9.4.5.2.2a shall be performed for the following variables, as stated in the SCD-BSC or SCD-EPD:

At one temperature specified.

Up to a forward current, IDIODE–FORWARD., which is as a minimum, equal to 1,1 times the expected string current at solar array level at the corresponding temperature

Up to a reverse voltage, VDIODE–REVERSE. which is as a minimum, equal to 1,33 times the expected solar cell open circuit voltage at the corresponding temperature.

ECSS-E-ST-20-08\_0090699

In case of an integral protection diode the electrical isolation of cell and diode shall be tested by measuring the current when a voltage (as stated in the SCD-BSC) is applied between the front contacts of the protection diode and of the cell at the temperature as stated in the SCD-BSC

##### Pass-fail criteria

ECSS-E-ST-20-08\_0090700

The diode characteristics test shall satisfy the pass-fail criteria stated in the SCD-BSC or SCD-EPD

### Documentation

ECSS-E-ST-20-08\_0090701

Documentation on acceptance tests shall conform to clause 9.8.

## Qualification tests

### General

ECSS-E-ST-20-08\_0090702

Qualification of EPDs and IPDs shall be granted by the customer.

1. Qualification is only valid for the company who applied process and parameters for joining the interconnects to the diode.

ECSS-E-ST-20-08\_0090703

The supplier shall provide details of the outcome of the qualification programme to the customer.

### Integral protection diodes

ECSS-E-ST-20-08\_0090704

The qualification of the diode shall be part of the bare solar cell and SCA qualification for the integral diode concept.

ECSS-E-ST-20-08\_0090705

For the qualification tests of integral protection diodes, Table 6‑1 and Table 7‑2 shall be applied.

ECSS-E-ST-20-08\_0090706

The qualification plan shall consist of the tests specified in Table 9‑3.

ECSS-E-ST-20-08\_0090707

The subgroup A tests applicable for bare solar cells shall be done on the integral protection diodes also.

ECSS-E-ST-20-08\_0090708

The integral protection diodes shall be equipped with front interconnectors as step 7 in Table 7‑2.

ECSS-E-ST-20-08\_0090709

The subgroups F and H tests shall be done on integral protection diodes with interconnects and either with or without coverglass (SCA level) and cell carrier.

ECSS-E-ST-20-08\_0090710

For a procurement lot of previously qualified solar cells with integral diodes, the qualification tests need not be repeated if the following conditions are satisfied:

No changes are made to the design, function or electrical or mechanical parameters of the bare solar cell and integral protection diode.

The same source control drawing is applicable.

No changes are made to the PID.

Delta qualification tests are performed to cover the requirements imposed by the new application.

ECSS-E-ST-20-08\_0090711

The new requirements referred in 9.5.2g.4 shall be included in a new version of the SCD-BSC.

ECSS-E-ST-20-08\_0091048

Table ‑: Qualification test plan for integral protection diode

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| Test | Symbol | Method | Bare diodes (88) | | Assembled diodes |
| V (80) | H (8) | F(20) |
| Welding of interconnectors2) | WI | See Note 2 | 1 | 1 | 3 |
| Visual inspection | VI | 9.6.2 | 2,5 | 2,8 | 1,4,8,11,14 |
| Dimensions | DW | 9.6.3 |  | 3 | 5 |
| Burn-in | BI | 9.6.5 | 4 |  |  |
| Diode characterisation | DC | 9.6.15 | 3,6 | 4,5,7 | 2,6,9,12,15 |
| ESD | DE | 9.6.16 |  | 6 |  |
| Switching | DS | 9.6.17 |  |  | 7,13 |
| Long duration-Life Test | LT | 9.6.18 |  |  | 10 |
| NOTE 1 Objectives of subgroups: Subgroup H: Protection diode ESD test Subgroup V: Burn-in Subgroup F: Protection diode long duration-life test and switching  NOTE 2 Integrate the front interconnector to the integral diode  NOTE 3 Guidelines for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. | | | | | |

### External protection diodes

ECSS-E-ST-20-08\_0090712

The qualification plan shall consist of the tests specified in Table 9‑4 for bare protection diodes (BPD) and in Table 9‑5 for Protection Diode Assemblies (PDA).

ECSS-E-ST-20-08\_0090713

During the qualification, all external protection diodes shall be equipped with n- and p-interconnectors, except for the diodes of subgroup O.

ECSS-E-ST-20-08\_0091146

For a procurement lot of a previously qualified external protection diodes, the qualification tests need not be repeated if the following conditions are satisfied:

No changes are made to the design, function or electrical or mechanical parameters of the external protection diode.

The same source control drawing is applicable.

No changes are made to the PID.

Delta qualification tests are performed to cover the requirements imposed by the new application.

ECSS-E-ST-20-08\_0090715

The new requirements referred in 9.5.3c.4 shall be included in a new version of the SCD-EPD.

ECSS-E-ST-20-08\_0091049

Table ‑: Qualification test plan for bare protection diodes

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Test | | Symbol |  | Method | Bare external protection diodes (144) | | | |
|  | C(24) | O (20) | W (20) | V (80) |
| Welding of Interconnectors | | WI |  | 2) | 1 | 3) | 6 | 1 |
| Visual inspection | | VI |  | 9.6.2 | 2,6,9 | 1,5,8,11 | 1,7,10,13 | 2,5 |
| Dimensions & Weight | | DW |  | 9.6.3 |  | 2 | 2 |  |
| Diode Characterisation | | DC |  | 9.6.15 | 3,7,10 | 3,6,9 | 5,8,11 | 3,6 |
| Thermal Cycling | | CY |  | 9.6.4 |  | 7 |  |  |
| Burn in | | BI |  | 9.6.5 |  |  |  | 4 |
| Humidity & Temperature 1 | | HT1 |  | 9.6.6 |  | 4 |  |  |
| Contact uniformity | | CU |  | 9.6.7 |  |  | 3 |  |
| Surface Finish | | SF |  | 9.6.9 |  |  | 4 |  |
| Contact adherence | | CA |  | 9.6.10 |  | 10 |  |  |
| Pull | | PT |  | 9.6.11 |  |  | 12 |  |
| Electron Irradiation | | EI |  | 9.6.12 | 5 |  |  |  |
| Temperature annealing | | TA |  | 9.6.13 | 8 |  |  |  |
| Temperature behaviour | | TB |  | 9.6.14 | 4,11 |  |  |  |
| ESD | | DE |  | 9.6.16 |  |  | 9 |  |
|  | NOTE 1 Objective of subgroups Subgroup C: Electron irradiation Subgroup O: Extended storage simulation Subgroup W: Weldability and ESD Subgroup V: Protection diode burn-in  NOTE 2 Integrate the front and rear interconnectors to the diode.  NOTE 3 Use a pressure contact for this group.  NOTE 4 Guidelines for relaxation of qualification tests due to similarity with earlier performed qualification are described in the handbook ECSS-E-HB-20-08. | | | | | | | |

ECSS-E-ST-20-08\_0091147

Table 9‑5: Qualification test plan for protection diode assemblies

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| Test | Symbol | Method | Bare external protection diodes (60) | | |
| A(20) | E (20) | F (20) |
| Welding of Interconnectors | WI |  | 32) | 33) | 33) |
| Visual inspection | VI | 9.6.2 | 1,4,7,10 | 1,4,7,10 | 1,4,8,11,14 |
| Dimensions & Weight | DW | 9.6.3 |  |  | 5 |
| Diode Characterisation | DC | 9.6.15 | 2,5,8 | 2,5,8 | 2,6,9,12,15 |
| Thermal Cycling | CY | 9.6.4 | 6 | 6 |  |
| Pull | PT | 9.6.11 | 9 | 9 |  |
| Switching | DS | 9.6.17 |  |  | 7,13 |
| Long Duration – Life Test | LT | 9.6.18 |  |  | 10 |
| NOTE 1 Objective of subgroups Subgroup A: Cathode contact interconnector adherence Subgroup E: Anode contact interconnector adherence Subgroup F: Protection diode Long Duration - Life Test and switching  NOTE 2 Integrate the cathode interconnector to the diode. Bond diode coverglass, before cathode contact interconnector welding, in case required.  NOTE 3 Integrate the cathode and anode contact interconnectors to the diode. Bond diode coverglass, before cathode and/or anode contact interconnector welding, in case required. | | | | | |

### Integral and external protection diodes

#### Production and test schedule

ECSS-E-ST-20-08\_0090716

Before starting production of the qualification lot, the manufacturer shall compile a production test schedule showing by date and duration the production and test activities, including all major processing operations and key stages in the production and testing.

ECSS-E-ST-20-08\_0090717

A production flow chart, process schedules and inspection procedures shall be provided.

#### Qualification test samples

ECSS-E-ST-20-08\_0090718

The diodes for qualification testing shall conform to the PID.

ECSS-E-ST-20-08\_0090719

The test samples shall be chosen statistically and at random from a minimum number of diodes, stated in the SCD-BSC or SCD-EPD, and from the first n batches, where n is also stated in the SCD-BSC or SCD‑EPD.

1. For sampling see ISO 2859.

ECSS-E-ST-20-08\_0090720

Facilities shall be available to safely store the qualification lot including failed samples for a minimum of 6 years (equivalent to five years in storage and one year in orbit).

#### Qualification testing

ECSS-E-ST-20-08\_0090721

The total quantity of test samples shall be a minimum in conformance with Table 9‑3 (for IPD) or Table 9‑4 and Table 9‑5 (for EPD).

1. The number of samples per subgroup can be increased, but all samples have to follow the complete test sequence. The only aim is to allow for possible losses of qualification samples e.g. mishandling while maintaining the minimum required number.

ECSS-E-ST-20-08\_0090722

The qualification tests shall be divided into subgroups of tests, and the samples assigned to a subgroup subjected to the tests in that subgroup in the sequence specified.

ECSS-E-ST-20-08\_0090723

A failure in any subgroup shall constitute a failure in the qualification.

1. For a definition of failure see 9.7.

## Test methods, conditions and measurements

### General

ECSS-E-ST-20-08\_0090724

The level of allowable spikes to the diode shall be agreed between the customer and supplier and included in the SCD-BSC or SCD-EPD.

ECSS-E-ST-20-08\_0090725

The test system shall be checked on compliance with 9.6.1a by using an oscilloscope and dummy cell before performing the following electrical test on diodes, 9.6.5, 9.6.14, 9.6.15, 9.6.16, 9.6.17 and 9.6.18.

1. The test methods, conditions and measurement requirements for the tests in Table 9‑3 and Table 9‑4 are detailed in clauses 9.6.2 to 9.6.18. For failure criteria, see clause 9.7.

### Visual inspection (VI)

#### Applicability

The requirements on visually observable defects specified in this clause apply to granting qualification approval to a high quality protection diode.

#### Test process

ECSS-E-ST-20-08\_0090726

Protection diodes shall be inspected by one of the following methods:

with an equipment with a resolution which is 5 times higher than the minimum allowed defect size for defects on protection diodes and contacts, or

An optical inspections method agreed with the customer.

#### Deviations

ECSS-E-ST-20-08\_0090727

Any deviation from the visual inspection requirements on defects (clauses 9.6.2.4 and 9.6.2.5) shall:

not affect performance or reliability,

be agreed with the customer, and

be justified.

#### Protection diode defects

ECSS-E-ST-20-08\_0090728

Cracks and fingerprints shall not be present.

ECSS-E-ST-20-08\_0091063

The mesa-groove area shall be free of residuals from the etching process.

#### External protection diode contact area defects

##### General

ECSS-E-ST-20-08\_0090729

The protection diode contact area shall be free of digs, scratches, and probe prints, unless metallization is still present.

ECSS-E-ST-20-08\_0090730

Peeling, blistering and delamination of contacts shall not be present.

ECSS-E-ST-20-08\_0090731

Digs or depressions deeper than 0,025 mm shall not be present.

##### N-side and P-side contact area

ECSS-E-ST-20-08\_0090732

The maximum dimension of voids or bubbles shall be 0,25 mm in diameter.

ECSS-E-ST-20-08\_0090733

The maximum dimension of drops and spatter shall be 0,25 mm in diameter and 0,05 mm in height.

### Dimensions and weight (DW)

ECSS-E-ST-20-08\_0090734

The overall lateral dimensions of the protection diode (including thickness of the EPD), contact dimensions and interconnector position shall conform to the requirements stated in the SCD-BSC or SCD-EPD.

ECSS-E-ST-20-08\_0090735

The weight of the external protection diode shall

be verified by determination of the average weight per qualification lot or weight per contacts vacuum evaporation batch (sample base) and

conform to the requirements specified in the SCD-EPD.

ECSS-E-ST-20-08\_0090736

The weight of the integral protection diode shall be considered as part of the bare solar cell weight

### Thermal cycling (CY)

#### Purpose

The purpose of this test is to assess the reliability of test samples under a thermal stress equivalent to the number of eclipses that occur during one year in orbit for LEO missions, 1000 thermal cycles for GEO missions or the complete lifetime cycling for interplanetary or other mission types.

#### Process

ECSS-E-ST-20-08\_0090737

For external protection diodes the number of cycles and the extreme temperatures shall be those as stated in the SCD-EPD.

ECSS-E-ST-20-08\_0090738

Thermal cycling of internal protection diodes shall be part of the BSC thermal cycling testing.

ECSS-E-ST-20-08\_0091148

Additional cycles, to the ones specified in requirement 9.6.4.2a, shall be added to cover mission phases with low occurrence but very extreme temperatures additional cycles and agreed with the customer.

### Burn in (BI)

#### Purpose

This test is operational load test to screen for infant mortality within the qualification batch.

#### Process

ECSS-E-ST-20-08\_0090739

Each qualification sample shall be submitted to a burn-in process under ambient pressure conditions.

ECSS-E-ST-20-08\_0090740

The diode temperature shall be TJ = TBS °C as indicated in the SCD-BSC or SCD-EPD.

ECSS-E-ST-20-08\_0090741

During the process the samples shall be under load.

ECSS-E-ST-20-08\_0090742

The process shall consist of the following phases:

Phase 1: 200 h reverse biased with VREV = -1,5 x Voc in which Voc is the open circuit voltage of the project relevant solar cell at the minimum mission temperature specified in the solar array specification.

Phase 2: 16 h forward biased with IFW = 1,1 Isc, in which Isc is the maximum solar cell short circuit current of the project relevant solar cell during the mission.

### Humidity and temperature

#### HT1 for qualification testing (subgroup O)

##### Purpose

This test is an accelerated shelf life test to monitor the stability of functioning, contacts and coatings in a humid atmosphere.

##### Process

ECSS-E-ST-20-08\_0090743

All protection diodes in subgroup O shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0090744

The chamber temperature shall then be increased to 60 C minimum.

ECSS-E-ST-20-08\_0090745

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0090746

The duration of the test shall be 30 days.

ECSS-E-ST-20-08\_0090747

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0090748

Water condensation on the surface of the protection diodes shall be prevented.

ECSS-E-ST-20-08\_0090749

If there are requirements on specific environmental conditions, they shall be stated in the SCD-EPD.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

#### HT2 for acceptance testing

##### Purpose

This test is to verify the adherence of the contacts of the protection diodes, if available.

##### Process

ECSS-E-ST-20-08\_0091149

All protection diodes shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0091150

The chamber temperature shall then be increased to 95 °C minimum.

ECSS-E-ST-20-08\_0091151

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0091152

The duration of the test shall be 24 h.

ECSS-E-ST-20-08\_0091153

High-purity water in accordance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0091154

Water condensation on the surface of the protection diodes shall be prevented.

ECSS-E-ST-20-08\_0091155

If there are requirements on specific environmental conditions, such as chemical vapours, they shall be stated in the SCD-BSC.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

### Contact uniformity (CU)

#### Purpose

The diode contact uniformity test verifies the uniformity of the thickness of the diode contacts during qualification.

The test applicable to integral protection diodes is similar to the test described in clause 7.5.9.

#### Process

ECSS-E-ST-20-08\_0090750

The uniformity of the thickness of the metal contact in the interconnector weld area shall be checked with a with a step-height profiler for instance a betascope, or a similar instrument.

#### Pass Fail Criteria

ECSS-E-ST-20-08\_0090751

The uniformity of the contact thickness of the metal layers of the cell contact shall conform to the requirements of the interconnection process (as stated in the SCD-EPD) and the procurement specification of the supplier.

### Contact thickness (CT)

#### Purpose

The diode contact thickness test verifies the thickness of the diode contact during acceptance test.

The test applicable to integral protection diodes is similar to the test described in clause 7.5.10.

#### Process

ECSS-E-ST-20-08\_0090752

The thickness of the diode metal contact in the interconnector weld area or on dedicated in­process test samples shall be checked (either with a step-height profiler for instance a betascope or similar instrument).

#### Pass Fail Criteria

ECSS-E-ST-20-08\_0090753

The thickness of the metal layers of the diode contacts shall conform to the requirements of the interconnection process (as stated in the SCD-EPD), and the certified procurement specification of the supplier.

### Surface Finish (SF)

#### Purpose

The diode surface finish test verifies the surface finish of the diode contacts.

The test applicable to integral protection diodes is similar to the test described in clause 7.5.11.

#### Process

ECSS-E-ST-20-08\_0090754

The surface finish in the interconnector weld area shall be checked with a micro surface-roughness tester.

#### Pass Fail Criteria

ECSS-E-ST-20-08\_0090755

The surface finish of the metal layers of the diode contact shall conform to the requirements of the interconnection process (as stated in the SCD-EPD), and the certified procurement specification of the supplier.

### Contact adherence (CA)

#### Purpose

This test is performed to verify the durability of the contacts of the external protection diodes.

The test applicable to internal protection diodes is similar to the test described in clause 7.5.8.

#### Process

ECSS-E-ST-20-08\_0090756

All diodes shall be subjected to a coating adherence test on both full sample faces.

ECSS-E-ST-20-08\_0090757

Test method shall be established according to a standard which is mutually agreed with the customer.

1. Example of such standards are MIL-M-13508, ISO 9211-4 or ECSS-Q-ST-70-13.

ECSS-E-ST-20-08\_0090758

The adhesive tape used for this test shall be clear in colour with an adhesive strength on steel of at least 0,28 N/mm.

1. Example of a standard that can be used to measure the strength is EN 1939.

ECSS-E-ST-20-08\_0090759

The adhesion of the used tape shall be within a tolerance of + 10 %.

ECSS-E-ST-20-08\_0090760

Any visible delamination of parts of the contacts shall not exceed the limits specified in clause 9.6.2.5.

### Pull test (PT)

#### Purpose

The objective of the pull test is to check the bond strength of the positive and negative contacts under mechanical and environmental stress.

#### Process

ECSS-E-ST-20-08\_0090761

A gradually increasing pull force shall be applied to the interconnector separately for each interconnector tab at a pull speed as stated in the SCD-BSC or SCD-EPD.

ECSS-E-ST-20-08\_0090762

The ultimate pull strength of each tab shall be as stated in the SCD-BSC or SCD-EPD, considering the number of pulled tabs and their widths.

ECSS-E-ST-20-08\_0090763

The pull direction that either can be 0°, 45° or 90° shall be as stated in the SCD-BSC or SCD-EPD.

ECSS-E-ST-20-08\_0091156

The type of failure shall be recorded in the data documentation package (DDP) as specified in clause 9.8.

### Electron irradiation (EI)

#### Purpose

This test is an accelerated life test to check the protection diode performance degradation under electron particle irradiation. The test described hereafter is only applied on the external protection diodes. Integral protection diodes are irradiated as part of the bare solar cell irradiation test, clause 7.5.13.

#### Process

ECSS-E-ST-20-08\_0090764

The external protection diodes shall be subjected to 1 MeV electron irradiation.

1. ISO 23038 outlines a methodology to perform this test.

ECSS-E-ST-20-08\_0090765

The flux density and energy shall be uniform over the cell area within ±10 %.

ECSS-E-ST-20-08\_0090766

During irradiation, the test samples shall be protected from oxidation, using either vacuum (below 10-3 Pa) or a dry atmosphere of nitrogen or argon at a temperature of (20 ± 10) C.

ECSS-E-ST-20-08\_0090767

The nominal rate shall be lower than 5 × 1011 e- cm-2 s-1.

ECSS-E-ST-20-08\_0090768

The irradiation facility, dosimetry included, shall be approved by the customer.

ECSS-E-ST-20-08\_0090769

The irradiation shall be performed as follows:

State the expected dose for the envisaged application (included transfer orbit dose), Φe, in the SCD-EPD.

Divide Subgroup C (in conformance with Table 9‑4) in three batches of 8 samples.

Irradiate the batches specified in 2. as follows:

the first batch at Φe/2;

the second batch, at Φe.

the third batch, at 2 × Φe.

ECSS-E-ST-20-08\_0090770

After electron irradiation and temperature annealing, the requirements as stated in the SCD-EPD for the diode characteristics shall be satisfied.

### Temperature annealing (TA)

#### Purpose

This test is to verify the stability of protection diode performance under temperature. The test described hereafter is only applied on the external protection diodes. Integral protection diodes are tested as part of the bare solar cell photon irradiation and temperature annealing test, clause 7.5.15.

#### Process

ECSS-E-ST-20-08\_0090771

The protection diodes shall be temperature annealed for 24 h at 60 C

ECSS-E-ST-20-08\_0090772

After the test, the samples shall be kept at temperatures below 50 C until the diode characterization test is performed.

### Temperature behaviour (TB)

#### Purpose

The purpose of this test is to assess the corresponding electrical parameters of the protection diodes as a function of temperature over the entire temperature range of the application and to provide data for the design of the solar generator.

#### Process

ECSS-E-ST-20-08\_0090773

Temperature behaviour of all samples in subgroup C shall be measured.

ECSS-E-ST-20-08\_0090774

The diode characterization described in clause 9.6.15 shall be measured, as a minimum,

at three temperatures: TJ = 25 °C, 80 °C and 150 °C.

For mission specific qualification, at three protection diode temperatures: the two temperature extremes t1 and t2 and the operational temperature.

* t1 = highest operation diode temperature (without margins) predicted for the mission + 25 C
* t2 = lowest operation diode temperature (without margins predicted for the mission.

### Diode characterization (DC)

#### Purpose

The purpose of diode characterization tests is to monitor the performance before, for example, environmental tests, and to subsequently check for performance degradation after these tests. In addition the test is to provide data for array level design.

#### Process

ECSS-E-ST-20-08\_0090775

The test under illumination shall be performed at 1 S.C. (AM0).

ECSS-E-ST-20-08\_0090776

The forward and reverse I/V characteristic of the diode shall be recorded:

in darkness

under illumination, unless it is demonstrated that the protection diode has a negligible photovoltaic response.

with a limiting power supply (to avoid destructive breakdown), and

with temperature control imposed (to avoid thermal runaway),

ECSS-E-ST-20-08\_0090777

Provision 9.6.15.2b shall be performed for the following variables, as stated in the SCD-BSC or SCD-EPD:

At different temperatures (including maximum and minimum operating temperature with margins and sustained operation in forward bias).

For different times.

Up to a forward current, IDIODE–FORWARD., which is as a minimum, equal to 1,1 times the expected string current at solar array level at the maximum mission temperature specified in the solar array specification.

Up to a reverse voltage, VDIODE–REVERSE. which is as a minimum, equal to n times the expected solar cell open circuit voltage at the minimum mission temperature specified in the solar array specification, being

n =1,33 for acceptance testing and

n=1,5 for qualification testing

1. 1 It is good practice not to exceed the physical limits of the device, as stated in the SCD-BSC or SCD-EPD, when applying the margins for acceptance and qualification testing.
2. 2 In case a reverse current out of specification is measured, it is good practice to make a thermographic picture or emission microscopy of the respective by-pass diode.

ECSS-E-ST-20-08\_0090778

The increase of temperature in forward mode at maximum operating temperature shall be assessed in order to avoid overheating of the diode.

ECSS-E-ST-20-08\_0090779

In case of an integral protection diode the electrical isolation of cell and diode shall be tested by measuring the current when a voltage (as stated in the SCD-BSC) is applied between the front contacts of the protection diode and of the cell at the temperatures as stated in the SCD-BSC.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0090780

The diode characteristics test shall satisfy the pass-fail criteria stated in the SCD-BSC or SCD-EPD.

### Human body ESD (DE)

#### Purpose

The purpose of this test is to determine the robustness of the protection diode against human body electrostatic discharges.

#### Process

ECSS-E-ST-20-08\_0090781

The protection diodes shall be equipped with interconnects.

ECSS-E-ST-20-08\_0090782

The diodes shall be in flight like configuration which means connected to the adjacent cell.

ECSS-E-ST-20-08\_0090783

The test shall be performed in conformance with IEC 60749‑26:2006.

ECSS-E-ST-20-08\_0090784

The voltage level shall be 12 kV for single and multi-pulse testing.

ECSS-E-ST-20-08\_0090785

Solar cell performance shall be verified in between tests.

ECSS-E-ST-20-08\_0090786

Diode characterization shall be performed at the end of the sequence of pulses, after disconnection of the diode from the cell.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0090787

The cell electrical characteristics shall satisfy the pass-fail criteria stated in the SCD-BSC.

ECSS-E-ST-20-08\_0090788

The diode electrical characteristics test shall satisfy the pass-fail criteria stated in the SCD-BSC or SCD-EPD.

### Switching test (DS)

#### Purpose

The purpose of this test is to determine the robustness of the protection diode against the transients which it can be subjected to during the ground life and in-orbit. Transients can result from three different categories of events

* ground handling and testing:
* mating and demating
* repair activities
* solar array performance measurements (flasher and interface compatibility with light conversion tests)
* electrical health checks (continuity, insulation, by-pass diode function)
* in-orbit electrostatic discharges, in particular primary discharges
* Switching mode transients due to power subsystem commutations

#### Process

ECSS-E-ST-20-08\_0090789

The protection diodes shall be equipped with interconnects.

ECSS-E-ST-20-08\_0090790

The number of switching cycles per category shall be at least 100.

ECSS-E-ST-20-08\_0090791

One switching cycle shall be defined as a vice-versa cycle between the reverse bias and forward bias points as defined in the Figure 9‑1.

ECSS-E-ST-20-08\_0090792

The applied signal for the switching cycles shall be in conformance with the Figure 9‑2.

ECSS-E-ST-20-08\_0090793

The three different categories as defined in clause 9.6.17 shall be represented by two different parameter settings (VREV , IFW , T1 , T2 and T3) for the applied signal defining two different modes, of which only one of the modes is tested if it envelopes the other mode.

ECSS-E-ST-20-08\_0090794

The test parameters for the two different modes shall be defined as follows:

switching level 1 ( to cover ground testing and bus commutations)

For IFW, IREV, T1, T2 and T3:

* The following default values, if they cover the transient of the switching regulator:   
  VREV=1,5 × Voc (where Voc is the open circuit voltage of the solar cell connected in parallel to a protection diode as per minimum mission temperature specified in the solar array specification, in accordance with SCD­BSC or SCD­EPD)   
  IFW  = 1,1 × Isc (where Isc is the short circuit current of the solar cell connected in parallel to a protection diode as per maximum mission temperature specified in the solar array specification, in accordance with SCD­BSC or SCD­EPD) T1 = 1 s T2 = 50 s. T3 = Recommended value of 1s.
* The values stated in the SCD-BSC or SCD-EPD, otherwise.

For the temperature, the most extreme between the following values:

* The values stated in the SCD-BSC or SCD-EPD.
* The highest and minimum operational temperatures with the margins predicted for the mission.

switching level 2 (to cover primary discharges):

For IFW, IREV, T1, T2 and T3, the values stated in the SCD-BSC or SCD-EPD.

For the temperature, the most extreme between the following values:

* The values stated in the SCD-BSC or SCD-EPD.
* The highest and minimum operational temperatures with the margins predicted for the mission.

1. to item 2(a): Typical test conditions defined for specific LEO mission (solar array size dependent) are VREV  = ‑5,3 V, IFW = 4,5 A, T1 = 50 s, T2 = 180 s and T3 > 1 s.



ECSS-E-ST-20-08\_0091050

Figure ‑: Diode forward and reverse test profile

Diagram

Description automatically generated

1. 1: Switching time from VREV to IFWD in less than T1.
2. 2: IFWD applied for a minimum of T2.
3. 3: No specific requirement to the slope between forward mode and reverse bias, but recommended same order of magnitude of T1.
4. 4: VRE applied for a minimum of T3.

ECSS-E-ST-20-08\_0091051

Figure ‑: Diode switching test profile

#### Pass-fail criteria

ECSS-E-ST-20-08\_0090795

The diode characteristics test shall satisfy the pass-fail criteria stated in the SCD-BSC or SCD-EPD.

### Long Duration – Life test (LT)

#### Purpose

The purpose of this test is to determine the stability of the protection diodes under worst case operation for long duration.

#### Process

ECSS-E-ST-20-08\_0090796

The protection diodes shall be equipped with interconnects

ECSS-E-ST-20-08\_0090797

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ECSS-E-ST-20-08\_0090798

The duration of the long duration-life test shall be in conformance with the duration of the mission.

ECSS-E-ST-20-08\_0090799

The long duration test shall be performed at the temperature minimum of the following two values:

The maximum allowable temperature of the diode, to be specified in the SCD-EPD.

The temperature corresponding to the acceleration factor applied, calculated as follows:

Determine the activation energy Ea corresponding to a predefined level of degradation.

Extrapolate the test temperature by using the expression:

τ (T) ~ A exp (Ea/kBT)

Where:

τ (T) = time to reach a predefined level of degradation at temperature T,

A = constant

Ea = activation energy corresponding to a predefined level of degradation,

KB = Boltzman constant

1. to item 2(a): The activation energy can be determined experimentally by measuring τ at various temperatures above the aimed temperature or by comparison with literature data of similar degradation processes.

ECSS-E-ST-20-08\_0090800

The test duration and parameter settings for each individual diode shall be as in Table 9‑5 and mission requirements.

ECSS-E-ST-20-08\_0091052

Table ‑: Diode long duration-life test parameters

| Test | Duration | Parameter | Requirements |
| --- | --- | --- | --- |
| Reverse Bias  (first step) | >200 h(a) | VREV | IREV ≤ TBD(b) mA |
| Forward Bias | 6 h(a) | IFW | VFW @ IFW < TBD(c) V |
| … |  |  |  |
| Reverse Bias  (Last step) | >200 h(a)  0-100 % of step duration | VREV | IREV ≤ TBD(b) mA (e.g. Ge-mode) |
| >200 h(a)  80-100 % of step duration | Stability during step:  (IREV max-IREV min) ≤ (0,1x(IREV max+IREV min)/2) |
| Reverse Bias  (Additional step) (d) | 200 h(a)  0-100 % of step duration | VREV | IREV ≤ TBD(b) mA (e.g. Ge-mode) |
| 200 h(a)  80-100 % of step duration | Stability during step:  (IREV max-IREV min) ≤ (0,1x(IREV max+IREV min)/2) |
| Note: IREV, VREV, IFW, IREV max and IREV min are recorded values of the diode electrical parameters during Long Duration-Life Test.  (a) The total number of reverse bias and forward bias test steps is determined in the SCD-BSC or SCD-EPD.  (b) Maximum allowed IREV: To be determined by the supplier and specified in the SCD-BSC or SCD-IPD  (c) Maximum allowed VFW: To be determined by the supplier and specified in the SCD-BSC or SCD-IPD  (d) Additional step to be performed at the mission operational temperature (e.g. 80°C for GEO or 110°C for standard LEO), in case the requirements of the last step are not met. | | | |

#### Pass-fail criteria

ECSS-E-ST-20-08\_0090801

The diode characteristics test shall satisfy the pass-fail criteria stated in the SCD-BSC or SCD-EPD related to IREV,VFW at IFW.

## Failure definition

### Failure criteria

ECSS-E-ST-20-08\_0090802

The following shall constitute failures:

Components that fail during subgroup tests for which the pass-fail criteria are inherent in the test method.

Components failing to conform to the requirements of visual inspection stated in the SCD-BSC or SCD-EPD.

Components whose marking fails to conform to the requirements of clause 9.2.3.

Components that, when subjected to diode characteristics measurements after acceptance tests in conformance with the SCD-BSC or SCD-EPD, fail to meet one or more of the specified limits, measurement accuracy included.

### Failed components

ECSS-E-ST-20-08\_0090803

A component shall be considered to have failed if it exhibits one or more of the failure modes specified in clause 9.7.1.

ECSS-E-ST-20-08\_0090804

Failed components shall be identified as such and included in the delivery.

ECSS-E-ST-20-08\_0090805

Failure analysis of these components shall be performed by the supplier and the results provided to the customer as part of the NRB documentation.

1. For NRB, see ECSS-Q-ST-10-09.

## Data documentation

ECSS-E-ST-20-08\_0090806

The supplier shall provide a data documentation package (DDP) in conformance with Annex G for the qualification approval records and for each component delivery lot.

## Delivery

ECSS-E-ST-20-08\_0090807

All deliverable hardware specified in the order shall be delivered together with documentation in conformance with the requirements specified in clause 9.8.

ECSS-E-ST-20-08\_0090808

One set of documents shall be sent to the customer.

## Packing, despatching, handling and storage

### Overview

For packaging, despatching, handling and storage of components see ECSS-Q-ST-20-08.

### ESD sensitivity

ECSS-E-ST-20-08\_0090809

If a protection diode is sensitive to ESD according to clause 5.2 of ESCC 23800 Issue 1 then it shall be handled and stored according to ESCC 24900 Issue 2, clause 10.

# Solar simulators and calibration procedures

## Solar simulators

### Spectral distribution

#### AM0 spectrum

ECSS-E-ST-20-08\_0090810

The AM0 reference solar spectral irradiance distribution shall be in conformance with [Gueymard, C., 2018].

1. 1 This spectrum is, corresponding to an irradiance of 1361,1 W/m2 (solar constant) at AM0, on a plane surface under normal incidence.
2. 2 The spectrum data along with related uncertainties per each wavelength can be obtained electronically from a link attached to [Gueymard, C., 2018].

#### Total Irradiance of the Solar simulator

ECSS-E-ST-20-08\_0090811

Total Irradiance (solar constant AM0-equivalent) of the Sun simulator on the test plane shall be determined by the use of AM0 calibrated reference cells as indicated in clause 10.2.

#### Spectral distribution of the Solar simulator

ECSS-E-ST-20-08\_0090812

The spectral match of a simulator shall be defined by the deviation from AM0 reference spectral irradiance as provided in [Gueymard, C., 2018].

ECSS-E-ST-20-08\_0090813

For simulator evaluation purposes in terms of spectral match, the wavelength range is defined from 0,30 µm to 1,9 µm, and for the wavelength intervals of interest of equal photon flux, the percentage of total irradiance should be taken from Table 10‑2.

1. The classification of a Solar simulator in terms of spectral match is not mandatory. In addition, it is generally recognized that a classification does not allow for a prediction of measurement uncertainties.

ECSS-E-ST-20-08\_0091053

Table ‑: <<deleted>>



















ECSS-E-ST-20-08\_0091054

Table ‑: Classes of single and multi-source solar simulators (informative)

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| Wavelength Interval [nm] | Total Irradiance between indicated wavelength intervals  [W/m²] | Percent of Total Irradiance for between indicated Total Range of AM0 spectrum (300nm – 1900nm) within various wavelength intervals | Class A+ | Class A | Class B | Class C |
| 300 - 1900 | 1249,93 | 100% |
| 300 - 507 | 296,32 | 23,7% | ±15 % | ±25 % | ±40 % | -60% to +100 % |
| 507 - 629 | 220,61 | 17,6% |
| 629 - 755 | 181,91 | 14,6% |
| 755 - 898 | 152,07 | 12,2% |
| 898 - 1067 | 128,18 | 10,3% |
| 1067 - 1273 | 107,21 | 8,6% |
| 1273 - 1532 | 89,81 | 7,2% |
| 1532 - 1900 | 73,82 | 5,9% |

ECSS-E-ST-20-08\_0090814

The following method shall be used to verify spectral match of the solar simulator irradiance:

The spectral distribution of irradiance shall be measured with a calibrated spectroradiometer.

Calculate the deviation of the total energy per spectral region with reference to the AM0 spectrum using the following expression:



where

*E(*λ*)SIM* is the spectral irradiance of the solar simulator;

*E(*λ*)AM*0 is the AM0 spectral irradiance;

*Range* is the spectral region of interest.

ECSS-E-ST-20-08\_0090815

For a given test lot of solar cells, the spectral distribution of the solar simulator in the test plane shall be adjusted to AM0 equivalent conditions according to 10.2.6.1 such that errors introduced due to the typical spread in spectral response of the relevant lot of cells is 1 % or less, as follows:

Measure the spectral response of a representative subset of the test lot, at least 1 cell per current grade .

Calculate the spectral mismatch factor (SMM) using the spectral distribution of the solar simulator adjusted to AM0 equivalent conditions, the AM0 spectrum, as per clause 10.1.1.1, and the spectral responses of the cells that were measured in step 1 and the spectral response(s) of the secondary working standard(s).

If the deviation of each SMMs found under step 2 from the SMM average is 1 % or less, the requirement is fulfilled.

ECSS-E-ST-20-08\_0090816

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### Irradiance uniformity

ECSS-E-ST-20-08\_0090817

The uniformity of the irradiance, as specified in requirement 10.1.2e, in the test plane over the full extent of the nominated test area, should meet one of the classes of solar simulators in Table 10‑3.

ECSS-E-ST-20-08\_0090818

In case multijunction solar cells are to be characterised, the relevant class of solar simulator in Table 10‑3 should be determined for each junction.

1. Ideally, the spectral response of the irradiance detector(s) matches the spectral responsivity of each junction; this can be accomplished by using multiple detectors with different spectral responsivities (e.g. component cells), by using a single detector with optical filters to modify its spectral response, or by a combination of both methods. This becomes particularly important when single-source simulators with different filters are used where spectrally dependent non-uniformities cannot be measured separately as it is typically possible when multi-source simulators are used.

ECSS-E-ST-20-08\_0090819

For testing bare solar cells and SCAs, the largest dimension of the detector shall be less than half of the smallest dimensions of the cell or SCA to be tested or the reference devices using for adjusting the solar simulator, with a minimum dimension of 1 cm side length for a rectangular detector, or a minimum area of 1cm² for circular detector.

ECSS-E-ST-20-08\_0090820

In the case of coupons, the detector shall not be bigger than the SCAs bonded to it.

ECSS-E-ST-20-08\_0090821

The nonconformity in the uniformity of the irradiance shall be calculated as follows:

Nonconformity (%) = 100 x (MI − mI)/(MI + mI)

Where:

* MI = Maximum irradiance,
* mI = Minimum irradiance,

With the maximum and minimum irradiance measured with the detectors over the nominated test area (corrected for temporal instability).

ECSS-E-ST-20-08\_0091055

Table ‑: Classes of solar simulators with respect to   
nonconformity of irradiance uniformity (informative)



|  |  |  |  |  |
| --- | --- | --- | --- | --- |
| Class | Class A + | **Class A** | Class B | Class C |
| Nonconformity (%) | ± 1 | ± 2 | ± 5 | ± 10 |

ECSS-E-ST-20-08\_0090822

The irradiance uniformity of the solar simulator in the test plane shall not introduce errors due to the positioning accuracy of the relevant cells higher than 1 % or other value proposed by the supplier and accepted by the customer.

ECSS-E-ST-20-08\_0090823

The irradiance uniformity of the solar simulator in the test area shall not introduce errors due to the dimension of the reference cell used to adjust Sun simulator irradiance to AM0 equivalent conditions higher than 1 % or other value proposed by the supplier and accepted by the customer.

1. See clause 10.2 for requirements of reference solar cells.

### Irradiance stability

ECSS-E-ST-20-08\_0090824

For the regular time interval of data acquisition of a particular test the irradiance, shall be stable to the degree specified for one of the corresponding class of solar simulator in Table 10‑4.

1. See requirement 10.2.6.1c for solar simulator verification.

ECSS-E-ST-20-08\_0090825

In case multijunction solar cells are to be characterised, the relevant class of solar simulator in Table 10‑4 shall be determined for each junction.

ECSS-E-ST-20-08\_0090826

The temporal instability, the time to measure a complete IV curve, shall be calculated with the following expression:

Temporal instability (%) = 100 x (MI − mI) / (MI + mI)

Where :

* MI = Maximum irradiance,
* mI = minimum irradiance

with the maximum and minimum irradiance measured with the detector at any particular point of the nominated test area plane during the time of data acquisition.

ECSS-E-ST-20-08\_0091056

Table ‑: Classes of solar simulators with respect to   
temporal instability of irradiance



|  |  |  |  |  |
| --- | --- | --- | --- | --- |
| Class | Class A + | **Class A** | Class B | Class C |
| Nonconformity (%) | ± 1 | ± 2 | ± 5 | ± 10 |

ECSS-E-ST-20-08\_0090827

The irradiance stability of the Sun simulator in the test plane shall be capable to guarantee reproducibility and, thus, not introduce errors on measured solar cell electrical parameters (Isc, Voc, and Pmax) higher than 1 % or other value proposed by the supplier and accepted by the customer.

## Standard cell and Solar simulator calibration

### Primary standards

ECSS-E-ST-20-08\_0090828

Single junction or component primary standard cells, calibrated using a method defined in ISO 15387, shall be used for setting light sources to standard illumination conditions.

ECSS-E-ST-20-08\_0090829

The number and type of primary standard cells shall be mutually agreed upon between the supplier and the customer.

### Secondary working standards (SWS)

#### Selection of secondary working standards

ECSS-E-ST-20-08\_0090830

For single junctions*,* 10 solar cells representing a spectral response range similar when compared in conformance with requirement 10.2.2.1d to that of the cells to be tested, shall be calibrated for their AM0 equivalent short-circuit current using a Solar simulator, conforming to clause 10.1, using the accepted primary standards

ECSS-E-ST-20-08\_0090831

For multi-junctions, three sets of component solar cells representing a spectral response range similar when compared in conformance with requirement 10.2.2.1d to the cells to be tested, shall be calibrated for their AM0 equivalent short-circuit current using a multi-source solar simulator, conforming to clause 10.1, using the accepted primary standards.

ECSS-E-ST-20-08\_0090832

Cells shall be matched in its size to the cells under test.

ECSS-E-ST-20-08\_0090833

The comparison method shall be agreed with the customer.

#### <<deleted>>

ECSS-E-ST-20-08\_0090834

<<deleted>>

ECSS-E-ST-20-08\_0090835

<<deleted>>

#### Secondary working standards performance requirements

##### Visual inspection requirements.

ECSS-E-ST-20-08\_0090836

SWS shall meet visual inspection requirements on defects (clauses 7.5.1.4 and 7.5.1.5 for bare solar cells, or clause 6.4.3.1 for SCA’s).

ECSS-E-ST-20-08\_0090837

Any deviation from the visual inspection requirements on defects shall:

not affect performance or reliability,

be agreed with the customer, and

be justified.

##### Stability of the sensitivity

ECSS-E-ST-20-08\_0090838

The stability of the sensitivity of the SWS under operating conditions shall be verified by comparing the short-circuit current of five of the SWS before and after a photon-irradiation test with the short-circuit current of the remaining five SWS which are kept in the dark.

ECSS-E-ST-20-08\_0090839

If the average short-circuit current of the photon-irradiated cells deviates by more than 1 % from the original values, a new set of SWS shall be selected from a different production process established to yield stable cells.

ECSS-E-ST-20-08\_0090840

The spectral response range of these cells shall be verified by spectral response measurements and the subsequent calculation of mismatch errors between the SWS and production cells, in conformance with requirement 10.2.2.3.2d.

ECSS-E-ST-20-08\_0090841

The maximum error shall not be higher than 1 %.

##### Linearity

ECSS-E-ST-20-08\_0090842

For linearity measurements methods, IEC 60904-10 shall be applied.

ECSS-E-ST-20-08\_0090843

Current and Voltage Linearity Test with respect to irradiance and temperature range of interest shall be verified:

The variation of the slope of short circuit to irradiance remains constant within 2 %.

The variation of the slope of open circuit voltage to the logarithm of irradiance [ln (G)] remains constant within 5 %.

The variation of the slope of short-circuit current and open circuit voltage to cell temperature remains constant within 10 %.

##### Use of SWS with pulse solar simulator

ECSS-E-ST-20-08\_0090844

For their use with pulsed simulators, it shall be verified by using a memory oscilloscope, that SWSs have a response in short-circuit mode capable to generate the AM0 equivalent short-circuit current.

##### Verification of SWS

ECSS-E-ST-20-08\_0090845

Correlation measurements between the SWS in daily use and a primary standard shall be made at intervals mutually agreed upon between the supplier and the customer.

### Standards cells documentation

ECSS-E-ST-20-08\_0090846

The following data shall be reported when using a standard cell:

Cell description (identification, type, size),

Calibration data with uncertainty budget,

calibration type,

calibration laboratory,

calibration light source class spectrum,

If primary standard and SWS have a different size, stability and uniformity,

Normalized spectral response curve, indicating type of normalization,

Temperature Coefficients and calibration date.

### Maintenance of standards

ECSS-E-ST-20-08\_0090847

All standard solar cells (primary and SWS) shall be kept at temperatures below 50 C during operation and storage.

ECSS-E-ST-20-08\_0090848

The standard cells shall be kept in the dark during storage periods of more than one month.

### Recalibration and intercomparison

ECSS-E-ST-20-08\_0090849

Periodically recalibration and intercomparison shall be made in a period agreed with the customer.

ECSS-E-ST-20-08\_0090850

Those cells that do not meet the stability requirements (> 1 % change per year in short circuit current) shall be discarded as reference cells.

### Solar simulator calibration and maintenance

#### Solar simulator calibration

ECSS-E-ST-20-08\_0090851

The irradiance in the test plane shall be adjusted to the AM0 equivalent intensity by means of an SWS for single junction solar cells with a deviation from the calibrated short-circuit current of the SWS, including the applicable spectral mismatch factor in accordance with IEC 60904-7, not be higher than 1 %.

ECSS-E-ST-20-08\_0090852

For multi-junction solar cells, the irradiance in the test plane shall be adjusted to AM0 equivalent conditions for each component cell with a maximum allowable deviation of 1 % in the calibrated short-circuit current of each SWS component cell, including the applicable spectral mismatch factor in accordance with IEC 60904-7.

ECSS-E-ST-20-08\_0090853

The simulator intensity shall be verified with the aid of the SWS at regular intervals.

ECSS-E-ST-20-08\_0090854

The length of the intervals specified in requirement 10.2.6.1c shall be:

such as to guarantee an intensity drift of less than 1 % between two subsequent SWS measurements;

specified by the manufacturer in the product assurance plan.

#### Solar simulator maintenance

ECSS-E-ST-20-08\_0090855

The procedure for maintenance, according to the technology of the solar simulator, shall be used to verify its performance in conformance with clause 10.1.

# Capacitance measurement methods

## Single junction solar cell capacitance measurement

### Overview

#### General

This method is intended to be used for the measurement of capacitance of bare solar cells and solar cell assemblies, and as an outline for qualification coupons (see requirements 5.5.3.5.2a and 6.4.3.16.2a).

#### Description

This clause describes a method of measuring the dynamic properties of a single junction solar cell, using the small signal method. This consists of measurement of the cell impedance in darkness for several bias voltages.

The measurement is performed between 0 V and the bias voltage corresponding to a current of 200 mA. The frequencies are between 10 Hz and 10 MHz.

These measurements enable the cell capacitance for each bias voltage to be estimated and, subsequently, to build a model of the capacitance according to the cell voltage and current.

The following parameters and values are used

* The minimum number of frequencies is Nf = 26 with logarithmic steps
* The minimum number of voltage biases is Np= 6
* V1= 0 V
* V2= V3 / 2
* V3= bias voltage corresponding to a current of 1 mA
* V4= bias voltage corresponding to a current of 10 mA
* V5= bias voltage corresponding to a current of 100 mA
* V6= bias voltage corresponding to a current of 200 mA

### Signal measurement method

ECSS-E-ST-20-08\_0091083

The signal measurement method that should be used is the shunt method.

### Measurement procedure

#### Preparation of the measurement equipment

ECSS-E-ST-20-08\_0091084

The test bay should be prepared according to Figure 11‑1 and the following equipment list:

One DC power supply.

Two precision voltmeters.

One 4-points ohmmeter (or one of the 2 voltmeters if they are multi-meters).

One network analyser.

The measuring head containing one non-inductive shunt (1 Ω) and connections for BNC cables and the voltmeters, with the following:

The hot terminal of the shunt to the voltmeters connected to the voltmeters via an air coil inductance higher than 45 μH.

A resonance frequency higher than 10 MHz and damped by a 270 Ω resistor in parallel.

The coil made with a 10 mm diameter Teflon mandrel of roughly 125 jointed turns of a 2/10 mm wire.

The injection elements with the following properties:

Direct current: 200 Ω resistor, power 10 W, stable with regard to the temperature.

Alternating current: electrochemical capacitance of 1 000 μF and four common mode cores T22 FT40.

One 50 Ω cable for injection passing through the 4 common mode cores.

A ground braid between the analyser ground and the measuring head.

Two 50 Ω cables of same length for measurement.

Two twisted unshielded cables for voltmeter connection with a maximum length of 1,50 m.

One male BNC adapter.

1. To item 5(b): This device is used to suppress the influence of the harness and the parasitic capacitances of the voltmeters on the shunt in the measuring bandwidth.



ECSS-E-ST-20-08\_0091085

Figure ‑: Solar cell impedance measurement equipment

ECSS-E-ST-20-08\_0091086

The parameters of the network analyser should be adjusted using the network analyser in the *B/A* mode (*B/A*= (Vcell+Vshunt)/Vshunt), ensuring that the channels are not inverted, as follows:

frequency range: 10 Hz to 10 MHz;

number of frequencies Nf : at least 26;

step type: logarithmic;

bandwidth: automatic or otherwise limited to few Hz in order to limit the noise at low frequency;

injection level: default value of the network analyser;

program the network analyser to record the *B/A* values in the complex form *X*+j ×*Y*; or in the amplitude |*B/A*| and phase ϕ (*B/A*).

#### Process for calibration of the test equipment

ECSS-E-ST-20-08\_0091087

The balancing of the channels at low frequency, and the influence of the parasitic inductance between the two measuring points, A and B, once before the measurements should be verified by replacing the solar cell with a short-circuit according to Figure 11‑2.

ECSS-E-ST-20-08\_0091089

The *B/A* ratio between 10 Hz and 10 MHz should be ensured to conform to the following provisions:

At low frequency: equal to (1 ± 2) % (or equal to (0 ± 2) dB).

At 10 MHz: lower than 1,6 (or 4 dB).

1. It is considered that the shunt has no inductance; this means that the inductance of the short-circuit is lower than 20 nH. A ratio lower than 1 (or < 0 dB) means that the A and B channels are inverted.



ECSS-E-ST-20-08\_0091088

Figure ‑: Channel balancing and reduction of the parasitic inductances

ECSS-E-ST-20-08\_0091090

The ohmic value of the shunt associated with the cabling and the network analyser should be measured at room temperature using one of the following two methods:

Calculation: to be used if the certified calibrated value of the shunt, of the cable and of the 50 Ω input are known.

In this case:

Rshunt measured = 

Direct measurement: measure Rshunt measured with the cell short-circuited, the channel A plugged on the network analyser, all the other cables unplugged (Figure 11‑3), and a 4-wire setting, as follows:

unplug the injection cable (RF channel);

unplug the Vcell measuring cable and keep it insulated;

unplug the cable on channel B of the network analyser and plug it into the input “input” of the ohmmeter with a BNC adaptor, paying attention to the polarities;

unplug the measuring cable Vshunt and plug it in the input “sense” of the ohmmeter, paying attention to the polarities;

monitor the calculated or measured value.



Figure ‑: Measurement of the resistance value of the shunt in the measuring conditions (shunt in parallel with the input of the network analyser)

ECSS-E-ST-20-08\_00911158

The injection level of the network analyser shall be adjusted as follows:

Connect the cell in place of the short-circuit and keep the voltage supply at 0 V.

Begin at 0 dB and lower the signal with 3 dB steps until there is no change at low frequency (variation lower than 0,1 dB).

Monitor the selected injection level.

1. 1 to item 1: The injection level is selected low enough so as not to generate a variation of the impedance curves when the level changes.
2. 2 to item 1:

#### Measurement of the cell with the network analyser

ECSS-E-ST-20-08\_0091091

The cell should be measured with the network analyser as follows:

If the measurement is performed at several temperatures in a thermostatic chamber:

Wait for thermal equilibrium.

Determine the resistance value of the shunt at each temperature (requirement ).

Determine and record the voltage of the power supply to obtain the bias voltages defined in clause 11.1.1.2 and set the power supply to 0 V at the end.

Measure the *B/A* ratios for the chosen bias voltages, as follows. For each bias voltage:

Adjust the power supply voltage to the determined value.

Note the cell and the shunt voltages.

Measure the *B/A* ratios in the complex form *X*+j × *Y*; or in the amplitude |*B/A*| and phase ϕ (*B/A*) from 10 Hz to 10 MHz, and store the data file in the network analyser.

Note or record the cell voltage change (to detect a temperature increase of the cell).

Set the power supply voltage to 0 V.

Record the stored data file.

### Measurement analysis

#### Correction of the measurement with respect to the actual impedance of the shunt (impedance values from the *B/A* measurements)

ECSS-E-ST-20-08\_0091092

For a 1 Ω shunt, the value given by the analyser is the impedance of the cell in series with the 1 Ω resistor, where the cell impedance should be determined using the following calculation:

If *B/A* is given in amplitude |*B/A*| and phase ϕ (*B/A*), the cell impedance is:

Zcell = Rshunt measured × 

If *B/A* is given in the complex form *X*+j × *Y*

Zcell = Rshunt measured × [ 1 +X2 + Y2 – 2X]1/2

#### Modelling

##### Calculation of the items of the equivalent network using the impedance values

ECSS-E-ST-20-08\_0091093

The small signal electrical model parameters (Figure 11‑4) should be calculated for each bias voltage Vcell,i and bias current Icell,i with respect to the frequency, as follows:



Minimize the relative error of the theoretical impedance *Ztheo*(*Ls,Rs,Cp,Rp,*ƒ) with the measured values (regression by least square method).

Calculate each parameter *Rp, Cp, Ls* and *Rs* by successive iterative optimization, one after the other, using the following initial parameters:

*Rp*0 = *Z*(*f*MIN),

*Cp*0 = 1/ (2 × π × *fMIN* *Z*(*fMIN*)),

*Ls*0 = *Z*(*fMAX*) /(2 × π × *fMAX*),

*Rs*0 = minimum value of *Z*(*f*).

1. As the **Nf** impedance measurements



are associated to the frequencies



the function to minimize is



which is a function of *Ls, Rs, Cp* and *Rp*.



Figure ‑: Small signal electrical schema biased with a DC voltage associated impedance

##### Determination of the capacitance model

ECSS-E-ST-20-08\_0091094

From the capacitance measurements at several bias voltages, the following parameters of the model of capacitance should be determined with respect to the cell junction voltage and temperatures:

*C*0 (capacitance at 0 V),

*C*1 (diffusion parameter), and

Φ (voltage barrier at measurement temperature),

ECSS-E-ST-20-08\_0091095

Provision 11.1.4.2.2a should be determined as follows:

Use the capacitance model based on the following expression:



where

* 
* *T* = measurement temperature
* *k* = 1,38 × 10-23 J/K
* *q* = 1,602 × 10-19 C

Minimize the relative error between the theoretical capacitance *C*(*C*0, Φ, *C*1, *v*) and the previously calculated capacitances (regression by least square method).

1. 1 to item 1: For measurement in darkness and low currents, the cell voltage Vi and the junction voltage vi are the same (the error is 4 mV for a bias current of 200 mA and a cell serial resistance of 20 mΩ).
2. 2 to item 2: As the **Np** impedance measurements



are associated to the voltages



the function to minimize is

,

which is the function of C0, Φ and C1.

ECSS-E-ST-20-08\_0091159

Each parameter *C*0, *C*1 and Φ shall be calculated by successive iterative optimization one after the other, where the initial parameters are as follows:

*C*0 = *C*(*V*1)



Φ - 1, 5 VNp

### Measurement of the capacitance of a multi-junction cell

The cell capacitance measurement method cannot be directly applied to multi-junction solar cells because it assumes that the photo-currents of each junction of the cell were perfectly matched.

For real cells, this matching is not realized and the voltage profile through the different junctions of the cell is different when the cell is illuminated and when it is in darkness. The measurement in darkness enables the order of magnitude of the capacitance to be evaluated.

In order to obtain a higher precision, these measurements are added to measurements under illumination with the right spectral irradiance.

1. 1 Some measurements have been performed and the capacitance has been observed to be higher than the values measured in darkness, even at low bias voltage. This is under experimentation and currently there is not a lot of information available.
2. 2 This is the fundamental difference between single junction and multi-junction cells: measurements done in darkness are sufficient to characterize the dynamic behaviour of single junction cells in darkness and under illumination.
3. 3 Measurements done in darkness are not sufficient to characterize the dynamic behaviour of multi-junction cells under illumination.

## Time domain capacitance measurement

### Overview

#### General

This method is intended to be used for the measurement of the capacitance of SCAs and qualification coupons that are part of power subsystems that use sequential switching shunt regulators.

#### Description

This clause describes a method for measuring the dynamic properties of a solar cell or qualification coupon, using the time domain method while operating in the current region (to the left of the maximum power point on the curve).

The capacitance of the solar cell or qualification coupon, when switching between two different voltage operational points with the assumptions that

* the capacitance is constant between the two points, and
* the current is constant in the two points,

is obtained with the expression:

,

where

* *I* is the measured current at the two points;
* Δ*t* is the time increment;
* Δ*V* is the voltage increment.

The measurements are performed at 1 S.C (AM0) illumination and at constant temperature.

The capacitance that is derived from the short-circuit current point and the operational voltage of the solar cell or qualification coupon is used to derive the requirements for the design of sequential switching shunt regulators specified in ECSS-E-ST-20.

### Measurement procedure

#### Measurement equipment set-up

ECSS-E-ST-20-08\_0091096

The time domain capacitance measurement test set-up, should comprise the following test equipment:

A continuous or pulsed solar simulator according to the requirements specified in clause 10.

A solar array capacity tester which supplies a synchronizable fast switch to perform a controlled short-circuit release at the open circuit condition of the qualification coupon or SCA under test.

A digital-analogue oscilloscope to capture the voltage-current transient during the short-circuit release at the open circuit condition.

A twisted harness of short length to reduce the parasitic inductance of the harness from the test specimen to the capacity tester.

ECSS-E-ST-20-08\_0091097

The voltage should be measured at the test specimen terminals.

ECSS-E-ST-20-08\_0091098

For qualification coupons with multiple strings, each particular string voltage should be measured not including the string blocking diode (see requirement 5.5.1.3.3f).

ECSS-E-ST-20-08\_0091099

External parallel capacitors to derive the capacitance of the qualification coupon or SCA should not be used because this parameter depends on the rate of change of the transient.

#### Calibration of the measurement equipment

ECSS-E-ST-20-08\_0091100

The continuous or pulsed solar simulator should be calibrated according to the requirements specified in clause 10.2.

#### Performance measurement

ECSS-E-ST-20-08\_0091101

The short-circuit release at the open circuit condition of the SCA or qualification coupon should be performed under the illumination conditions specified in clause 11.2.2.2 and at constant temperature.

ECSS-E-ST-20-08\_0091102

The voltage curve vs time and the current curve vs time of the test specimen should be recorded during the release.

#### Data processing

ECSS-E-ST-20-08\_0091103

Since the voltage of the test specimen at the moment of the short-circuit release is difficult to measure (due to the high frequency oscillations created by the parasitic harness inductance), one of the following two methods should be used to determine the voltage:

mathematical analysis to find a curve without oscillation that fits the voltage curve measured;

calculation of the intersection of two voltage curves.

1. Example of two voltage curves that can be used for this purpose are the first voltage curve at the test specimen terminals and the second voltage curve at the capacity tester terminal (+) and test specimen terminal (-).

ECSS-E-ST-20-08\_0091104

The voltage determined in requirement 11.2.2.4a should be used to calculate the capacitance according to the expression and conditions specified in clause 11.2.1.2.

# Planar Blocking Diodes

## Overview

Strings of multi-junction solar cells are protected by so-called blocking diodes at the end of each string in a solar array, to prevent reverse currents. In opposite to solar cell protection diodes, blocking diodes are constantly biased in forward direction under normal conditions. Only in case the string is not working as a current generator, the blocking diode is reverse biased, to protect the solar string.

Blocking diodes, intended for the use in solar arrays, can be of several different designs. In the following clause the testing of blocking diodes manufactured as bare dies, as well as connector integrated diode (CIBD) are covered. Packaged diodes, which are also very common for use in solar panels, are covered by ESCC 5000. However, if a blocking diode is used in form of a bare diode, their integration into a photovoltaic string is very similar to this one of solar cell protection diodes. On the other hand, power and thermal requirements on blocking diodes strongly differ from these ones. Therefore, for the final test definition, the standard ESCC 5000 is used as guideline with corresponding adaptions due to the bare design of the blocking diode.

This clause 12 specifies requirements for the qualification of bare and connector integrated blocking diodes and outlines commonly used test methods and conditions.

For recovery time requirements refer to ECSS-E-ST-20-06.

## Testing, deliverable components and Marking

### Testing

#### Tests for qualification and procurement

ECSS-E-ST-20-08\_0091160

The qualification test programme for the blocking diodes shall comprise both acceptance and qualification testing.

ECSS-E-ST-20-08\_0091161

Testing for the procurement of qualified blocking diodes shall comprises acceptance tests and delta qualification tests in conformance with requirement 12.5.2b.

#### Conditions and methods of tests

ECSS-E-ST-20-08\_0091162

The conditions and methods of planar blocking diode testing shall conform to the source control drawing (SCD-PBD) detailed in Annex H.

1. The planar blocking diode specification consists of two parts, the generic specification (this Standard) and the SCD-PBD. The SCD-PBD contains the technical specification for a diode type relevant to acceptance testing, as well as for the qualification testing. For the preparation of the SCD-PBD for planar blocking diodes, refer to Annex H, checklist for SCD-PBD.

ECSS-E-ST-20-08\_0091163

The SCD-PBD shall be prepared by the supplier in conformance with Annex H and provided to the customer for reviewing and agreement.

ECSS-E-ST-20-08\_0091164

Any deviation from the required in-process, acceptance and qualification test shall be justified.

ECSS-E-ST-20-08\_0091165

Deviations from this Standard applicable to the SCD-PBD shall:

be agreed between the customer and the supplier;

include alternative requirements equivalent to those of this Standard;

not affect the reliability and performances of the PBD;

only be those specified in requirement 12.2.1.2c.

#### Responsibility of supplier for the performance of tests and inspections

ECSS-E-ST-20-08\_0091166

The supplier shall ensure that the tests and inspections specified in clauses 12.4 and 12.5 are performed.

ECSS-E-ST-20-08\_0091167

The tests and inspections specified in clauses 12.4 and 12.5 shall be performed at the manufacturer’s plant or at a facility approved by the customer.

1. For test house requirements, see ECSS-Q-ST-20-07.

### Deliverable components

ECSS-E-ST-20-08\_0091168

Delivered planar blocking diodes shall be processed and inspected in conformance with the requirements of the process identification document (PID) specified in clause 12.3.

ECSS-E-ST-20-08\_0091169

Delivered planar protection diodes shall have completed all tests and inspections specified in the SCD-PBD.

### Marking

ECSS-E-ST-20-08\_0091170

All delivered planar blocking diodes shall be marked in conformance with one of the following approaches, agreed with the customer:

permanently marked with a code to enable traceability of the diodes at the level specified in the SCD-PBD,

marked reduced to delivery batch level.

## Production control (process identification document)

ECSS-E-ST-20-08\_0091171

The process identification document (PID) for the blocking diodes to be qualified shall be prepared as specified in Annex F by the supplier and provided to the customer for review.

## Acceptance test

### General

ECSS-E-ST-20-08\_0091172

Acceptance tests shall be performed on components for delivery, as well as components used for qualification.

### Planar blocking diodes

ECSS-E-ST-20-08\_0091173

The acceptance tests shall consist of the tests specified in Table 12‑1.

ECSS-E-ST-20-08\_0091174

The generic specification to be used for acceptance tests shall be agreed with the customer.

ECSS-E-ST-20-08\_0091175

The quantity of samples for testing shall be in conformance with the percentages and pieces given in Table 12‑1.

ECSS-E-ST-20-08\_0091176

The test documentation of the acceptance tests shall be delivered together with the delivered diodes and the qualification test lot.

ECSS-E-ST-20-08\_0091177

Table 12‑1: Acceptance test matrix planar blocking diodes

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| Test | Symbol | Method | Sample Size | | |
| Bare Diode | CIBD |
| Visual inspection | VI | 12.6.1 | 100% | 100% |
| Dimensions Check | D | 12.6.2 | 1% (min. 5 pcs./batch(1)) | 1% |
| Weight | W | 12.6.2 | 1% (min. 5 pcs./batch(1))) | 1% |
| Diode characterization | DC | 12.6.3 | 100% | 100 % |
| Humidity and Temperature | HT2 | 12.6.4.2 | 1% (min. 5 pcs./batch(1))) | 1% |
| High Temperature Reverse Bias Burn-In | HTRB-BI | 12.6.7.3 | - | 100 % |
| Contact Adherence | CA | 12.6.6 | 1% (min. 5 pcs./batch(1))) | Use bare diode data |
| Contact uniformity | CU | 12.6.13 | 2 pcs. / batch(1)) | Use bare diode data |
| Surface Finish | SF | 12.6.14 | 2 pcs. / batch(1)) | Use bare diode data |
| Pull test | PT | 12.6.16 | 1% (min. 5 pcs./batch(1))) | 1% |
| NOTE 1 A batch is a defined set of wafer that are processed and tested together as a unit. | | | | | | |

## Qualification tests

### General

ECSS-E-ST-20-08\_0091178

Qualification of PBDs shall be granted by the customer.

1. Qualification is only valid for the company who applied process and parameters for joining the interconnects to the diode.

ECSS-E-ST-20-08\_0091179

The supplier shall provide details of the outcome of the qualification programme to the customer.

### Blocking diodes

ECSS-E-ST-20-08\_0091180

The qualification plan shall consist of the tests specified in Table 12‑2.

ECSS-E-ST-20-08\_0091181

For a procurement lot of previously qualified blocking diode, the qualification tests need not be repeated if the following conditions are satisfied:

No changes are made to the design, function or electrical or mechanical parameters of the blocking diode.

The same source control drawing is applicable.

No changes are made to the PID.

The same manufacturer.

Delta qualification tests are performed to cover the requirements imposed by the new application.

### Production and test schedule

ECSS-E-ST-20-08\_0091182

Before starting production of the qualification lot, the manufacturer shall compile a production test schedule showing by date and duration the production and test activities, including all major processing operations and key stages in the production and testing.

ECSS-E-ST-20-08\_0091183

A production flow chart, process schedules and inspection procedures shall be provided.

### Qualification test samples

ECSS-E-ST-20-08\_0091184

The blocking diodes for qualification testing shall conform to the PID.

ECSS-E-ST-20-08\_0091185

The test samples shall be chosen statistically and at random from a minimum number of diodes, stated in the SCD-PBD.

1. For sampling see ISO 2859.

ECSS-E-ST-20-08\_0091186

Facilities shall be available to safely store the qualification lot including failed samples for a minimum of 6 years.

1. This is equivalent to five years in storage and one year in orbit.

### Qualification testing

ECSS-E-ST-20-08\_0091187

The total quantity of test samples shall be a minimum in conformance with Table 12‑2 and Table 12‑3.

ECSS-E-ST-20-08\_0091188

The qualification tests shall be divided into subgroups of tests, and the samples assigned to a subgroup subjected to the tests in that subgroup in the sequence specified.

ECSS-E-ST-20-08\_0091189

If the full qualification is executed on the higher assembly level (CIBD), the test reports of the executed qualification tests, that are covering the bare diode subgroups A and V as well, shall be made available to third parties.

ECSS-E-ST-20-08\_0091190

Table 12‑2: Qualification test plan for bare blocking diodes

| Test | Symbol | Method | Bare blocking diodes (84) | | | |
| --- | --- | --- | --- | --- | --- | --- |
| **O (20)** | **V (20)** | **C (24)** | **A (20)** |
| Visual inspection | VI | 12.6.1 | 1, 6, 9,12 | 1, 6, 14 | 1, 7, 12, 17, 20 | 1, 8, 15 |
| Dimensions Check | D | 12.6.2 | 2 | 2 | 2 | 2 |
| Weight | W | 12.6.2 | 3 | 3 | 3 | 3 |
| Diode characterization | DC | 12.6.3 | 4, 7, 10 | 4, 7, 9, 11, 13 | 4, 6, 14, 16 | 4, 9, 11, 13 |
| Humidity and Temperature | HT1 | 12.6.4.1 | 5 |  |  |  |
| Temperature Cycling | CY | 12.6.5 | 8 |  |  |  |
| Contact Adherence | CA | 12.6.6 | 11 |  |  |  |
| Welding of Interconnectors | WI | - |  | 5 | 5 | 7 |
| Power Burn-in | FWD-BI | 12.6.7.2 |  | 8 | 8 |  |
| High Temperature Reverse Bias Burn-in | REV-BI | 12.6.7.3 |  | 10 | 9 |  |
| Long Duration-Life Test | LT | 12.6.8 |  | 12 |  |  |
| Temperature behaviour | TB | 12.6.9 |  |  | 10, 18 |  |
| Temperature robustness | TR | 12.6.10 |  |  | 11, 19 |  |
| Total Dose Radiation Testing | RT | 12.6.11 |  |  | 13 |  |
| Temperature Annealing | TA | 12.6.12 |  |  | 15 |  |
| Contact uniformity | CU | 12.6.13 |  |  |  | 5 |
| Surface Finish | SF | 12.6.14 |  |  |  | 6 |
| Human Body ESD | ESD | 12.6.15 |  |  |  | 12 |
| Pull test | PT | 12.6.16 |  |  |  | 14 |
| Surge-Test | ST | 12.6.17 |  |  |  | 10 |
| NOTE Objective of subgroups  Subgroup O: Extended storage simulation  Subgroup V:Long duration life test endurance  Subgroup C: Radiation Testing  Subgroup A: Contact adherence and ESD | | | | | | | |

ECSS-E-ST-20-08\_0091191

Table 12‑3: Qualification test plan for connector integrated blocking diodes

| Test | Symbol | Method | CIBD (64) | | | Bare blocking diodes (40) | |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **O (20)** | **V (20)** | **C (24)** | **A (20)** | **E (20)** |
| Visual inspection | VI | 12.6.1 | 1, 7 | 1 | 1, 13 | 1, 8, 15, 18 | 1, 8, 14, 18 |
| Dimensions Check | D | 12.6.2 | 2 | 2 | 2 | 2 | 2 |
| Weight | W | 12.6.2 | 3 | 3 | 3 | 3 | 3 |
| Diode characterization | DC | 12.6.3 | 4, 6 | 4, 6, 8 | 4, 8, 10 | 4, 9, 11, 13, 16 | 4, 9, 12, 15 |
| Humidity & Temperature incl. biasing | HT1 | 12.6.4.1 | 5 |  |  |  |  |
| Temperature Cycling | CY | 12.6.5 |  |  |  | 14 | 13 |
| Front Interconnect Welding | FIW | - | (\*) | (\*) | (\*) | 7 | 5 |
| Rear Interconnect Welding | RIW | - | (\*) | (\*) | (\*) |  | 6 |
| Cover glass Bonding | CB | - | (\*) | (\*) | (\*) |  | 7 |
| Power Burn-in | FWD-BI | 12.6.7.2 |  | 5 |  |  |  |
| High Temperature Reverse Bias Burn-in | REV-BI | 12.6.7.3 |  | 7 |  |  |  |
| Long Duration-Life Test | LT | 12.6.8 |  | 9 |  |  |  |
| Temperature behaviour | TB | 12.6.9 |  |  | 5, 11 |  |  |
| Temperature robustness | TR | 12.6.10 |  |  | 6, 12 |  |  |
| Total Dose Radiation Testing | RT | 12.6.11 |  |  | 7 |  |  |
| Temperature Annealing | TA | 12.6.12 |  |  | 9 |  |  |
| Contact uniformity | CU | 12.6.13 |  |  |  | 5 |  |
| Surface Finish | SF | 12.6.14 |  |  |  | 6 |  |
| Human Body ESD | ESD | 12.6.15 |  |  |  | 12 |  |
| Interconnector Adherence | IA | 12.6.16 |  |  |  | 17 | 17 |
| Surge-Test | ST | 12.6.17 |  |  |  | 10 | 11 |
| Thermo-Optical Properties | TO | 12.6.18 |  |  |  |  | 10, 16 |
| NOTE 1 Objective of subgroups  Subgroup O: Extended storage simulation  Subgroup V: Long duration life test endurance  Subgroup C: Radiation testing  Subgroup A: Cathode contact interconnector adherence  Subgroup E: Anode contact interconnector adherence  NOTE 2 (\*) To be completed prior to the qualification. | | | | | | | |

## Test methods, conditions and measurements

### Visual inspection (VI)

#### Process

ECSS-E-ST-20-08\_0091192

Blocking diodes shall be inspected by one of the following methods:

The used equipment has a resolution which is 5 times higher than the minimum allowed defect size.

Alternatively, an agreed optical inspection method with the customer.

#### Deviations

ECSS-E-ST-20-08\_0091193

Any deviation from the visual inspection requirements on defects specified in clause 12.6.1.3 shall:

not affect performance or reliability,

be agreed with the customer, and

be justified.

#### Defects

ECSS-E-ST-20-08\_0091194

Material, construction and dimensions shall be in accordance with the SCD-PBD.

ECSS-E-ST-20-08\_0091195

Surface shall be free from foreign particles, fingerprints and contamination.

ECSS-E-ST-20-08\_0091196

The blocking diode contact area shall be free of digs, scratches and probe prints, unless metallization is still present.

ECSS-E-ST-20-08\_0091197

Peeling, blistering and delamination of contacts shall not be present.

ECSS-E-ST-20-08\_0091198

There shall be no evidence of corrosion, peeling of finish or plating or of holes and cracks.

ECSS-E-ST-20-08\_0091199

Surfaces shall not show any unusual colouring changes unless explained in the relevant Process Identification Document.

ECSS-E-ST-20-08\_0091200

The mesa-groove area shall be free of residuals from the etching process.

### Dimensions and weight (DW)

ECSS-E-ST-20-08\_0091201

The overall lateral dimensions of the blocking diode, including thickness, contact dimensions and interconnector position shall conform to the requirements stated in the SCD-PBD.

ECSS-E-ST-20-08\_0091202

The weight of the planar blocking diode shall:

be verified by determination of the average weight per qualification lot or weight per evaporation batch, and

conform to the requirements specified in the SCD-PBD.

### Diode characterization (DC)

#### Purpose

At each of the relevant points during qualification and between tests, electrical measurements are performed to monitor the performance degradation during the test sequence.

#### Process

ECSS-E-ST-20-08\_0091203

The diode characterization shall be performed as follows:

Forward and reverse I/V characteristic of the diode are recorded.

For room temperature diode characterization, the forward current IFwd and a reverse voltage Vrev are specified in the SCD-PBD.

In darkness.

with a limiting power supply, to avoid destructive breakdown, and

with temperature control imposed, to avoid thermal runaway.

ECSS-E-ST-20-08\_0091204

The diode characterization test specified in 12.6.3.2a shall be performed for the following variables, as stated in the SCD-PBD:

At ambient temperature.

For the specified times in forward and reverse bias.

Up to a forward current, Ifw, which is as a minimum, equal to 1,33 times the expected string current at solar array level.

Up to a reverse voltage, Vrev, which is as a minimum, equal to 1,33 times the expected solar cell open circuit voltage, however being Vrev x 1,33 always smaller than 80 % of the Breakdown Voltage at that temperature.

The increase of temperature in forward mode at maximum operating temperature is assessed in order to avoid overheating of the diode.

#### Pass/fail criteria

ECSS-E-ST-20-08\_0091205

The blocking diodes shall satisfy the pass-fail criteria stated in the relevant SCD-PBD.

### Humidity and Temperature

#### HT1 for qualification testing (subgroup O)

##### Purpose

This test is an accelerated shelf life test to monitor the stability of functioning, contacts and coatings in a humid atmosphere.

##### Process

ECSS-E-ST-20-08\_0091206

The diodes shall be placed in a sealed test chamber at ambient pressure.

ECSS-E-ST-20-08\_0091207

The temperature shall be increased up to 60 °C minimum.

ECSS-E-ST-20-08\_0091208

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0091209

The duration of the test shall be 30 days.

ECSS-E-ST-20-08\_0091210

High-purity water in conformance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0091211

Water condensation on the surface of the planar blocking diodes shall be prevented.

ECSS-E-ST-20-08\_0091212

For bare blocking diodes, if there are requirements on specific environmental conditions, they shall be stated in the SCD-PBD.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

ECSS-E-ST-20-08\_0091213

For connector integrated blocking diodes, requirements for voltage loading to simulate ambient illumination and other required environmental conditions shall be stated in the SCD-PBD.

1. Other required environmental conditions are for example, chemical vapour requirements.

#### HT2 for acceptance testing

##### Purpose

This test is to verify the adherence of the contacts of the planar blocking diodes, if available.

##### Process

ECSS-E-ST-20-08\_0091214

All blocking diodes shall be placed in a chamber at ambient pressure.

ECSS-E-ST-20-08\_0091215

The chamber temperature shall then be increased to 95 °C minimum.

ECSS-E-ST-20-08\_0091216

Relative humidity shall be higher than 90 %.

ECSS-E-ST-20-08\_0091217

The duration of the test shall be 24 h.

ECSS-E-ST-20-08\_0091218

High-purity water in accordance with ASTM D1193-99, Type I, shall be used.

ECSS-E-ST-20-08\_0091219

Water condensation on the surface of the blocking diodes shall be prevented.

ECSS-E-ST-20-08\_0091220

If there are requirements on specific environmental conditions, such as chemical vapours, they shall be stated in the SCD-BSC.

1. For example, chemical vapour requirements and/or voltage loading to simulate ambient illumination.

### Temperature Cycling (CY)

#### Purpose

The purpose of this test is to assess the reliability of test samples under a thermal stress equivalent to the number of eclipses that occur during one year in orbit for LEO missions, and 1000 thermal cycles for GEO missions or the complete lifetime cycling for interplanetary or other mission types.

#### Process

ECSS-E-ST-20-08\_0091221

The number of cycles and the extreme temperatures shall be as stated in the SCD-PBD.

ECSS-E-ST-20-08\_0091222

Additional cycles, to the ones specified in 12.6.5.2a, shall be added to cover mission phases with low occurrence but very extreme temperatures, and agreed with the customer.

### Contact Adherence (CA)

#### Purpose

This test is performed to verify the durability of the contacts of the planar blocking diodes.

#### Process

ECSS-E-ST-20-08\_0091223

All diodes shall be subjected to a coating adherence test on both sample faces.

ECSS-E-ST-20-08\_0091224

Test method shall be established according to a standard which is mutually agreed with the customer.

1. Example of such standards are MIL-M-13508, ISO 9211-4 or ECSS-Q-ST-70-13.

ECSS-E-ST-20-08\_0091225

The adhesive tape used for this test shall be clear in colour with an adhesive strength on steel of at least 0,28 N/mm.

1. Example of a standard that can be used to measure the strength is EN 1939.

ECSS-E-ST-20-08\_0091226

The adhesion of the used tape shall be within a tolerance of + 10 %.

#### Pass/fail criteria

ECSS-E-ST-20-08\_0091227

Any visible delamination of parts of the contacts shall not exceed the limits specified in clause 12.6.1.3.

### Burn-in (BI)

#### Purpose

This test is performed to eliminate marginal devices or those with defects resulting from manufacturing aberrations that are evidenced as time and stress dependent failures. In case of bipolar devices, there are two types of burn-in: The Power Burn-in stresses the diode in forward direction and the high temperature reverse bias burn-in with a reverse bias applied. Due to the constant forward bias in normal operation, the power burn-in are performed with a longer duration.

#### Power Burn-in (FWD-BI)

##### Purpose

The test simulates actual device operation but with accelerated conditions.

##### Process

ECSS-E-ST-20-08\_0091228

The power burn-in test shall be performed as follows:

The devices are subjected to the forward current specified in the SCD-PBD for a minimum of 96 hours or an extended period to be agreed with the customer, and

at a diode temperature Tj as specified in the SCD-PBD.

#### High Temperature Reverse Bias Burn-in (HTRB-BI)

##### Process

ECSS-E-ST-20-08\_0091229

The high temperature reverse bias burn-in test shall be performed with the cathode positively biased for a maximum of 48 hours.

ECSS-E-ST-20-08\_0091230

The duration, specified in 12.6.7.3.1a may be reduced, in agreement with the customer, based on the results obtained in the engineering test lot.

ECSS-E-ST-20-08\_0091231

The reverse bias shall be a DC bias.

ECSS-E-ST-20-08\_0091232

The temperature shall be the maximum operating temperature plus 10 K margin.

ECSS-E-ST-20-08\_0091233

At the end of the high-temperature test time, the temperature shall be lowered and the test voltage maintained on the devices until a device temperature of +30°C ±5°C is attained.

ECSS-E-ST-20-08\_0091234

After removal of the bias voltage, no other voltage shall be applied to the device before taking the post measurement.

ECSS-E-ST-20-08\_0091235

The applied voltage shall be 80% of the maximum reverse voltage of the diode, which is identified by characterization of the breakdown according to MIL-STD-750 Method 4021.

1. The typical applied voltage is 10V lower than the breakdown voltage.

### Long duration-Life Test (LT)

#### Purpose

The long duration-Life test (LT) determines the stability of the diodes under extreme operation conditions for long duration.

#### Process

ECSS-E-ST-20-08\_0091236

The diodes shall be forward and reverse biased at maximum operating temperature.

ECSS-E-ST-20-08\_0091237

For the definition of the maximum temperature and once per diode technology, the temperature step stress test as defined in ESCC 2265000 shall be performed.

ECSS-E-ST-20-08\_0091238

Forward and reverse conditions are mission dependent and shall be specified in the SCD-PBD.

ECSS-E-ST-20-08\_0091239

The test duration shall be defined based on the activation energy and the mission duration and stated in the SCD-PBD.

ECSS-E-ST-20-08\_0091240

The activation energy shall be:

determined in accordance with ESCC 2265000, or

for silicon PN junction blocking diodes be 0,7 eV.

ECSS-E-ST-20-08\_0091241

Intermediate and End-Point Electrical Measurements shall be performed.

#### Pass/fail criteria

The pass/fail criteria the long duration-life test shall be defined in the SCD-PBD.

### Temperature behaviour test (TB)

#### Purpose

The purpose of the Temperature behaviour test is to assess the corresponding electrical parameters of the planar blocking diodes as a function of temperature over the entire temperature range of the application and to provide data for the design of the solar generator.

#### Process

ECSS-E-ST-20-08\_0091242

Electrical measurements shall be performed at maximum (t1) and minimum (t2) junction temperatures, as well as at operational temperature and three temperatures close to extremes t1 and three temperatures close to extreme t2, where:

t1 = highest temperature (without margins) predicted for the application.

t2 = lowest temperature (without margins) predicted for the application.

1. The 3 temperatures close to the extremes to be chosen at equidistance of 10 K to 20 K depending on the limitations of the test facility with at least one measurement at the extreme temperature.

ECSS-E-ST-20-08\_0091243

Electrical measurements shall be performed up to a forward current IFwd and a reverse voltage VRev respectively; IFwd and VRev are specified in the SCD-PBD for each temperature.

ECSS-E-ST-20-08\_0091244

The electrical measurement shall be performed in darkness.

### Temperature robustness test (TR)

#### Purpose

The purpose of Temperature robustness test is to demonstrate the devices robustness at extreme temperatures.

#### Process

ECSS-E-ST-20-08\_0091245

The Temperature robustness test shall be performed as follows:

At the extreme temperatures predicted for the application, t1 and t2, plus a margin of 10 K.

Up to a forward current, IFwd, which is as a minimum, equal to 1,33 times the expected string current at solar array level.

Up to a reverse voltage, VRev, which is as a minimum, equal to 1,33 times the expected solar cell open circuit voltage, however VRev x 1,33 shall always be smaller than 80 % of the Breakdown Voltage at that temperature.

### Total Dose Radiation Testing (RT)

#### Ionising radiation test

##### Process

ECSS-E-ST-20-08\_0091246

The radiation source used for the test shall be the field of a Cobalt 60 gamma source or an electron accelerator beam.

1. Alternative sources that can be correlated to these sources may be used but, in the case of dispute, between the customer and the supplier, the Cobalt 60 or electron accelerator methods shall govern.

ECSS-E-ST-20-08\_0091247

The dose at the device under test shall be determined with an accuracy of better than 10 % and the non-uniformity of the radiation field in the test area be a maximum of 5 %.

ECSS-E-ST-20-08\_0091248

The ionising radiation test shall be performed as follows:

Reverse and forward bias are applied to the diode during the radiation test.

While connected to the bias fixture, the biasing condition for the test devices are maintained and monitored to remain within 3 % of the conditions specified in the SCD-PBD.

If these limits are exceeded the test is void.

The bias applied to the test devices is worst case conditions to produce the greatest radiation-induced damage to those devices.

ECSS-E-ST-20-08\_0091249

The irradiation and bias conditions from Table 12‑4 shall be applied.

ECSS-E-ST-20-08\_0091250

Table 12‑4: Diode Irradiation and bias conditions

|  |  |
| --- | --- |
| **Temperature:** | Room temperature |
| **Total dose limit:** | Typical 50 Mrad (Si eq.) |
| **Dose rate** | Typical ≥ 180 krad (Si eq.)(1) |
| **Bias:** |  |
| Group I (8 diodes) | Forward biased |
| Group II (8 diodes) | Reverse biased |
| Group III (8 diodes) | not biased |
| Note 1 No dose rate dependence for silicon diodes expected. | |

ECSS-E-ST-20-08\_0091251

Post irradiation electrical characterisation should start within 1 hour of completion of the irradiation.

ECSS-E-ST-20-08\_0091252

A ionizing dose of 50 Mrad is a typical value and shall cover most LEO and GEO missions.

ECSS-E-ST-20-08\_0091253

For more exotic missions, which require higher doses, the ionising dose of 50 Mrad shall be adjusted, in agreement with the customer, considering a margin of 1,2.

##### Pass/fail criteria

ECSS-E-ST-20-08\_0091254

After ionizing irradiation and temperature annealing, the requirements as stated in the SCD-PBD for the diode characteristics shall be satisfied.

#### Non-ionising radiation test

##### Purpose

Technologies, which can be identified as being sensitive to displacement damage shall be exposed to non-ionising radiation. For these technologies the preferred radiation source is an electron accelerator. This test is an accelerated life test to check the blocking diode performance degradation under electron particle irradiation.

##### Process

ECSS-E-ST-20-08\_0091255

The planar blocking diodes shall be subjected to 1 MeV electron irradiation.

1. ISO 23038 outlines a methodology to perform this test.

ECSS-E-ST-20-08\_0091256

The flux density and energy shall be uniform over the cell area within ±10 %.

ECSS-E-ST-20-08\_0091257

During irradiation, the test samples shall be protected from oxidation, using either vacuum below 10-3 Pa or a dry atmosphere of nitrogen or argon at a temperature of (20 ±10) °C.

1. The nominal rate is typical in the area of:

5 × 1011 e- cm-2 s-1.

ECSS-E-ST-20-08\_0091258

The irradiation facility, dosimetry included, shall be approved by the customer.

ECSS-E-ST-20-08\_0091259

The irradiation shall be performed as follows:

State the expected dose Φe, in the SCD-PBD for the envisaged application, including the transfer orbit dose and a margin factor of 1,2.

Divide Subgroup C in three batches of 8 samples.

Irradiate the batches specified in 2. As follows:

the first batch at Φe/2;

the second batch, at Φe.

the third batch, at 2 × Φe.

##### Pass/fail criteria

ECSS-E-ST-20-08\_0091260

After electron irradiation and temperature annealing, the requirements as stated in the SCD-PBD for the diode characteristics shall be satisfied.

### Temperature Annealing (TA)

#### Purpose

After the irradiation and the first post-irradiation electrical characterisation, temperature annealing is performed followed by the second electrical characterisation, in order to verify the blocking diode stability.

#### Process

ECSS-E-ST-20-08\_0091261

The samples shall be kept at 25 °C for 24 hours and at 100 °C for 168 hours to achieve an annealing effect.

### Contact uniformity test (CU)

#### Purpose

The Contact uniformity test verifies the uniformity of contact in order to ensure adequate and reproducible results of subsequent interconnector welding processes.

#### Process

ECSS-E-ST-20-08\_0091262

The uniformity of the thickness of the metal contact in the interconnector weld area shall be checked with a with a step-height profiler for instance a betascope, or a similar instrument, on front and rear side contacts.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0091263

The thickness uniformity of the contact material shall conform to the requirements specified in the SCD-PBD and the certified procurement specification of the supplier.

### Surface Finish test (SF)

#### Purpose

The diode surface finish test verifies the surface finish of the diode contacts.

#### Process

ECSS-E-ST-20-08\_0091264

The surface finish in the interconnector weld area shall be checked with a micro surface-roughness tester.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0091265

The surface finish of the metal layers of the diode contact shall conform to the requirements of the interconnection process, as specified in the SCD-PBD, and the certified procurement specification of the supplier.

### Human Body ESD test (ESD)

#### Purpose

The Human Body ESD test determines the robustness of the diode against human body electrostatic discharges.

#### Process

ECSS-E-ST-20-08\_0091266

The planar blocking diodes shall be equipped with interconnects.

ECSS-E-ST-20-08\_0091267

The test shall be performed in conformance with IEC 60749-26:2006.

ECSS-E-ST-20-08\_0091268

Planar blocking diode performances shall be verified in between tests.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0091269

The planar blocking diode electrical characteristics shall satisfy the pass-fail criteria stated in the SCD-PBD

### Pull test (PT) / Interconnector adherence test (IA)

#### Purpose

The pull test and interconnector adherence test is performed to check the bond strength of the contacts under mechanical and environmental stress and to verify the electrical stability after interconnector welding.

#### Process

ECSS-E-ST-20-08\_0091270

A gradually increasing pull force shall be applied to the interconnector tabs at a pull speed as stated in the SCD-PBD.

ECSS-E-ST-20-08\_0091271

The pull direction shall:

be either 0°, 45° or 90°;

be as stated in the SCD-PBD.

ECSS-E-ST-20-08\_0091272

The type of failure shall be recorded in the data documentation package (DDP) as specified in clause 12.8.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0091273

The pull strength shall satisfy the pass-fail criteria stated in the SCD-PBD.

### Surge test (ST)

#### Purpose

Surge is the application of a high peak current ten times (minimum) the device average current maximum rating applied for a short pulse width appropriate to determine processing defects (e.g., wire bond integrity, micro cracks, and bond voids).

#### Process

ECSS-E-ST-20-08\_0091274

While the diode is biased at the maximum forward current, in accordance with the SCD-PBD, 10 pulses of 80 A with 8,3 ms duration shall be applied with a waiting time of 1 minute between one surge pulse and the other.

ECSS-E-ST-20-08\_0091275

In case the current level is not compatible with the diode technology, the manufacturer may propose a lower current level for customer approval, supported by an analysis that shows an acceptable margin to cover the mission expected electrical surge stresses.

1. Typical test conditions covering GEO and LEO missions can be in accordance with MIL-STD-750 Method 4066.

#### Pass-Fail criteria

ECSS-E-ST-20-08\_0091276

Pass-fail criteria for the surge test shall be as stated in the SCD-PBD

### Thermo-optical data (TO)

#### Purpose

Thermo-optical data is used for computation of the solar panel operational temperature.

#### Process

ECSS-E-ST-20-08\_0091277

The solar absorptance and the hemispherical emittance should be measured according to ECSS-Q-ST-70-09.

#### Pass-fail criteria

ECSS-E-ST-20-08\_0091278

Pass-fail criteria for thermo-optical properties shall be as stated in the SCD-PBD.

## Failure definition

### Failure criteria

ECSS-E-ST-20-08\_0091279

The following shall constitute failures:

Blocking diodes that fail during subgroup tests for which the pass-fail

Blocking diodes failing to conform to the requirements of visual inspection stated in the SCD-PBD

Blocking diodes whose marking fails to conform to the requirements of clause 12.2.3.

Blocking diodes that, when subjected to diode characteristics measurements after acceptance tests in conformance with the SCD-PBD, fail to meet one or more of the specified limits, measurement accuracy included.

### Failed Blocking Diodes

ECSS-E-ST-20-08\_0091280

A component shall be considered to have failed if it exhibits one or more of the failure modes specified in clause 12.7.1.

ECSS-E-ST-20-08\_0091281

Failed components shall be identified as such and included in the delivery.

ECSS-E-ST-20-08\_0091282

Failure analysis of these components shall be performed by the supplier and the results provided to the customer as part of the NRB documentation.

1. For NRB, see ECSS-Q-ST-10-09.

## Data documentation

ECSS-E-ST-20-08\_0091283

The supplier shall provide a data documentation package (DDP) in conformance with Annex G for the qualification approval records and for each component delivery lot.

## Delivery

ECSS-E-ST-20-08\_0091284

All deliverable hardware specified in the order shall be delivered together with documentation in conformance with the requirements specified in clause 12.8.

ECSS-E-ST-20-08\_0091285

One set of documents shall be sent to the customer.

## Packing, despatching, handling and storage

### Overview

For packaging, despatching, handling and storage of components see ECSS-Q-ST-20-08.

### ESD sensitivity

ECSS-E-ST-20-08\_0091286

If a blocking diode is sensitive to ESD according to clause 5.2 of ESCC 23800 Issue 1 then it shall be handled and stored according to ESCC 24900 Issue 2, clause 10.

1. (normative)  
   Source control drawing for photovoltaic assembly (SCD‑PVA) ‑  DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement 5.2b.

* + 1. Purpose and objective

The source control drawing for photovoltaic assembly (SCD-PVA) contains the specific project dependent requirements, and together with this Standard, which contains the general requirements, constitutes the whole set of requirements for the qualification and acceptance of photovoltaic assemblies.

The SCD-PVA can be produced as a standalone document or as part of a system-level specification document.

The information on traceability to high level requirements can be included in the SCD-PVA itself or in the requirements traceability in the design justification file (DJF, see ECSS-E-ST-10). In either case a cross reference is made.

The SCD-PVA is a major input to the qualification plan.

* 1. Expected response
     1. Scope and content

Introduction

ECSS-E-ST-20-08\_0090878

The SCD-PVA shall contain a description of the purpose, objective, content and the reasons prompting its preparation.

Applicable and reference documents

ECSS-E-ST-20-08\_0090879

The SCD-PVA shall list the applicable and reference documents to support the generation of the document.

Terms and definitions, abbreviated terms and symbols

ECSS-E-ST-20-08\_0090880

The SCD-PVA shall include any additional definition, abbreviation or symbol used.

Deviations from ECSS-E-ST-20-08

ECSS-E-ST-20-08\_0090881

In conformance with clause 5.2, the SCD-PVA shall include the description and justification for any deviation in the in-process, acceptance and qualification tests.

Qualification test coupons

ECSS-E-ST-20-08\_0090882

In conformance with clause 5.5.1.3.3, the SCD-PVA shall include the following:

In conformance with clause 5.5.1.3.3, the SCD-PVA shall include the front and rear side drawings of each qualification coupons with physical dimensions and including tolerances.

In conformance with clause 5.5.1.3.3, the SCD-PVA shall include the number of repaired cells to be included on each qualification coupon.

In-process tests

Mass measurement

ECSS-E-ST-20-08\_0090883

The SCD-PVA shall state the maximum value of the mass of the coupon, in g, obtained from the mass measurement specified in clause 5.4.3.2.

Wet insulation

ECSS-E-ST-20-08\_0090884

In conformance with clause 5.4.3.3, the SCD-PVA shall state:

The test voltage, in V.

The fluid to use.

The minimum value for the wet insulation, in MΩ.

1. 1 The fluid used is normally ethyl or isopropyl.
2. 2 A usual value for the wet insulation is 100 MΩ.

Adherence to substrate

ECSS-E-ST-20-08\_0090885

In conformance with clause 5.4.3.4, the SCD-PVA shall state the minimum flatwise tensile strength, in N.

ECSS-E-ST-20-08\_0091287

In conformance with 5.4.3.4b.1(b), the SCD-PVA shall state the required curing duration of the adhesive to bond the solar cells specified in 5.4.3.4b.1(a).

ECSS-E-ST-20-08\_0091288

In conformance with 5.4.3.4b.2(b) the SCD-PVA shall state the required curing duration of the adhesive to bond the two Kapton foils specified in 5.4.3.4b.2(a).

In-process visual inspection

ECSS-E-ST-20-08\_0090886

In conformance with clause 5.4.3.5, the SCD-PVA shall state the visual inspection procedure.

In-process continuity

ECSS-E-ST-20-08\_0090887

In conformance with clause 5.4.3.6, the SCD-PVA shall state the maximum value of the resistance, in Ω.

Qualification tests

Fatigue thermal cycling

ECSS-E-ST-20-08\_0090888

In conformance with clause 5.5.1.3, the SCD-PVA shall state the following:

The following test conditions:

the number of cycles to perform;

the temperature limits, in °C.

For the acceptance criteria:

the maximum variation of IOP, in %,;

the minimum insulation, in MΩ.

Humidity

ECSS-E-ST-20-08\_0090889

In conformance with clause 5.5.1.4, the SCD-PVA shall state:

The chemical contents, type and % in the mist, to be added to the humid environment when there are specific requirements on the contents of the environment and the voltage bias conditions to be applied to the PVA.

For the acceptance criteria:

the maximum variation of IOP, in %,;

the minimum insulation, in MΩ.

Erosion of materials

ECSS-E-ST-20-08\_0090890

In conformance with clause 5.5.1.6, the SCD-PVA shall state the test sequence, test definitions and requirements for the erosion of materials test.

EMC

ECSS-E-ST-20-08\_0090891

In conformance with clause 5.5.1.7, the SCD-PVA shall state the test sequence, test definitions and requirements for the EMC test.

Definition of tests and checks

Add-on mass

ECSS-E-ST-20-08\_0090892

In conformance with clause 5.5.3.1, the SCD-PVA shall state the maximum add-on mass of the coupon, in g, obtained from a mass measurement.

Full visual inspection

ECSS-E-ST-20-08\_0090893

The SCD-PVA shall state:

The maximum number of cell cracks on the coupons (in conformance with requirement ).

The maximum number of gridlines that a cell crack can cross (in conformance with requirement ).

The inspection criteria for solar cells on substrates (in conformance with clause 5.5.3.2.5).

Electrical health

ECSS-E-ST-20-08\_0090894

For electrical continuity check, in conformance with clause 5.5.3.3.2, the SCD-PVA shall state the following conditions for checking the continuity of the strings:

current to be applied, in A, or voltage to be measured, in V.

specified illumination to performed the measurement.

ECSS-E-ST-20-08\_0090895

For insulation resistance, the SCD-PVA shall state the minimum insulation resistance, in MΩ, at a test voltage specified in V, for the configurations specified in clause 5.5.3.3.3.

ECSS-E-ST-20-08\_0090896

For grounding spot resistance, in conformance with clause 5.5.3.3.4, the SCD-PVA shall state:

The maximum value, in Ω, of the resistance of bleed resistor lead (+) to substrate (-).

The maximum value, in Ω, of the grounding spots (+) to substrate (-).

ECSS-E-ST-20-08\_0090897

For bleed resistor test, in conformance with clause 5.5.3.3.5, the SCD-PVA shall state the range of values, in kΩ, of the bleed resistor.

ECSS-E-ST-20-08\_0090898

For blocking diode test, in conformance with clause 5.5.3.3.6, the SCD-PVA shall state:

The IFORWARD in A, and the VREVERSE in V, of the blocking diode.

The values for VFORWARD, in V, and IREVERSE, in A, to be obtained from the test.

ECSS-E-ST-20-08\_0090899

For shunt diode, in conformance with clause 5.5.3.3.7, the SCD-PVA shall state:

The IFORWARD, in A, to be used, and the maximum drop of forward voltage, in V, per cell, to be obtained from the test.

The test method to be used.

The maximum temperature, specified in C.

ECSS-E-ST-20-08\_0090900

For thermal sensor test, in conformance with clause 5.5.3.3.8, the SCD-PVA shall state:

The resistance of the thermal sensor as a function of the temperature.

The range of resistance to be obtained from the test, in Ω.

1. A reference to a calibration table, included in the SCD, can be used.

ECSS-E-ST-20-08\_0090901

For resistance measurements, in conformance with clause 5.5.3.3.9, the SCD-PVA shall state the maximum value of the resistance, in Ω, between the (+)/(+) and   
(-)/(-) ends of the harness.

Electrical performance

ECSS-E-ST-20-08\_0090902

In conformance with clause 5.5.3.4.2, the SCD-PVA shall state the following values, together with their inaccuracies, recalculated to 25 C, for 1 S.C. (AM0) (as defined in clause 10), providing the test voltage VOP range (specified in V), and the temperature range (specified in C):

the nominal value of the IOP,MIN, in A;

the nominal value of VP,MAX., in V;

the nominal value of VOC, in V;

the nominal value of IP,MAX, in A;

the nominal value of ISC, in A.

Capacitance

ECSS-E-ST-20-08\_0090903

In conformance with clause 5.5.3.5, the SCD-PVA shall state a procedure to measure the capacitance, including the test temperature (average operational temperature).

Bake-out

ECSS-E-ST-20-08\_0090904

In conformance with clause 5.5.3.6, the SCD-PVA shall state: the test conditions, as a combination of time and temperature.

Acceptance thermal cycling test

ECSS-E-ST-20-08\_0090905

In conformance with clause 5.5.3.7, the SCD-PVA shall state:

The following test conditions for the tests specified in clause 5.5.3.7:

The number of cycles to perform.

The temperature limits, in C.

For the acceptance criteria:

The maximum increment of IOP, in %.

The minimum insulation, in MΩ.

Reflectance

ECSS-E-ST-20-08\_0090906

In conformance with clause 5.5.3.8, the SCD-PVA shall state the maximum reflectance change, in %, for the following wavelength bands:

λ ≤ 300 nm;

300 nm < λ < 900 nm;

900 nm< λ < 1 800 nm.

Transmission

ECSS-E-ST-20-08\_0090907

In conformance with clause 5.5.3.9, the SCD-PVA shall state the acceptance criteria for the change in transmission due to contamination in the band of 280 nm < λ < 2 500 nm.

X-ray

ECSS-E-ST-20-08\_0090908

In conformance with clause 5.5.3.9, the SCD-PVA shall state the acceptance criteria, for the integrity of:

busbars,

wire collection strips, and

diode boards.

Substrate integrity

ECSS-E-ST-20-08\_0090909

In conformance with clause 5.5.3.10, the SCD-PVA shall state:

The test method, either airscan, or C-scan, or destructive test, for the integrity of the skin to honeycomb.

The acceptance criteria.

Vacuum thermal cycling

ECSS-E-ST-20-08\_0090910

In conformance with clause 5.5.3.11, the SCD-PVA shall state the maximum acceptable degradation, as follows:

The maximum increment for IOP, in %.

The minimum insulation, in MΩ .

* + 1. Special remarks

None.

1. (normative)  
   Source control drawing for solar cell assembly (SCD‑SCA) ‑ DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement 6.1.2b.

* + 1. Purpose and objective

The source control drawing for solar cell assembly (SCD-SCA) contains the specific project dependent requirements, and together with this Standard, which contains the general requirements, constitutes the whole set of requirements for the qualification and acceptance of solar cell assemblies.

The SCD-SCA can be produced as a standalone document or as part of a system-level specification document.

The information on traceability to high level requirements can be included in the SCD-SCA itself or in the requirements traceability in the design justification file (DJF, see ECSS-E-ST-10). In either case a cross-reference is made.

The SCD-SCA is a major input to the qualification plan.

* 1. Expected response
     1. Scope and content

Introduction

ECSS-E-ST-20-08\_0090911

The SCD-SCA shall contain a description of the purpose, objective, content and the reason prompting its preparation.

Applicable and reference documents

ECSS-E-ST-20-08\_0090912

The SCD-SCA shall list the applicable and reference documents to support the generation of the document.

Terms and definitions, abbreviated terms and symbols

ECSS-E-ST-20-08\_0090913

The SCD-SCA shall include any additional definition, abbreviation or symbol used.

Deviations from ECSS-E-ST-20-08

ECSS-E-ST-20-08\_0090914

In conformance with clause 6.1.2, the SCD-SCA shall include the justification for any deviation in the in-process, acceptance and qualification tests.

Materials

ECSS-E-ST-20-08\_0090915

The SCD-SCA shall include the following solar cell characteristics:

For silicon solar cells:

growth technique, base resistivity, and thickness.

for ARC: materials

for metal contact materials and thickness

For GaAs single or multi-junction solar cells:

for the substrate: type of material and thickness;

for each sub-cell: materials,.

for ARC: materials

for metal contact materials and thickness

For interconnects:

materials and dimensions, all metal layers and their thickness.

joining technique, additional materials (if any) and reference to the procedure

For coverglass: material, thickness, ARC, and conductive coating.

For coverglass adhesive, material and outgassing rates and reference to the procedure for process details and cementing conditions.

1. See ECSS-Q-ST-70-02.

Test methods, conditions and measurements

Dimensions and weight

ECSS-E-ST-20-08\_0090916

In conformance with clause 6.4.3.2, the SCD-SCA shall include:

A figure, showing the physical dimensions of the solar cell assembly, including both, the nominal values and tolerances.

The average weight (per lot) of solar cell assemblies including the interconnector, in grams.

Electrical performance

ECSS-E-ST-20-08\_0090917

In conformance with clause 6.4.3.3, the SCD-SCA shall include, the information shown in , extended if there are several operational voltages at a solar cell temperature of 25 C, under illumination of 1 S.C (AM0).

ECSS-E-ST-20-08\_0091057

: Minimum current requirement for solar assemblies (25 C or operating temperature)

|  |  |  |  |
| --- | --- | --- | --- |
| Sample | Irradiation dose | Test voltage  Vt (mV) | Current at  Vt (mA) |
| Minimum for individual solar cell assemblies | BOL | [Insert value] | [Insert value] |
| EOL | [Insert value] | [Insert value] |
| Minimum average for solar cell assemblies | BOL | [Insert value] | [Insert value] |
| EOL | [Insert value] | [Insert value] |
| Test temperature: [Insert value] | | | |
| NOTE: EOL is defined as 1 MeV Φp electron dose (in conformance with 6.4.3.12) plus photon irradiation and temperature annealing (in conformance with 6.4.3.13). | | | |

Temperature coefficient

ECSS-E-ST-20-08\_0090918

In conformance with clause 6.4.3.4, the SCD-SCA shall include the six equidistant solar cell temperatures to which the test is performed.

Spectral response

ECSS-E-ST-20-08\_0090919

In conformance with clause 6.4.3.5, the SCD-SCA shall include for multi-junction GaAs solar cells, the number of narrow band interference filters and their wavelength.

Thermo-optical properties

ECSS-E-ST-20-08\_0090920

In conformance with clause 6.4.3.6, the SCD-SCA shall include the following:

The maximum value of the solar absorptance as a percentage of SCAs with tolerances.

The maximum value of normal emittance as a percentage (%) of SCAs with tolerances.

Thermal cycling

ECSS-E-ST-20-08\_0090921

In conformance with clause 6.4.3.7, the SCD-SCA shall include the number of cycles to be performed and their extreme temperatures, to simulate the number of eclipses occurring during one year in orbit for LEO missions, and 1000 thermal cycles for GEO missions, or the complete lifetime cycling for interplanetary or other mission types.

Humidity and temperature

ECSS-E-ST-20-08\_0090922

In conformance with clause 6.4.3.8, the SCD-SCA shall include the chemical contents, type and % in the mist, to be added to the humid environment, when there are specific requirements on the contents of the environment and the voltage bias condition to be applied to the SCA.

Coating adherence

ECSS-E-ST-20-08\_0090923

In case of coverglass with conductive coating, in conformance with clause 6.4.3.9, the SCD-SCA shall specify which of the two standards ISO 9211-4 or ECSS Q-ST-70-13 is applied

Interconnector adherence

ECSS-E-ST-20-08\_0090924

In conformance with clause 6.4.3.10 the SCD-SCA shall include:

the value of the pull speed, in mm/min;

the pull direction

the value of the separation pull strength of interconnectors, in N.

Electron irradiation

ECSS-E-ST-20-08\_0090925

In conformance with clause 6.4.3.11, the SCD-SCA shall include:

The three fluences at 1MeV, in e- cm2;

<<deleted>>

Surface conductivity

ECSS-E-ST-20-08\_0090926

In conformance with clause 6.4.3.13, the SCD-SCA shall describe:

The method to perform the surface conductivity test that shall be between the contact dots or an alternative one to be specified here in the SCD-SCA.

The minimum value, in Ω, and the maximum variation after any test, in Ω, of the cover conductivity before and after qualification tests of SCA of subgroup D (in conformance with Table 6‑1).

Solar Cell reverse bias test

ECSS-E-ST-20-08\_0090927

In conformance with clause 6.4.3.14, that is applicable only for SCAs without protection diode or with a protection diode electrically isolated form the cell, the SCD-SCA shall include:

The reverse I/V characteristics measured under illumination of 1 S.C.;

The following measurement parameters shall be clearly stated in the SCD-SCA

power supply limitation

temperature

hold time

maximum reverse bias voltage

The pass-fail criteria

the maximum change in the value of reverse current ∆I, in mA from the initial value of the same parameter when measured as delivered. Pass fail criteria shall be specified in the SCD-SCA.

the maximum absolute value of the reverse current, in mA.

Ultraviolet exposure

ECSS-E-ST-20-08\_0090928

In conformance with clause 6.4.3.15, the SCD-SCA shall include the following:

The operational test temperature, in C.

The EOL UV loss factor.

Capacitance

ECSS-E-ST-20-08\_0090929

In conformance with clause 6.4.3.16, the SCD-SCA shall include the test temperature, in C and the capacitance test method as specified either in clause 11.1 or 11.2 of this Standard.

Flatness

ECSS-E-ST-20-08\_0090930

In conformance with clause 6.4.3.17, the SCD-SCA shall include the minimum flatness, as a maximum deviation given in mm.

* + 1. Special remarks

None.

1. (normative)  
   Source control drawing for bare solar cell (SCD‑BSC) ‑ DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement .

* + 1. Purpose and objective

The source control drawing for bare solar cell (SCD-BSC) contains the specific project dependent requirements, and together with this Standard, which contains the general requirements, constitutes the whole set of requirements for the qualification and acceptance of bare solar cells.

The SCD-BSC can be produced as a standalone document or as part of a system-level specification document.

The information on traceability to high level requirements can be included in the SCD-BSC itself or in the requirements traceability in the design justification file (DJF, see ECSS-E-ST-10). In either case a cross-reference is made.

The SCD-BSC is a major input to the qualification plan.

* 1. Expected response
     1. Scope and content

Introduction

ECSS-E-ST-20-08\_0090931

The SCD-BSC shall contain a description of the purpose, objective, content and the reason prompting its preparation.

Applicable and reference documents

ECSS-E-ST-20-08\_0090932

The SCD-BSC shall list the applicable and reference documents to support the generation of the document.

Terms and definitions, abbreviated terms and symbols

ECSS-E-ST-20-08\_0090933

The SCD-BSC shall include any additional definition, abbreviation or symbol used.

Deviations from ECSS-E-ST-20-08

ECSS-E-ST-20-08\_0090934

In conformance with requirement 7.1.1.2c, the SCD-BSC shall include the justification for any deviation in the in-process, acceptance and qualification tests.

Materials

ECSS-E-ST-20-08\_0090935

The SCD-BSC shall include:

Reference to the procurement specification of the supplier.

For silicon solar cells, the following characteristics of the cells:

growth technique;

doping element;

orientation;

main breakage direction;

base resistivity;

thickness;

for ARC: materials;

for metal contact materials and thickness.

For single and multi-junction III-V solar cells, the following characteristics of the cells:

substrate material, orientation and thickness;

doping element of the substrate;

substrate resistivity;

for each sub-cell: materials,

for ARC: materials;

for metal contact materials and thickness.

Acceptance tests

Visual inspection.

ECSS-E-ST-20-08\_0090936

In conformance with clause 7.5.1.5.4, the SCD-BSC shall list the maximum visible semiconductor length at the corners, in mm.

Dimensions and weight

ECSS-E-ST-20-08\_0090937

In conformance with clause 7.5.2, the SCD-BSC shall include:

The dimensions shown in to including tolerances.

The measurement method used to perform the test.

The interval of the thickness of the silicon layer, in μm, for silicon solar cells.

The interval of the thickness of the substrate with epi-layers, in m, for III-IV cells.

The maximum weight, in mg, of the average shipment lot.



ECSS-E-ST-20-08\_0091058

: BSC front side



: BSC rear side



ECSS-E-ST-20-08\_0091059

: BSC contact

Contact uniformity

ECSS-E-ST-20-08\_0090938

In conformance with clause 7.5.10, the SCD-BSC shall include:

The equipment to measure the contact thickness;

The maximum and minimum values of the contact thickness in μm.

Surface finish

ECSS-E-ST-20-08\_0090939

In conformance with clause 7.5.11, the SCD-BSC shall include the maximum value of the surface finish (Rz) in μm.

Electrical performance

ECSS-E-ST-20-08\_0090940

In conformance with clause 7.3.2.2.2, the SCD-BSC shall include the following test conditions:

the Vtest, in mV;

the temperature, in C;

the cells used as reference and their traceability to primary standards.

ECSS-E-ST-20-08\_0090941

In conformance with clause 7.3.2.2.3 for the pass-fail criteria, the following requirements shall be included:

the minimum value for Itest, in mA;

the average value for Itest, in mA;

ECSS-E-ST-20-08\_0090942

In conformance with clause 7.3.2.2.4 the SCD-BSC shall include the intervals in mA for electrical grading

Hemispherical reflectance

ECSS-E-ST-20-08\_0090943

In conformance with clause 7.5.6.2, the SCD-BSC shall include the interval of reflectance for silicon BSR cells, at 1,5 μm, as a percentage (%).

Humidity and temperature

ECSS-E-ST-20-08\_0090944

In conformance with clause 7.5.7.2.2, the SCD-BSC shall include the chemical contents, type and % in the mist, to be added to the humid environment when there are specific requirements on the contents of the environment and the voltage bias condition to be applied to the BSC.

Pull

ECSS-E-ST-20-08\_0090945

In conformance with clause 7.5.12, the SCD-BSC shall include:

the interconnection technique parameter;

the material and dimension of the interconnectors;

the value of the pull speed in mm/min;

the value of the ultimate pull strength in N;

the pull direction (0°, 45° or 90°).

Integral diode performance

ECSS-E-ST-20-08\_0090946

In conformance with clause 9.4.5.2, the SCD-BSC shall include for cells with protection diode electrically isolated from the cell:

For the test specified in requirement :

the temperature,

the forward current,

the reverse voltage.

The pass-fail criteria for the test specified in clause 9.4.5.2.3:

the maximum absolute value of the forward voltage in V;

the reverse current in mA.

The physical limits in terms of maximum forward current and reverse voltage.

Cell coverglass gain-loss

ECSS-E-ST-20-08\_0090947

In conformance with clause 7.5.6.3, the SCD-BSC shall include:

the agent used to simulate the properties of the adhesive;

the coverglass used for the test;

for the test conditions, the temperature, in C;

for the pass-fail criteria, the maximum ISC, in %.

Qualification

Visual inspection

ECSS-E-ST-20-08\_0090948

The SCD-BSC shall include the same provisions as in the visual inspection for the acceptance tests (in conformance with clause ).

Dimensions and weight

ECSS-E-ST-20-08\_0090949

The SCD-BSC shall include the same provisions as in the dimensions and weight for the acceptance tests (in conformance with clause ).

Electrical performance

ECSS-E-ST-20-08\_0090950

In conformance with clause 7.5.3.2, the SCD-BSC shall include the pass-fail values shown in , for

the individual solar cells, and

the minimum average.

ECSS-E-ST-20-08\_0091060

: Electrical performance pass-fail criteria

|  |  |  |  |  |
| --- | --- | --- | --- | --- |
| Parameter | BOL | Remaining Factors (at 25 C) | | |
| EOL([Insert value]) (particles/cm2)a) | EOL([Insert value]) (particles/cm2)a) | EOL([Insert value]) (particles/cm2)a) |
| Ratio | Ratio | Ratio |
| VOC [mV] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |
| Isc [mA/cm2] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |
| Vmax [mV] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |
| Imax [mA/cm2] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |
| Pmax [mW/cm2] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |
| I(Vt) [mA] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |
| a) particles are electrons or protons after photon irradiation and temperature annealing | | | | |

Spectral response

ECSS-E-ST-20-08\_0090951

If the method using narrow band interference filters the SCD-BSC shall include (in conformance with requirement for multi-junction GaAs solar cells the number of narrow band interference filters and their wavelength.

Optical properties

ECSS-E-ST-20-08\_0090952

Hemispherical reflectance

The SCD-BSC shall include the same provisions as in the hemispherical reflectance for acceptance tests (in conformance with clause ).

ECSS-E-ST-20-08\_0090953

Coverglass gain-loss

The SCD-BSC shall include the same provisions as in the coverglass gain-loss for acceptance tests (in conformance with clause ).

Humidity and temperature

ECSS-E-ST-20-08\_0090954

The SCD-BSC shall include the same provisions as in the humidity and temperature for acceptance tests (in conformance with clause .).

Contact uniformity

ECSS-E-ST-20-08\_0090955

In conformance with clause 7.5.9, the SCD-BSC shall include

the equipment to measure the contact thickness;

the requirements of the interconnection process to uniformity of the contact.

1. Example: maximum and minimum values of the contact thickness in μm.

Surface finish

ECSS-E-ST-20-08\_0090956

The SCD-BSC shall include the same provisions as in the surface finish for acceptance tests (in conformance with clause ).

Pull

ECSS-E-ST-20-08\_0090957

The SCD-BSC shall include the same provisions as in the pull test for acceptance tests (in conformance with clause ).

Electron irradiation

ECSS-E-ST-20-08\_0090958

In conformance with clause 7.5.13.2, the SCD-BSC shall include:

The five fluences at 1 MeV and five fluences at 3MeV, in e- cm-2.

<<deleted>>

<<deleted>>

Proton irradiation

ECSS-E-ST-20-08\_0090959

In conformance with clause 7.5.14.2, the SCD-BSC shall include:

The five fluences at 1 MeV and the five fluences at 3 MeV, in p+cm‑2 ;

For each of the two energies defined in C.2.1<7.11> a.1, the nominal flux in p+cm‑2 s-2.

Solar cell reverse bias

ECSS-E-ST-20-08\_0090960

In conformance with clause 7.5.16.2, the SCD-BSC shall include

the parameters of reverse IV characteristics measurement, such as test temperature in °C, hold time in s, current limitation in mA and maximum reverse bias in V

the pass/fail criteria

1. Example: maximum allowed difference in Iop before and after test.

Integral diode

ECSS-E-ST-20-08\_0090961

In conformance with clause 9.6, the SCD-BSC shall include for cells with integral protection diode electrically isolated from the cell:

for burn in (in conformance with clause 9.6.5): the junction temperature of the diode at which burn in is to be performed

for diode characterization the same provisions as in the diode characterization for the acceptance tests (in conformance with clause )

for ESD (in conformance with clause 9.6.16.3): the pass fail criteria

for switching test (in conformance with requirement ): the test conditions and pass fail criteria for level 1 and 2

for Long Duration - Life Test (in conformance with requirement ): the total number of reverse bias and forward bias test steps, and the IREV, IFW and VFW.

Thermal cycling

ECSS-E-ST-20-08\_0090962

In conformance with clause 7.5.17, the SCD-BSC shall include the number of thermal cycles to be performed before pull test on subgroup A and after humidity and temperature test in subgroup O, and their extreme temperatures.

Active-passive interface evaluation

ECSS-E-ST-20-08\_0090963

In conformance with clause 7.5.18, the SCD-BSC shall include:

The deviation of total energy in the spectral region of 0,8 μm to 1,1 μm as a percentage, using a non-infrared rich solar simulator.

The maximum delta in Voc of the cell under both solar simulator conditions (1 S.C. (AM0) and non-infrared rich).

Flatness

ECSS-E-ST-20-08\_0090964

In conformance with clause 7.5.19, the SCD-BSC shall include:

The measurement method used to determine the flatness.

The minimum flatness, as the maximum value of deflection, in mm.

* + 1. Special remarks

None.

1. (normative)  
   Source control drawing for coverglass  
   (SCD‑CVG) ‑ DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement clause 8.3.1.2b.

* + 1. Purpose and objective

The source control drawing for coverglass (SCD-CVG) contains the specific project dependent requirements, and together with this Standard, which contains the general requirements, constitutes the whole set of requirements for the qualification and acceptance of coverglass.

The SCD-CVG can be produced as a standalone document or as part of a system-level specification document.

The information on traceability to high level requirements can be included in the SCD-CVG itself or in the requirements traceability in the design justification file (DJF, see ECSS-E-ST-10). In either case a cross-reference is made.

The SCD-CVG is a major input to the qualification plan.

* 1. Expected response
     1. Scope and content

Introduction

ECSS-E-ST-20-08\_0090965

The SCD-CVG shall contain a description of the purpose, objective, content and the reason prompting its preparation.

Applicable and reference documents

ECSS-E-ST-20-08\_0090966

The SCD-CVG shall list the applicable and reference documents to support the generation of the document.

Terms and definitions, abbreviated terms and symbols

ECSS-E-ST-20-08\_0090967

The SCD-CVG shall include any additional definition, abbreviation or symbol used.

Deviations from ECSS-E-ST-20-08

ECSS-E-ST-20-08\_0090968

In conformance with requirement 8.3.1.2c., the SCD-CVG shall include the justification for any deviation in the in-process, acceptance and qualification tests.

Materials

ECSS-E-ST-20-08\_0090969

The SCD-CVG shall include the following coverglass materials characteristics:

Coverglass base material, including doping elements and percentage (%).

Front surface coatings (including conductive coatings).

Rear surface coatings.

Marking (coating orientation)

ECSS-E-ST-20-08\_0090970

In conformance with clause 8.3.3, the SCD-CVG shall include a figure defining the coating orientation method for coverglass front surface coating identification.

1. This figure can be the same as the one mentioned in clause D.2.1<8.4>.

Acceptance tests

Sample size for acceptance

ECSS-E-ST-20-08\_0090971

In conformance with requirement , the SCD-CVG shall include the sample size for acceptance.

Transmission into air

ECSS-E-ST-20-08\_0090972

The SCD-CVG shall include the same provisions as for the transmission into air for qualification tests (in conformance with clause ).

Dimensions, weight and thickness

ECSS-E-ST-20-08\_0090973

The SCD-CVG shall include the same provisions as for the mechanical properties for the qualification tests (in conformance with , and ).

Visual inspection

ECSS-E-ST-20-08\_0090974

The SCD-CVG shall include the same provisions as for the visual inspection for qualification tests (in conformance with clause ).

Humidity and temperature HT2

ECSS-E-ST-20-08\_0090975

In conformance with clause 8.7.11.2, the SCD-CVG shall state the chemical contents (type and percentage (%) in the mist) of the humid environment when there are specific requirements on the contents of the environment.

Thermal cycling

ECSS-E-ST-20-08\_0090976

The SCD-CVG shall include the same provisions as for the thermal cycling for qualification tests (in conformance with clause D.2.1<8>).

Qualification tests

Qualification test samples

ECSS-E-ST-20-08\_0090977

In conformance with clause 8.6.2.2, the SCD-CVG shall include the number of the first production batches from which the coverglass qualification set is obtained.

Visual inspection

ECSS-E-ST-20-08\_0090978

In conformance with clause 8.7.1.2, the SCD-CVG shall include:

The maximum dimensions, in mm, of scratches and digs.

The maximum number of corner chips per coverglass.

Transmission into air

ECSS-E-ST-20-08\_0090979

Before the test the SCD-CVG shall include the transmission values shown in Table D-1.

ECSS-E-ST-20-08\_0090980

After the test the SCD-CVG shall include the transmission values shown in Table D-2.

ECSS-E-ST-20-08\_0091061

: Average transmission into air before test (%)

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Discrete wavelength (nm) | | | | Wavelength range (nm) | | | | |
| 400 | 450 | 500 | 600 | 300-320 | 400 - 450 | 600 - 800 | 450 - 1 100 | 900 - 1 800 |
| [Insert value] | [Insert value] | [Insert value] | [Insert value] | [Insert value] | [Insert value] | [Insert value] | [Insert value] | [Insert value] |

ECSS-E-ST-20-08\_0091062

: Maximum average deviation of transmission into air after test (%)

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
|  | Discrete Wavelength (nm) | | | | Wavelength Range (nm) | | | | |
| Environmental | 400 | 450 | 500 | 600 | 300 - 320 | 400 - 450 | 600 - 800 | 450 - 1 100 | 900- 1 800 |
| Boiling water | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] |
| Humidity and temperature HT1 | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] |
| Thermal cycling | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] |
| UV exposure | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] |
| Electron irradiation | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] |
| Proton irradiation | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] | [insert value] |

Electro-optical properties

ECSS-E-ST-20-08\_0090981

In conformance with clause 8.7.3, the SCD-CVG shall include a figure showing the nominal values and tolerances for the following electro-optical properties:

bulk resistivity and surface resistivity;

refractive index.

Mechanical properties

ECSS-E-ST-20-08\_0090982

In conformance with clause 8.7.4, the SCD-CVG shall include a figure showing the nominal values and tolerances of the following mechanical properties:

dimensions (A: length, B: width);

weight (average per shipping lot);

density

thickness;

edge parallelism;

perpendicularity of sides.

1. This figure can be the same as in clause D.2.1<8.4>.

Reflectance properties

ECSS-E-ST-20-08\_0090983

In conformance with clause 8.7.5, the SCD-CVG shall include a figure showing the nominal values and tolerances of the following reflectance properties:

reflectance (including wavelength);

reflectance cut-on;

reflectance cut-off;

reflectance bandwidth.

1. This figure can be the same as in clause D.2.1<8.4>.

Normal emittance

ECSS-E-ST-20-08\_0090984

In conformance with clause 8.7.6, the SCD-CVG shall include the minimum value of the normal emittance, as a percentage (%) and the equipment used to measure the normal emittance.

Surface resistivity

ECSS-E-ST-20-08\_0090985

In conformance with clause 8.7.7, the SCD-CVG shall include the minimum value of the surface resistivity, in Ω/cm2, and the equipment used to measure the resistivity.

Flatness or bow

ECSS-E-ST-20-08\_0090986

In conformance with clause 8.7.8, the SCD-CVG shall include:

The minimum value of the flatness or bow, as a maximum deviation, in mm.

The maximum value of coverglass displacement, from an optically flat surface over a specified distance in mm, for localized flatness deformations, in mm.

Transmission into adhesive

ECSS-E-ST-20-08\_0090987

In conformance with clause 8.7.9, the SCD-CVG shall include:

The values as shown in Table D-1.

The Fresnel’s equation used for the correction of the transmission for reflectance losses including all parameters.

HT1 humidity and temperature

ECSS-E-ST-20-08\_0090988

In conformance with clause 8.7.11.1, the SCD-CVG shall state the chemical contents (type and percentage (%) in the mist) of the humid environment when there are specific requirements on the contents of the environment.

Electron irradiation

ECSS-E-ST-20-08\_0090989

In conformance with clause 8.7.13.2, the SCD-CVG shall state the value of the nominal dose of the electron irradiation, in e- cm-2, and maximum rate, in e- cm-2 s-1.

Proton irradiation

ECSS-E-ST-20-08\_0090990

In conformance with clause 8.7.14.2, the SCD-CVG shall state the value of the high and low energy dose of the proton irradiation in p+ cm-2 and maximum flux, in p+ cm-2 s-1.

Breaking strength

ECSS-E-ST-20-08\_0090991

In conformance with clause 8.7.15, the SCD-CVG shall state the method to be used to test for the breaking strength and the limits of the breaking strength, in N.

Thermal cycling

ECSS-E-ST-20-08\_0090992

In conformance with clause 8.7.16, the SCD-CVG shall state the number of thermal cycles to be performed before contact adhesion and their extreme temperatures.

* + 1. Special remarks

None.

1. (normative)  
   Source control drawing for External Protection Diodes (SCD‑EPD) ‑ DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement 9.2.1.2.2b.

* + 1. Purpose and objective

The source control drawing for external protection diodes (SCD-EPD) contains the specific project dependent requirements, and together with this Standard, which contains the general requirements, constitutes the whole set of requirements for the qualification and acceptance of external protection diodes.

The SCD-EPD can be produced as a standalone document or as part of a system-level specification document.

The information on traceability to high level requirements can be included in the SCD-EPD itself or in the requirements traceability in the design justification file (DJF, see ECSS-E-ST-10). In either case a cross-reference is made.

The SCD-EPD is a major input to the qualification plan.

* 1. Expected response
     1. Scope and content

Introduction

ECSS-E-ST-20-08\_0090993

The SCD-EPD shall contain a description of the purpose, objective, content and the reason prompting its preparation.

Applicable and reference documents

ECSS-E-ST-20-08\_0090994

The SCD-EPD shall list the applicable and reference documents to support the generation of the document.

Terms and definitions, abbreviated terms and symbols

ECSS-E-ST-20-08\_0090995

The SCD-EPD shall include any additional definition, abbreviation or symbol used.

Deviations from ECSS-E-ST-20-08

ECSS-E-ST-20-08\_0090996

In conformance with requirement , the SCD-EPD shall include the justification for any deviation in the in-process, acceptance and qualification tests.

Materials

ECSS-E-ST-20-08\_0090997

The SCD-EPD shall include:

Reference to the procurement specification of the supplier.

The following characteristics of the external protection diodes:

growth technique;

doping element;

orientation;

main breakage direction;

base resistivity;

thickness.

Acceptance tests

ECSS-E-ST-20-08\_0090998

In conformance with 9.4.1.e, the SCD-EPD shall include the sample size.

ECSS-E-ST-20-08\_0090999

For dimensions and weigh, in conformance with clause 9.6.3, the SCD-EPD shall include:

The lateral dimensions and thickness, including tolerances.

The contact dimensions, including tolerances.

The maximum weight, in mg.

ECSS-E-ST-20-08\_0091000

For contact thickness, in conformance with clause 9.6.8, the SCD-EPD shall include the maximum and minimum values of the contact thickness in μm.

ECSS-E-ST-20-08\_0091001

For surface finish, in conformance with clause 9.6.9.3, the SCD-EPD shall include the requirements for the interconnection process.

ECSS-E-ST-20-08\_0091002

For humidity and temperature, in conformance with clause 9.6.6., the SCD-EPD shall include the chemical contents, type and % in the mist, to be added to the humid environment when there are specific requirements on the contents of the environment and the voltage bias condition to be applied to the EPD.

ECSS-E-ST-20-08\_0091003

For Pull, in conformance with clause 9.6.11, the SCD-EPD shall include:

the interconnection technique parameter;

the material and dimension of the interconnectors;

the value of the pull speed in mm/min and direction (0°, 45° or 90°);

the value of the ultimate pull strength in N.

ECSS-E-ST-20-08\_0091004

For diode performance, in conformance with clause 9.4.5.2 the SCD-EPD shall include:

For the test conditions specified in clause 9.4.5.2.2:

the temperature,

the forward current level ,

the reverse voltage level.

The pass-fail criteria for the test specified in clause 9.4.5.2.3:

the maximum absolute value of the forward voltage in V;

the reverse current in mA.

The physical limits in terms of maximum forward current and reverse voltage.

Qualification

Qualification test samples

ECSS-E-ST-20-08\_0091005

In conformance with requirement 9.5.4.2b, the SCD-EPD shall include:

The minimum number of protection diodes from which the qualification lot shall be selected.

The number of the first production batches from which the qualification lot is obtained.

Dimensions and weight

ECSS-E-ST-20-08\_0091006

In conformance with clause 9.6.3, the SCD-EPD shall include:

The lateral dimensions and thickness, including tolerances.

The contact dimensions, including tolerances.

The maximum weight, in mg.

Diode characteristics

ECSS-E-ST-20-08\_0091007

In conformance with clause 9.6.15.2, the SCD-EPD shall include:

For the test conditions:

the temperatures,

the times,

the forward current level,

the reverse voltage level.

The pass-fail criteria for the test specified in clause 9.6.15.3:

the maximum absolute value of the forward voltage in V;

the reverse current in mA.

The physical limits in terms of maximum forward current and reverse voltage.

Thermal cycling

ECSS-E-ST-20-08\_0091008

In conformance with clause 9.6.4.2, the SCD-EPD shall include the number of thermal cycles and their extreme temperatures.

Burn-in

ECSS-E-ST-20-08\_0091009

In conformance with clause 9.6.5.2, the SCD-EPD shall include the temperature of the burning process

Humidity and temperature

ECSS-E-ST-20-08\_0091010

In conformance with clause 9.6.6, the SCD-EPD shall include the chemical contents, type and % in the mist, to be added to the humid environment when there are specific requirements on the contents of the environment and the voltage bias condition to be applied to the EPD.

Contact uniformity.

ECSS-E-ST-20-08\_0091011

In conformance with clause 9.6.7.3, the SCD-EPD shall include the maximum and minimum values of the contact thickness in μm.

Surface finish.

ECSS-E-ST-20-08\_0091012

In conformance with clause 9.6.9.3, the SCD-EPD shall include the requirements for the interconnection process.

Pull

ECSS-E-ST-20-08\_0091013

In conformance with clause 9.6.11, the SCD-EPD shall include:

the interconnection technique parameter;

the material and dimension of the interconnectors;

the value of the pull speed in mm/min and direction (0°, 45° or 90°);

the value of the ultimate pull strength in N.

Electron irradiation

ECSS-E-ST-20-08\_0091014

In conformance with clause 9.6.12.2, the SCD-EPD shall include the expected total dose for the envisaged application, Φp, at 1MeV, in e- cm-2.

Switching:

ECSS-E-ST-20-08\_0091015

In conformance with requirement , the SCD-EPD shall include:

For level 1: The voltage (VREV), current (IFW), times (T1, T2 and T3) and temperatures.

For level 2: The voltage (VREV), current (IFW), times (T1, T2 and T3) and temperatures.

Long Duration - Life Testing:

ECSS-E-ST-20-08\_0091016

In conformance with requirement , the SCD-EPD shall include the total number of test steps in reverse and forward bias mode, VREV, IFW and the maximum allowables IREV and VFW.

ECSS-E-ST-20-08\_0091064

In conformance with requirement 9.6.18.2d.1, the SCD-EPD shall include maximum allowable temperature of the diode.

* + 1. Special remarks

None.

1. (normative)  
   Process identification document (PID) ‑ DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirements , , and .

* + 1. Purpose and objective

The purpose of the PID is to have a complete set of documentation defining the traceability of materials, processes and test results of the relevant components or sub-assemblies.

* 1. Expected response
     1. Scope and content

ECSS-E-ST-20-08\_0091017

The PID shall comprise copies of the definition documents of the SCA, and the manufacturing documents and testing procedures, and include the following:

in the case of SCAs, a parts list;

a materials list;

a list of all manufacturing drawings;

the production flow chart;

the specifications for the process used;

procedures for the inspection performed;

the overall test programme (including in-process tests and acceptance tests);

a table of contents with reference number and issue;

the test matrix for acceptance tests, including requirements and failure criteria;

the traceability details of the component.

1. 1 to item 5: If different manufacturing machine is used, different manufacturing process document applies.
2. 2 to item 10: The traceability details are as agreed between customer and supplier.
   * 1. Special remarks

ECSS-E-ST-20-08\_0091289

When a document is company confidential or contains proprietary information, the complete document need not be included.

ECSS-E-ST-20-08\_0091019

In the case specified in requirement 12.10.2a, a reference to the document shall be included.

1. (normative)  
   Data documentation package (DDP) - DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement , , , and .

* + 1. Purpose and objective

The DDP is the collection of the data related to the manufacturing, integration and test of the PVA, SCA, BSC, CVG and protection diode, which provides traceability and events records, and is the basis to support the acceptance and qualification of the PVA, SCA, BSC, CVG and protection diode.

* 1. Expected response for PVA DDP
     1. Scope and content

ECSS-E-ST-20-08\_0091020

The PVA-DDP of coupons for the delivery review board (DRB) shall include, as a minimum, the following items:

table of contents;

certificate of conformance;

shipping documents;

configuration item data list (CIDL);

product manufacturing and control file (PMCF);

parts, materials and processes (PMP) list;

list of requests for deviations;

list of requests for waivers;

list of nonconformances, including copies of nonconformance reports (NCRs) NRB documentation including failure analysis and failed coupon list;

history record;

connector mate and de-mate record;

serialized components list;

in-process inspection test results, including positioning in the manufacturing flow chart;

open work or open test;

replacement or temporary installation record;

acceptance and qualification test procedures and test reports;

assembly drawings and circuit diagram;

notes and comments;

operation and maintenance manuals and user restrictions;

minutes of delivery review board (DRB) meetings;

lower level data documentation packages (DDPs).

* + 1. Special remarks

None.

* 1. Expected response for SCA, BSC, CVG, and Protection diode DDP.
     1. Scope and content

ECSS-E-ST-20-08\_0091021

The DDP for SCA, BSC, CVG and protection diode shall consist of cover sheet or sheets, including as a minimum the following:

reference to the corresponding SCD, including issue and date;

reference to this Standard, including issue and date;

component type (for SCDs, BSCs, coverglasses and protection diodes);

procurement SCA, BSC, CVG and protection diode identification;

manufacturing SCA, BSC, CVG and protection diode identification;

number of purchase order or contract;

deviations from, or additions to, the corresponding SCD and this Standard, if so specified in the order;

manufacturer’s name and address;

location of the manufacturing plant;

signature on behalf of the manufacturer;

total number of pages of the data package.

ECSS-E-ST-20-08\_0091022

The DDP for SCA, BSC, CVG and protection diode shall consist of the summary compilation of the final production test data, showing:

For SCAs, the total number of SCAs submitted to, and the total number rejected after, each of the following tests:

Visual inspection,

Control of dimensions,

Electrical performance measurements,

Diode performance measurements.

For BSC, coverglasses and protection diodes, the total number of elements submitted to, and the total number rejected after, each of the acceptance tests.

ECSS-E-ST-20-08\_0091023

The DDP for SCA, BSC, CVG and protection diode shall consist of the qualification testing data, including:

For SCAs BSCs, and protection diodes, detailed data of all measurements made in conformance with:

and Figure 6‑2 (SCAs),

Annex C (BSCs),

Annex C (IPD) or Annex E (EPD).

data of all environmental tests

ECSS-E-ST-20-08\_0091024

The DDP for SCA, BSC, CVG and protection diode shall consist of failed SCAs, BSCs, CVGs and EPDs list and the corresponding non conformance reports , including:

The reference number and description of the test or measurement as stated in this Standard or in the corresponding SCD.

The identification of failed component (for SCDs, BSCs, coverglasses and protection diodes).

The failed parameter and the failure mode of the component (for SCDs, BSCs, coverglasses and protection diodes).

A detailed failure analysis report.

ECSS-E-ST-20-08\_0091025

The DDP for SCA, BSC, CVG and protection diode shall consist of certificate of compliance.

ECSS-E-ST-20-08\_0091026

The DDP for SCA, BSC, CVG and protection diode shall consist of full request of deviations and waivers.

ECSS-E-ST-20-08\_0091027

The DDP for SCA, BSC, CVG and protection diode shall consist of qualification test plan.

ECSS-E-ST-20-08\_0091028

The DDP for SCA, BSC, CVG and protection diode shall consist of acceptance and qualification test reports.

* + 1. Special remarks

ECSS-E-ST-20-08\_0091029

For identification purposes, each page of the data package shall include the following additional supporting data:

component type (for SCDs, BSCs, coverglasses and protection diodes);

manufacturer’s name;

manufacturing lot identification (for SCDs, BSCs, coverglasses and protection diodes);

date of establishment of the document;

page number.

1. (normative)  
   Source control drawing for Planar Blocking Diodes (SCD-PBD) - DRD
   1. DRD identification
      1. Requirement identification and source document

This DRD is called from ECSS-E-ST-20-08, requirement 12.2.1.2a and 12.2.1.1b.

* + 1. Purpose and objective

The source control drawing for planar blocking diodes (SCD-PBD) contains the specific project dependent requirements, and together with this Standard, which contains the general requirements, constitutes the whole set of requirements for the qualification and acceptance of planar blocking diodes.

The SCD-PBD can be produced as a standalone document or as part of a system-level specification document.

The information on traceability to high level requirements can be included in the SCD-PBD itself or in the requirements traceability in the design justification file (DJF, see ECSS-E-ST-10). In either case a cross-reference is made.

The SCD-PBD is a major input to the qualification plan.

* 1. Expected response
     1. Scope and content

Introduction

ECSS-E-ST-20-08\_0091290

The SCD-PBD shall contain a description of the purpose, objective, content and the reason prompting its preparation.

Applicable and reference documents

ECSS-E-ST-20-08\_0091291

The SCD-PBD shall list the applicable and reference documents to support the generation of the document.

Terms and definitions, abbreviated terms and symbols

ECSS-E-ST-20-08\_0091292

The SCD-PBD shall include any additional definition, abbreviation or symbol used.

Deviations from ECSS-E-ST-20-08

ECSS-E-ST-20-08\_0091293

The SCD-PBD shall include the justification for any deviation in the in-process, acceptance and qualification tests.

Materials

ECSS-E-ST-20-08\_0091294

The SCD-PBD shall include:

Reference to the procurement specification of the supplier.

The following characteristics of the planar blocking diodes:

growth technique;

doping element;

orientation;

main breakage direction;

base resistivity;

thickness.

Marking

ECSS-E-ST-20-08\_0091295

The level of the traceability of the manufactured planar blocking diodes in their marking shall be specified.

Acceptance tests

ECSS-E-ST-20-08\_0091296

The SCD-PBD shall include the sample size.

ECSS-E-ST-20-08\_0091297

For dimensions and weight, in conformance with clause 12.6.2 and 12.6.3, the SCD-PBD shall include:

the lateral dimensions and thickness, including tolerances.

the contact dimensions, including tolerances.

The maximum weight, in mg.

ECSS-E-ST-20-08\_0091298

For contact uniformity, in conformance with clause 12.6.13, the SCD-PBD shall include the maximum and minimum values of the contact thickness in μm.

ECSS-E-ST-20-08\_0091299

For surface finish, in conformance with clause 12.6.14, the SCD-PBD shall include the requirements for the interconnection process.

ECSS-E-ST-20-08\_0091300

For humidity and temperature, in conformance with clause 12.6.4, the SCD-PBD shall include the chemical contents, type and % in the mist, to be added to the humid environment when there are specific requirements on the contents of the environment.

ECSS-E-ST-20-08\_0091301

For Pull, in conformance with clause 12.6.16, the SCD-PBD shall include:

the interconnection technique parameter;

the material and dimension of the interconnectors;

the value of the pull speed in mm/min and direction (0°, 45° or 90°);

the value of the ultimate pull strength in N.

ECSS-E-ST-20-08\_0091302

For diode performance, in conformance with clause 12.6.3 the SCD-PBD shall include:

For the test conditions specified in requirement 12.6.3.2a:

the temperature;

the forward current level;

the reverse voltage level.

The pass-fail criteria for the test specified in clause 12.6.3.3:

the maximum absolute value of the forward voltage in V;

the reverse current in mA.

Qualification

Qualification test samples

ECSS-E-ST-20-08\_0091303

In conformance with requirement 12.5.4b, the SCD-PBD shall include:

the minimum number of blocking diodes from which the qualification lot is selected.

the number of the first production batches from which the qualification lot is obtained.

Dimensions check and Weight

ECSS-E-ST-20-08\_0091304

In conformance with clause 12.6.2, the SCD-PBD shall include:

the lateral dimensions and thickness, including tolerances.

the contact dimensions, including tolerances.

the maximum weight, in mg.

Diode Characterization

ECSS-E-ST-20-08\_0091305

In conformance with clause 12.6.3.2, the SCD-PBD shall include:

For the test conditions:

the temperatures,

the times,

the forward current level,

the reverse voltage level.

The pass-fail criteria for the test specified in clause 12.6.3.3:

the maximum absolute value of the forward voltage in V;

the reverse current in mA.

Temperature Cycling

ECSS-E-ST-20-08\_0091306

In conformance with clause 12.6.5.2, the SCD-PBD shall include the number of thermal cycles and their extreme temperatures.

Power Burn-in and High Temperature Reverse Bias Burn-in

ECSS-E-ST-20-08\_0091307

In conformance with clause 12.6.7.2 and 12.6.7.3, the SCD-PBD shall include the temperature, as well as the electrical conditions of the Burn-in process.

Humidity and temperature

ECSS-E-ST-20-08\_0091308

In conformance with clause 12.6.4.1.2h, the SCD-PBD shall include the voltage bias condition to be applied to the diode.

ECSS-E-ST-20-08\_0091309

In conformance with clause 12.6.4, the SCD-PBD shall include the chemical contents, type and % in the mist, to be added to the humid environment when there are specific requirements on the contents of the environment and the voltage bias condition to be applied to the diode.

Contact uniformity

ECSS-E-ST-20-08\_0091310

In conformance with clause 12.6.13, the SCD-PBD shall include the maximum and minimum values of the contact thickness in μm.

Surface finish

ECSS-E-ST-20-08\_0091311

In conformance with clause 12.6.14, the SCD-PBD shall include the requirements for the interconnection process.

Pull test

ECSS-E-ST-20-08\_0091312

In conformance with clause 12.6.16, the SCD-PBD shall include:

the interconnection technique parameter;

the material and dimension of the interconnectors;

the value of the pull speed in mm/min and direction (0°, 45° or 90°);

the value of the ultimate pull strength in N.

Total Dose Radiation Testing

ECSS-E-ST-20-08\_0091313

In conformance with clause 12.6.11, the SCD-PBD shall include the expected total dose for the envisaged application and the type of irradiation.

ECSS-E-ST-20-08\_0091314

In conformance with clause 12.6.11, the SCD-PBD shall include the minimum allowable IRev and VFwd after Ionising and Non-Ionising radiation.

Long Duration-Life Test

ECSS-E-ST-20-08\_0091315

In conformance with clause 12.6.8, the SCD-PBD shall include, the activation energy and the total number of hours in forward and reverse bias mode (VRev and IFwd).

ECSS-E-ST-20-08\_0091316

In conformance with clause 12.6.8, the SCD-PBD shall include maximum allowable temperature of the diode, as defined in the Temperature Stress Step Test of ESCC 2265000.

ECSS-E-ST-20-08\_0091317

In conformance with clause 12.6.8, the SCD-PBD shall include the minimum allowable IRev and VFwd after Long Duration-Life test.

Temperature Behaviour

ECSS-E-ST-20-08\_0091318

In conformance with clause 12.6.9, the SCD-PBD shall include the forward current IFwd and a reverse voltage VRev respectively, applied to the blocking diode, for each test temperature.

Human Body ESD

ECSS-E-ST-20-08\_0091319

In conformance with clause 12.6.15, the SCD-PBD shall include the minimum allowable IRev and VFwd after Human Body ESD test.

Surge Test

ECSS-E-ST-20-08\_0091320

In conformance with clause 12.6.17, the SCD-PBD shall include the maximum forward current IFwd to which the diode is biased during the surge test.

ECSS-E-ST-20-08\_0091321

In conformance with clause 12.6.17, the SCD-PBD shall include the minimum allowable IRev and VFwd after surge test.

Thermo-optical data

ECSS-E-ST-20-08\_0091322

In conformance with clause 12.6.18, the SCD-PBD shall include the following:

The maximum value of the solar absorptance as a percentage of planar blocking diode with tolerances.

The maximum value of normal emittance as a percentage (%) of planar blocking diode with tolerances.

* + 1. Special remarks

None.

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| --- | --- |
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